

Prüfbericht-Nr.: Test report no.:	CN26V5UF 001	Auftrags-Nr.: Order no.:	27239579	Seite 1 von 28 Page 1 of 28	
Kunden-Referenz-Nr.: Client reference no.:	N/A	Auftragsdatum: Order date:	2026-06-09		
Auftraggeber: Client:	SHENZHEN FENDA TECHNOLOGY CO.,LTD Fenda Hi-Tech Park, Zhoushi Road, Shiyan, Baoan, Shenzhen, Guangdong, China				
Prüfgegenstand: Test item:	L320 Party Speaker				
Bezeichnung / Typ-Nr.: Identification / Type no.:	NS-PSL320 (Trademark: INSIGNIA)				
Auftrags-Inhalt: Order content:	Test Report				
Prüfgrundlage: Test specification:	CFR Title 47 FCC Part 15, Subpart C, Section 15.247				
Wareneingangsdatum: Date of sample receipt:	2026-06-05	Please refer to Photo Document			
Prüfmuster-Nr.: Test sample no.:	A004298780-001 A004299962-001~002				
Prüfzeitraum: Testing period:	2026-06-16 - 2026-06-27				
Ort der Prüfung: Place of testing:	Shenzhen PSI Testing Co., Ltd.				
Prüflaboratorium: Testing laboratory:	TÜV Rheinland (Shenzhen) Co., Ltd.				
Prüfergebnis*: Test result*:	Pass				
geprüft von: tested by:			genehmigt von: authorized by:		
Datum: Date:	2026-07-02	Signed by: Jonathan Li		Ausstellungsdatum: Issue date:	2026-07-02
Stellung / Position:	Sachverständige(r)/Expert		Stellung / Position:	Sachverständige(r)/Expert	
Sonstiges / Other:	FCC ID: HBOPA2629				
Zustand des Prüfgegenstandes bei Anlieferung: Condition of the test item at delivery:	Prüfmuster vollständig und unbeschädigt Test item complete and undamaged				
* Legende: P(ass) = entspricht o.g. Prüfgrundlage(n) F(ail) = entspricht nicht o.g. Prüfgrundlage(n) N/A = nicht anwendbar N/T = nicht getestet * Legend: P(ass) = passed a.m. test specification(s) F(ail) = failed a.m. test specification(s) N/A = not applicable N/T = not tested					
Dieser Prüfbericht bezieht sich nur auf das o.g. Prüfmuster und darf ohne Genehmigung der Prüfstelle nicht auszugsweise vervielfältigt werden. Dieser Bericht berechtigt nicht zur Verwendung eines Prüfzeichens. <i>This test report only relates to the above mentioned test sample. Without permission of the test center this test report is not permitted to be duplicated in extracts. This test report does not entitle to carry any test mark.</i>					

Prüfbericht-Nr.: CN26V5UF 001
Test report no.:

Seite 2 von 28
Page 2 of 28

Anmerkungen
Remarks

1	Alle eingesetzten Prüfmittel waren zum angegebenen Prüfzeitraum gemäß eines festgelegten Kalibrierungsprogramms unseres Prüfhauses kalibriert. Sie entsprechen den in den Prüfprogrammen hinterlegten Anforderungen. Die Rückverfolgbarkeit der eingesetzten Prüfmittel ist durch die Einhaltung der Regelungen unseres Managementsystems gegeben. Detaillierte Informationen bezüglich Prüfbedingungen, Prüfequipment und Messunsicherheiten sind im Prüflabor vorhanden und können auf Wunsch bereitgestellt werden. <i>The equipment used during the specified testing period was calibrated according to our test laboratory calibration program. The equipment fulfils the requirements included in the relevant standards. The traceability of the test equipment used is ensured by compliance with the regulations of our management system. Detailed information regarding test conditions, equipment and measurement uncertainty is available in the test laboratory and could be provided on request.</i>
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3	Prüfklausel mit der Note * wurden an qualifizierte Unterauftragnehmer vergeben und sind unter der jeweiligen Prüfklausel des Berichts beschrieben. Abweichungen von Prüfspezifikation(en) oder Kundenanforderungen sind in der jeweiligen Prüfklausel im Bericht aufgeführt. <i>Test clauses with remark of * are subcontracted to qualified subcontractors and described under the respective test clause in the report.</i> <i>Deviations of testing specification(s) or customer requirements are listed in specific test clause in the report.</i>
4	Die Entscheidungsregel für Konformitätserklärungen basierend auf numerischen Messergebnissen in diesem Prüfbericht basiert auf der "Null-Grenzwert-Regel" und der "Einfachen Akzeptanz" gemäß ILAC G8:2019 und IEC Guide 115:2023, es sei denn, in der auf Seite 1 dieses Berichts genannten angewandten Norm ist etwas anderes festgelegt oder vom Kunden gewünscht. Dies bedeutet, dass die Messunsicherheit nicht berücksichtigt wird und daher auch nicht im Prüfbericht angegeben wird. Zu weiteren Informationen bezüglich des Risikos durch diese Entscheidungsregel siehe ILAC G8:2019. <i>The decision rule for statements of conformity, based on numerical measurement results, in this test report is based on the "Zero Guard Band Rule" and "Simple Acceptance" in accordance with ILAC G8:2019 and IEC Guide 115:2023, unless otherwise specified in the applied standard mentioned on Page 1 of this report or requested by the customer. This means that measurement uncertainty is not taken in account and hence also not declared in the test report. For additional information to the resulting risk based of this decision rule please refer to ILAC G8:2019.</i>

Test Summary

5.1.1 ANTENNA REQUIREMENT

RESULT: Pass

5.1.2 MAXIMUM PEAK CONDUCTED OUTPUT POWER

RESULT: Pass

5.1.3 CONDUCTED POWER SPECTRAL DENSITY

RESULT: Pass

5.1.4 6dB BANDWIDTH

RESULT: Pass

5.1.5 99% BANDWIDTH

RESULT: Pass

5.1.6 20dB BANDWIDTH

RESULT: Pass

5.1.7 CARRIER FREQUENCY SEPARATION

RESULT: Pass

5.1.8 NUMBER OF HOPPING FREQUENCY

RESULT: Pass

5.1.9 TIME OF OCCUPANCY

RESULT: Pass

5.1.10 CONDUCTED SPURIOUS EMISSIONS MEASURED IN 100 KHz BANDWIDTH

RESULT: Pass

5.1.11 RADIATED SPURIOUS EMISSION

RESULT: Pass

5.1.12 CONDUCTED EMISSION ON AC MAINS

RESULT: Pass

Contents

1	GENERAL REMARKS	5
1.1	COMPLEMENTARY MATERIALS.....	5
2	TEST SITES.....	6
2.1	TEST FACILITIES	6
2.2	LIST OF TEST AND MEASUREMENT INSTRUMENTS	6
2.3	TRACEABILITY	7
2.4	CALIBRATION.....	7
2.5	MEASUREMENT UNCERTAINTY	7
2.6	LOCATION OF ORIGINAL DATA	8
2.7	STATUS OF FACILITY USED FOR TESTING	8
3	GENERAL PRODUCT INFORMATION	9
3.1	PRODUCT FUNCTION AND INTENDED USE	9
3.2	RATINGS AND SYSTEM DETAILS.....	9
3.3	INDEPENDENT OPERATION MODES.....	11
3.4	NOISE GENERATING AND NOISE SUPPRESSING PARTS	11
3.5	SUBMITTED DOCUMENTS.....	11
4	TEST SET-UP AND OPERATION MODES.....	12
4.1	PRINCIPLE OF CONFIGURATION SELECTION	12
4.2	TEST OPERATION AND TEST SOFTWARE	12
4.3	SPECIAL ACCESSORIES AND AUXILIARY EQUIPMENT	12
4.4	COUNTERMEASURES TO ACHIEVE EMC COMPLIANCE	12
4.5	TEST SETUP DIAGRAM	13
5	TEST RESULTS	15
5.1	TRANSMITTER REQUIREMENT & TEST SUITES.....	15
5.1.1	<i>Antenna Requirement.....</i>	<i>15</i>
5.1.2	<i>Maximum Peak Conducted Output Power</i>	<i>16</i>
5.1.3	<i>Conducted Power Spectral Density.....</i>	<i>18</i>
5.1.4	<i>6dB Bandwidth</i>	<i>19</i>
5.1.5	<i>99% Bandwidth.....</i>	<i>20</i>
5.1.6	<i>20dB Bandwidth</i>	<i>21</i>
5.1.7	<i>Carrier Frequency Separation</i>	<i>22</i>
5.1.8	<i>Number of Hopping Frequency</i>	<i>23</i>
5.1.9	<i>Time of Occupancy.....</i>	<i>24</i>
5.1.10	<i>Conducted Spurious Emissions Measured in 100 kHz Bandwidth</i>	<i>25</i>
5.1.11	<i>Radiated Spurious Emission</i>	<i>26</i>
5.1.12	<i>Conducted Emission on AC Mains.....</i>	<i>27</i>
6	PHOTOGRAPHS OF THE TEST SET-UP	28
7	LIST OF TABLES.....	28

1 General Remarks

1.1 Complementary Materials

All attachments are integral parts of this test report. This applies especially to the following appendix:

Appendix A: Test Results of Bluetooth BR & EDR

Appendix B: Test Results of Bluetooth LE

Appendix C: Photographs of the Test Set-up

2 Test Sites

2.1 Test Facilities

Shenzhen PSI Testing Co., Ltd.

1-2F, Building 5, Yudafu Industrial Park, No.10, Xingye West Road, Shajing Street, Bao'an District, Shenzhen, Guangdong, China 518104

A2LA CAB identifier: CN1362

TÜV Rheinland (shenzhen) Co., Ltd. subcontract all test to Shenzhen PSI Testing Co., Ltd. And all tests at this site have been conducted under the supervision of a TÜV Rheinland engineer.

2.2 List of Test and Measurement Instruments

Table 1: List of Test and Measurement Equipment

Item	Equipment	Manufacturer	Model No.	Serial No.	Firmware Version	Last Cal.	Cal. Interval
1.	9*6*6 anechoic chamber	SKET	9*6*6	N/A	/	2025.12.18	3 Year
2.	Test Receiver	Rohde&Schwarz	ESCI 7	101032/003	4.42 SP3	2025.12.18	1 Year
3.	Loop Antenna	Schwarz beck	FMZB 1519B	00128	/	2025.01.02	2 Year
4.	Bilog Antenna	Schwarz beck	VULB 9168	01448	/	2025.01.02	2 Year
5.	Spectrum Analyzer	Rohde&Schwarz	FSV-40N	101648	3.70	2025.12.18	1 Year
6.	Horn Antenna	Schwarz beck	BBHA 9120 D	02706	/	2025.01.02	2 Year
7.	Amplifier	SKET	LAPA_01G18 G-45dB	SK2022032901	/	2025.12.18	1 Year
8.	Horn Antenna	Schwarz beck	BBHA 9170	00946	/	2024.12.31	2 Year
9.	Amplifier	SKET	LNPA_0118G-45	SK2020010801	/	2025.12.18	1 Year
10.	RF Power Probe	Rohde&Schwarz	NRP-Z11	1138.3004.02-117725-vh	/	2025.12.18	1 Year
11.	RF Power Probe	Rohde&Schwarz	NRP-Z11	1138.3004.02-1111533-Fz	/	2025.12.18	1 Year
12.	Vector Signal Generator	Agilent	N5182A	MY47420724	/	2025.12.18	1 Year
13.	Analog signal generator	Agilent	N5181A	MY50145363	/	2025.12.18	1 Year
14.	Comprehensive Test Instrument	Rohde&Schwarz	CMW 500	145266	/	2025.12.18	1 Year
15.	Spectrum Analyzer	Agilent	N9020A	MY51281067	A.14.03	2025.12.18	1 Year
16.	Temp. & Humid Chamber	Auchno	9606	/	/	2025.12.18	1 Year
17.	Regulated DC Power Supply	Xinouhua	ADC120V10A	202211251638		2025.12.18	1 Year

For Test Software Information

Item	Software Name	Manufacturer	Version
RE	EMC-I	Farad	PSI-3A1
RF	RTS	TACHOY	V1.0.0

For Power Line Conducted Emission Test Equipment:

Item	Equipment	Manufacturer	Model No.	Serial No.	Firmware Version	Last Cal.	Cal. Interval
1.	Test Receiver	Rohde&Schwarz	ESCI 7	101032/003	4.42 SP3	2025.12.18	1 Year
2.	L.I.S.N.	Rohde&Schwarz	ENV 216	102282	/	2025.12.18	1 Year
3.	L.I.S.N.	RFT	NNB111	13835240	/	2025.12.18	1 Year

For Test Software Information

Item	Software Name	Manufacturer	Version
CE	EZ-EMC	Farad	PSI-3A1

2.3 Traceability

All measurement equipment calibrations are traceable to NIM (National Institute of Metrology) or where calibration is performed in other countries, to equivalent nationally recognized standards organizations.

2.4 Calibration

Equipment requiring calibration is calibrated periodically by the manufacturer or according to manufacturer's specifications. Additionally all equipment is verified for proper performance on a regular basis using in house standards or comparisons.

2.5 Measurement Uncertainty

The estimated combined standard uncertainty for radiated emissions and conducted emissions measurements as below table.

Table 2: Measurement Uncertainty

Item	Uncertainty
Power Line Conducted Emissions Test	2.13dB
Radiation Emission test in 3m chamber(Below 30MHz)	4.07dB
Radiation Emission test in 3m chamber(30MHz to 1GHz)	4.51dB
Radiation Emission test in 3m chamber(1GHz to 18GHz)	5.07dB
Radiation Emission test in 3m chamber(18GHz to 40GHz)	5.21dB
Disturbance power test Equipment:	3.68dB
Radio Frequency	48.24KHz
Conducted RF Power	0.41dB
Power Spectral Density	0.39 dB
Occupied-Bandwidth	968Hz
Duty Cycle	1%
Conducted-Spurious Emission	1.26dB

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:

Seite 8 von 28
Page 8 of 28

2.6 Location of Original Data

The original copies of all test data taken during actual testing were attached at Appendix A & B & C of this report and delivered to the applicant. A copy has been retained in the TÜV Rheinland (Shenzhen) Co., Ltd. file for certification follow-up purposes.

2.7 Status of Facility Used for Testing

The **Error! Reference source not found.** Test facility located at **Error! Reference source not found.** is listed on the US Federal Communications Commission list of facilities approved to perform measurements.

3 General Product Information

3.1 Product Function and Intended Use

The product is a L320 Party Speaker which supports Bluetooth wireless technology.

For details refer to the User Manual, Technical Description and Circuit Diagram.

3.2 Ratings and System Details

Table 3: General Information of EUT

General Information of EUT	Value
Kind of Equipment:	L320 Party Speaker
Type Designation:	NS-PSL320
Trademark:	INSIGNIA
FCC ID:	HBOPA2629
Operating Voltage:	AC 100-240V, 50/60Hz, 2.5A or Battery operated (14.8Vdc, 2500mAh)
Testing Voltage:	Fully charged battery or AC 120V/60Hz
Technical Specification of Bluetooth (dual mode)	
Operating Frequency:	2402 MHz to 2480 MHz
Type of Modulation:	GFSK, $\pi/4$ -DQPSK, 8DPSK
Channel Number:	BR & EDR mode:79 channels, Low Energy mode:40 channels
Channel Separation:	BR & EDR mode:1MHz, Low Energy mode:2MHz
Data Rate:	BR & EDR mode: 1Mbps, 2Mbps, 3Mbps Low Energy mode: 1Mbps, 2Mbps
Antenna Type:	PCB Antenna
Antenna Gain:	1.83 dBi (Provided by the Client)

Note: The correctness of all data provided by customer in the test report is ensured and responsible of the customer. Any misjudgment of the test results caused by the use of incorrect data provided by customer shall be borne by the customer.

Table 4: RF Channel and Frequency of Bluetooth BR & EDR

RF Channel	Frequency (MHz)	RF Channel	Frequency (MHz)	RF Channel	Frequency (MHz)	RF Channel	Frequency (MHz)
0	2402.00	20	2422.00	40	2442.00	60	2462.00
1	2403.00	21	2423.00	41	2443.00	61	2463.00
2	2404.00	22	2424.00	42	2444.00	62	2464.00
3	2405.00	23	2425.00	43	2445.00	63	2465.00
4	2406.00	24	2426.00	44	2446.00	64	2466.00
5	2407.00	25	2427.00	45	2447.00	65	2467.00
6	2408.00	26	2428.00	46	2448.00	66	2468.00
7	2409.00	27	2429.00	47	2449.00	67	2469.00
8	2410.00	28	2430.00	48	2450.00	68	2470.00
9	2411.00	29	2431.00	49	2451.00	69	2471.00
10	2412.00	30	2432.00	50	2452.00	70	2472.00
11	2413.00	31	2433.00	51	2453.00	71	2473.00
12	2414.00	32	2434.00	52	2454.00	72	2474.00
13	2415.00	33	2435.00	53	2455.00	73	2475.00
14	2416.00	34	2436.00	54	2456.00	74	2476.00
15	2417.00	35	2437.00	55	2457.00	75	2477.00
16	2418.00	36	2438.00	56	2458.00	76	2478.00
17	2419.00	37	2439.00	57	2459.00	77	2479.00
18	2420.00	38	2440.00	58	2460.00	78	2480.00
19	2421.00	39	2441.00	59	2461.00		

Test frequencies are lowest channel: 2402 MHz, middle channel: 2441 MHz and highest channel: 2480 MHz for Bluetooth BR & EDR

Table 5: RF Channel and Frequency of Bluetooth LE

RF Channel	Frequency (MHz)	RF Channel	Frequency (MHz)	RF Channel	Frequency (MHz)	RF Channel	Frequency (MHz)
0	2402	10	2422	20	2442	30	2462
1	2404	11	2424	21	2444	31	2464
2	2406	12	2426	22	2446	32	2466
3	2408	13	2428	23	2448	33	2468
4	2410	14	2430	24	2450	34	2470
5	2412	15	2432	25	2452	35	2472
6	2414	16	2434	26	2454	36	2474
7	2416	17	2436	27	2456	37	2476
8	2418	18	2438	28	2458	38	2478
9	2420	19	2440	29	2460	39	2480

Test frequencies are lowest channel: 2402 MHz, middle channel: 2440 MHz and highest channel: 2480 MHz for Bluetooth LE

3.3 Independent Operation Modes

The basic operation modes are:

- A. On, Bluetooth transmitting mode (BR & EDR mode)
 - 1) Low Channel
 - 2) Middle Channel
 - 3) High Channel
- B. On, Bluetooth transmitting mode (Bluetooth LE mode)
 - 1) Low Channel
 - 2) Middle Channel
 - 3) High Channel
- C. On, Transmitting on Hopping channel
- D. On, Normal working + Charging
- E. Off

3.4 Noise Generating and Noise Suppressing Parts

Refer to Circuit Diagram for further details.

3.5 Submitted Documents

- | | |
|-------------------------|------------------------------|
| - Application Form | - User Manual |
| - Operation Description | - ID Label and Location Info |

4 Test Set-up and Operation Modes

4.1 Principle of Configuration Selection

Radio Spectrum: The equipment under test (EUT) was configured at its highest power output in order to measure its highest possible radiation and conducted level. The test modes were adapted accordingly in reference to the instructions for use.

Emission: The equipment under test (EUT) was configured to measure its highest possible radiation level. The test modes were adapted accordingly in reference to the instructions for use.

4.2 Test Operation and Test Software

Test operation refers to test setup in chapter 5. All tests were performed according to the procedures in ANSI C63.10:2020.

According to clause 3.1, all tests were performed on model *NS-PSL320* in this report.

4.3 Special Accessories and Auxiliary Equipment

Table 6: List of Accessories and Auxiliary Equipment

Description	Manufacturer	Model	Remark
Notebook PC	Dell	Latitude 3490	N/A
Aux Cable	UGREEN	3.5mm	N/A
USB Disk	Kinstong	8G	N/A
Wireless Microphone Pair	SHENZHEN FENDA	NS-PSMCPAIR	Micphone
Wireless Microphone Pair	SHENZHEN FENDA	NS-PSMCPAIR	Dongle
Mobile Phone	N/A	N/A	N/A

4.4 Countermeasures to Achieve EMC Compliance

The test sample which has been tested contained the noise suppression parts as described in the Technical Construction File (TCF).

No additional measures were employed to achieve compliance.

4.5 Test Setup Diagram

Diagram of Measurement Configuration for Radiation Test (Below 1GHz)

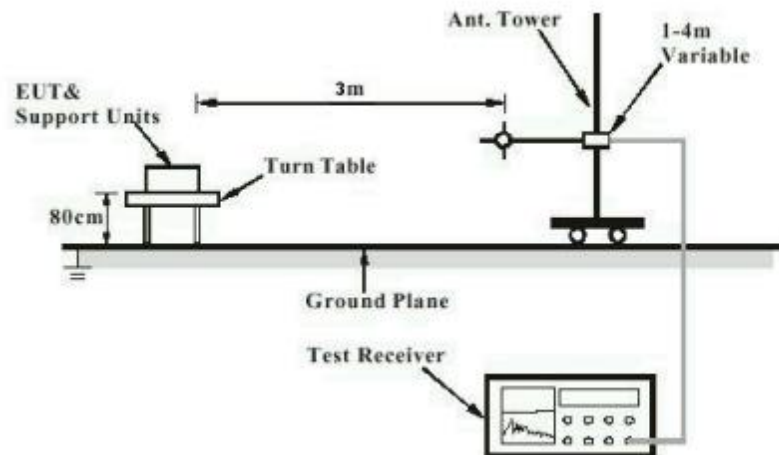


Diagram of Measurement Configuration for Radiation Test (Above 1GHz)

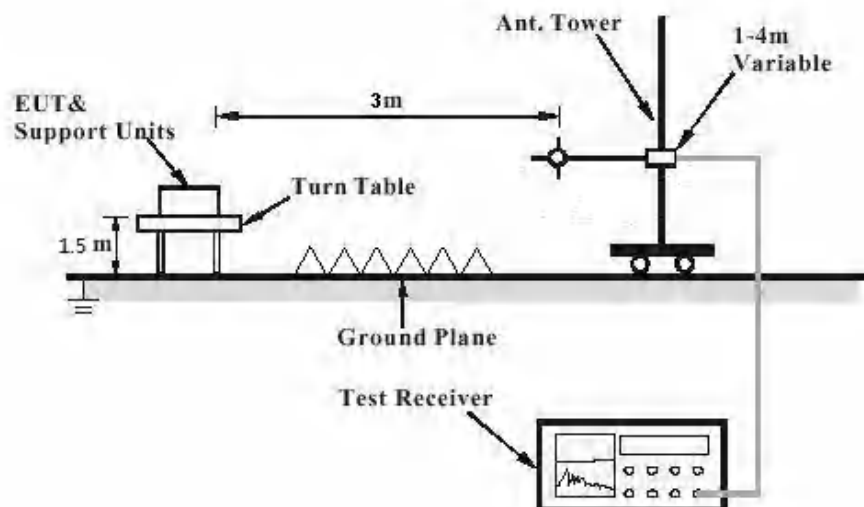


Diagram of Measurement Configuration for Mains Conduction Measurement

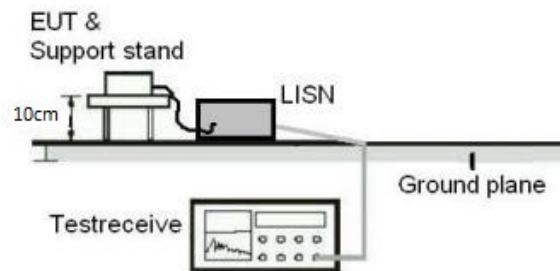
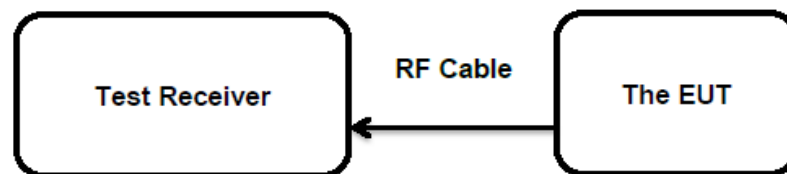


Diagram of Measurement Configuration for Conducted Transmitter Measurement



5 Test Results

5.1 Transmitter Requirement & Test Suites

5.1.1 Antenna Requirement

RESULT:

Pass

Test Specification

Test standard : FCC Part 15.247(b)(4) and Part 15.203

According to the manufacturer declared, the EUT has PCB Layout Antenna, permanent attachment and no consideration of replacement, refer to section 3.2 for details.

Therefore, the EUT is considered sufficient to comply with the provision.

Refer to EUT Photo for further details.

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:Seite 16 von 28
Page 16 of 28

5.1.2 Maximum Peak Conducted Output Power

RESULT:

Pass

Test Specification

Test standard	: FCC Part 15.247(b)(1)&(3)
Basic standard	: ANSI C63.10:2020
Limits	: FHSS < 0.125 Watts, DSSS < 1.0 Watts
Kind of test site	: Shielded Room

Test Setup

Date of testing	: 2026-06-16 to 2026-06-17
Input voltage	: Fully charged battery
Operation mode	: A, B
Test channel	: Low / Middle / High
Ambient temperature	: 24 °C
Relative humidity	: 56 %
Atmospheric pressure	: 101.1 kPa

For details refer to following test result.

Table 7: Test Result of Maximum Conducted Output Power, BR & EDR

Test Mode	Test Channel (MHz)	Measured Peak Power		Limit (W)
		(dBm)	(W)	
GFSK (BR)	2402.0	3.05	0.0020	< 0.125
	2441.0	2.91	0.0020	
	2480.0	2.80	0.0019	
8DPSK (EDR)	2402.0	3.19	0.0021	
	2441.0	3.04	0.0020	
	2480.0	2.95	0.0020	
Maximum Measured Value		3.19	0.0021	

Table 8: Test Result of Maximum Conducted Output Power, Bluetooth LE

Test Mode	Test Channel (MHz)	Measured Peak Power		Limit (W)
		(dBm)	(W)	
Bluetooth LE (1 Mbps)	2402	3.32	0.0021	< 1.0
	2440	3.12	0.0021	
	2480	3.01	0.0020	
Bluetooth LE (2 Mbps)	2402	3.15	0.0021	
	2440	2.98	0.0020	
	2480	2.88	0.0019	
Max. Measured Value		3.32	0.0021	

Note:

- 1) The cable loss is taken into account in results.
- 2) Antenna gain(G): 1.83dBi

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:

Seite 18 von 28
Page 18 of 28

5.1.3 Conducted Power Spectral Density

RESULT:

Pass

Test Specification

Test standard : FCC Part 15.247(e)
Basic standard : ANSI C63.10:2020
Limits : < 8 dBm / 3kHz
Kind of test site : Shielded Room

Test Setup

Date of testing : 2026-06-16 to 2026-06-17
Input voltage : Fully charged battery
Operation mode : B
Test channel : Low / Middle / High
Ambient temperature : 24 °C
Relative humidity : 56 %
Atmospheric pressure : 101.1 kPa

For the measurement records, refer to the appendix B.

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:

Seite 19 von 28
Page 19 of 28

5.1.4 6dB Bandwidth

RESULT:

Pass

Test Specification

Test standard : FCC Part 15.247(a)(2)
Basic standard : ANSI C63.10:2020
Limits : > 500 kHz
Kind of test site : Shielded Room

Test Setup

Date of testing : 2026-06-16 to 2026-06-17
Input voltage : Fully charged battery
Operation mode : B
Test channel : Low / Middle / High
Ambient temperature : 24 °C
Relative humidity : 56 %
Atmospheric pressure : 101.1 kPa

For the measurement records, refer to the appendix B.

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:

Seite 20 von 28
Page 20 of 28

5.1.5 99% Bandwidth

RESULT:

Pass

Test Specification

Test standard : FCC Part 15.247(a)
Basic standard : ANSI C63.10:2020
Kind of test site : Shielded Room

Test Setup

Date of testing : 2026-06-16 to 2026-06-17
Input voltage : Fully charged battery
Operation mode : A, B
Test channel : Low / Middle / High
Ambient temperature : 24 °C
Relative humidity : 56 %
Atmospheric pressure : 101.1 kPa

For the measurement records, refer to the appendix A, B.

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:

Seite 21 von 28
Page 21 of 28

5.1.6 20dB Bandwidth

RESULT:

Pass

Test Specification

Test standard : FCC Part 15.247(a)(1)
Basic standard : ANSI C63.10:2020
Kind of test site : Shielded Room

Test Setup

Date of testing : 2026-06-16 to 2026-06-17
Input voltage : Fully charged battery
Operation mode : A
Test channel : Low / Middle / High
Ambient temperature : 24 °C
Relative humidity : 56 %
Atmospheric pressure : 101.1 kPa

For the measurement records, refer to the appendix A.

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:

Seite 22 von 28
Page 22 of 28

5.1.7 Carrier Frequency Separation

RESULT:

Pass

Test Specification

Test standard	: FCC Part 15.247(a)(1)
Basic standard	: ANSI C63.10:2020
Limits	: $\geq 25\text{kHz}$ or $2/3$ of 20dB bandwidth, whichever is greater
Kind of test site	: Shielded Room

Test Setup

Date of testing	: 2026-06-16 to 2026-06-17
Input voltage	: Fully charged battery
Operation mode	: C
Ambient temperature	: $24\text{ }^{\circ}\text{C}$
Relative humidity	: 56 %
Atmospheric pressure	: 101.1 kPa

For the measurement records, refer to the appendix A.

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:

Seite 23 von 28
Page 23 of 28

5.1.8 Number of Hopping Frequency

RESULT:

Pass

Test Specification

Test standard	: FCC part 15.247(a)(1)(iii)
Basic standard	: ANSI C63.10:2020
Limits	: ≥ 15 non-overlapping channels
Kind of test site	: Shielded Room

Test Setup

Date of testing	: 2026-06-16 to 2026-06-17
Input voltage	: Fully charged battery
Operation mode	: C
Ambient temperature	: 24 °C
Relative humidity	: 56 %
Atmospheric pressure	: 101.1 kPa

For the measurement records, refer to the appendix A.

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:

Seite 24 von 28
Page 24 of 28

5.1.9 Time of Occupancy

RESULT:

Pass

Test Specification

Test standard : FCC part 15.247(a)(1)(iii)
Basic standard : ANSI C63.10:2020
Limits : < 0.4s
Kind of test site : Shielded Room

Test Setup

Date of testing : 2026-06-16 to 2026-06-17
Input voltage : Fully charged battery
Operation mode : C
Ambient temperature : 24 °C
Relative humidity : 56 %
Atmospheric pressure : 101.1 kPa

For the measurement records, refer to the appendix A.

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:Seite 25 von 28
Page 25 of 28

5.1.10 Conducted Spurious Emissions Measured in 100 kHz Bandwidth

RESULT:

Pass

Test Specification

Test standard	: FCC Part 15.247(d)
Basic standard	: ANSI C63.10:2020
Limits	: 20dB (below that in the 100kHz bandwidth within the band that contains the highest level of the desired power); In addition, radiated emissions which fall in the restricted bands, must also comply with the radiated emission limits specified in 15.209(a)
Kind of test site	: Shielded Room

Test Setup

Date of testing	: 2026-06-16 to 2026-06-17
Input voltage	: Fully charged battery
Operation mode	: A, B, C
Test channel	: Low / Middle / High
Ambient temperature	: 24 °C
Relative humidity	: 56 %
Atmospheric pressure	: 101.1 kPa

Test results of 100kHz Bandwidth of Frequency Band Edge by Conducted method refer to test plots, and compliance is achieved as well.

For the measurement records, refer to the appendix A, B.

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:Seite 26 von 28
Page 26 of 28

5.1.11 Radiated Spurious Emission

RESULT:

Pass

Test Specification

Test standard	: FCC Part 15.247(d) & FCC Part 15.205
Basic standard	: ANSI C63.10:2020
Limits	: Refer to 15.209(a) of FCC part 15.247(d)
Kind of test site	: 3m Semi-anechoic Chamber

Test Setup

Date of testing	: 2026-06-17 to 2026-06-22
Input voltage	: Fully charged battery
Operation mode	: A, B
Test channel	: Low / Middle / High
Ambient temperature	: Refer to test result
Relative humidity	: Refer to test result
Atmospheric pressure	: 101.1 kPa

Remark:

Testing was carried out within frequency range 9kHz to the tenth harmonics. Only the worst case spurious emissions configuration of the each mode were reported.

For the measurement records, refer to the appendix A, B.

Prüfbericht - Nr.: CN26V5UF 001
Test Report No.:

Seite 27 von 28
Page 27 of 28

5.1.12 Conducted Emission on AC Mains

RESULT:

Pass

Test Specification

Test standard	: FCC Part 15.207(a)
Basic standard	: ANSI C63.10:2020
Frequency range	: 0.15 – 30MHz
Classification	: Class B
Limits	: FCC Part 15.207(a)
Kind of test site	: Shielded Room

Test Setup

Date of testing	: 2026-06-27
Input voltage	: AC 120V, 60Hz
Operation mode	: D
Ambient temperature	: Refer to test result
Relative humidity	: Refer to test result
Atmospheric pressure	: 101.2 kPa

For the measurement records, refer to the appendix A.

6 Photographs of the Test Set-Up

For photographs of the test set-up, refer to the appendix C.

7 List of Tables

Table 1: List of Test and Measurement Equipment.....	6
Table 2: Measurement Uncertainty	7
Table 3: General Information of EUT.....	9
Table 4: RF Channel and Frequency of Bluetooth BR & EDR	10
Table 5: RF Channel and Frequency of Bluetooth LE	10
Table 6: List of Accessories and Auxiliary Equipment.....	12
Table 7: Test Result of Maximum Conducted Output Power, BR & EDR	17
Table 8: Test Result of Maximum Conducted Output Power, Bluetooth LE.....	17

Appendix A: Test Results of Bluetooth BR & EDR

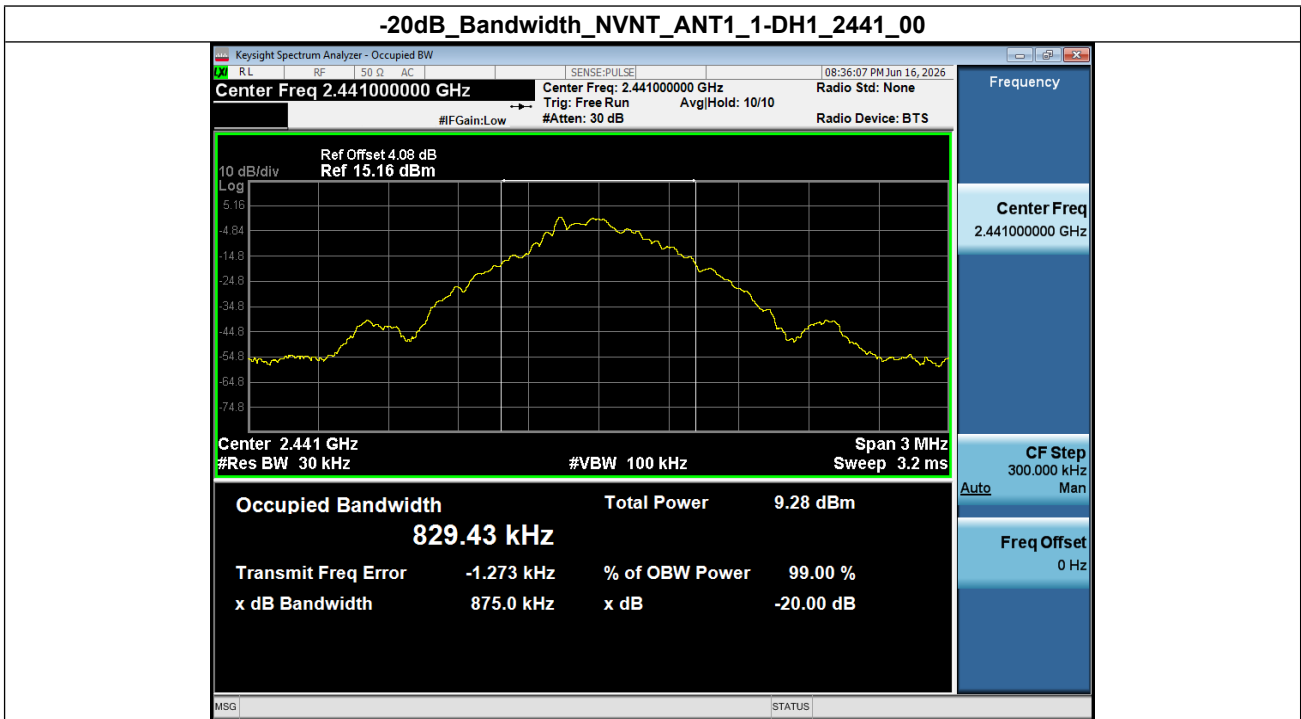
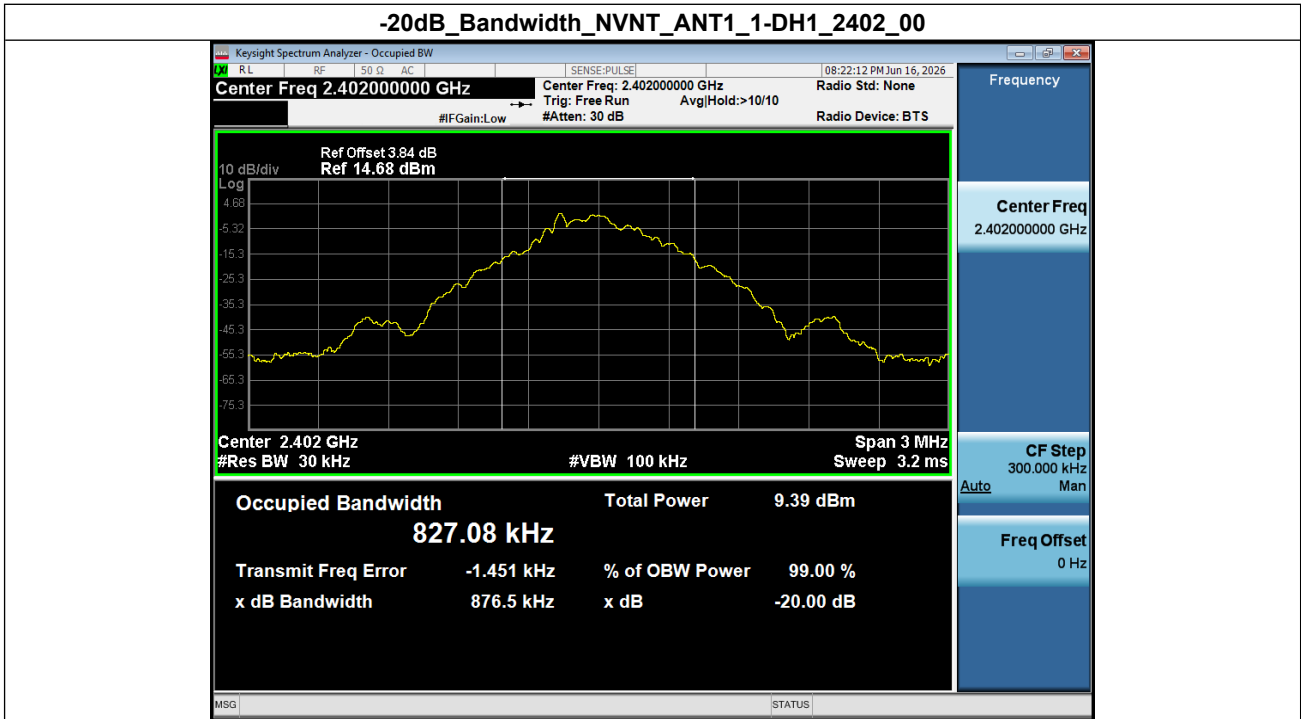
APPENDIX A: TEST RESULTS OF BLUETOOTH BR & EDR.....	1
APPENDIX A.1: TEST RESULTS OF 20DB BANDWIDTH	2
Test Result	2
Test Graphs	3
APPENDIX A.2: TEST RESULTS OF 99% BANDWIDTH	8
Test Result	8
Test Graphs	9
APPENDIX A.3: TEST RESULTS OF CARRIER FREQUENCY SEPARATION	14
Test Result	14
Test Graphs	15
APPENDIX A.4: TEST RESULTS OF TIME OF OCCUPANCY	17
Test Result	17
Test Graphs	18
APPENDIX A.5: TEST RESULTS OF NUMBER OF HOPPING FREQUENCY	27
Test Result	27
Test Graphs	28
APPENDIX A.6: TEST RESULTS OF BAND EDGE MEASUREMENTS	30
Test Result	30
Test Graphs	31
APPENDIX A.7: TEST RESULTS OF CONDUCTED SPURIOUS EMISSION	43
Test Result	43
Test Graphs	44
APPENDIX A.8: TEST RESULTS OF RADIATED SPURIOUS EMISSIONS	53
30MHz - 1GHz	53
1GHz - 18GHz	65
APPENDIX A.9: TEST RESULTS OF RADIATED EMISSIONS IN RESTRICTED BANDS	77
APPENDIX A.10: TEST RESULTS OF CONDUCTED EMISSION ON AC MAINS	89

Appendix A.1: Test Results of 20dB Bandwidth

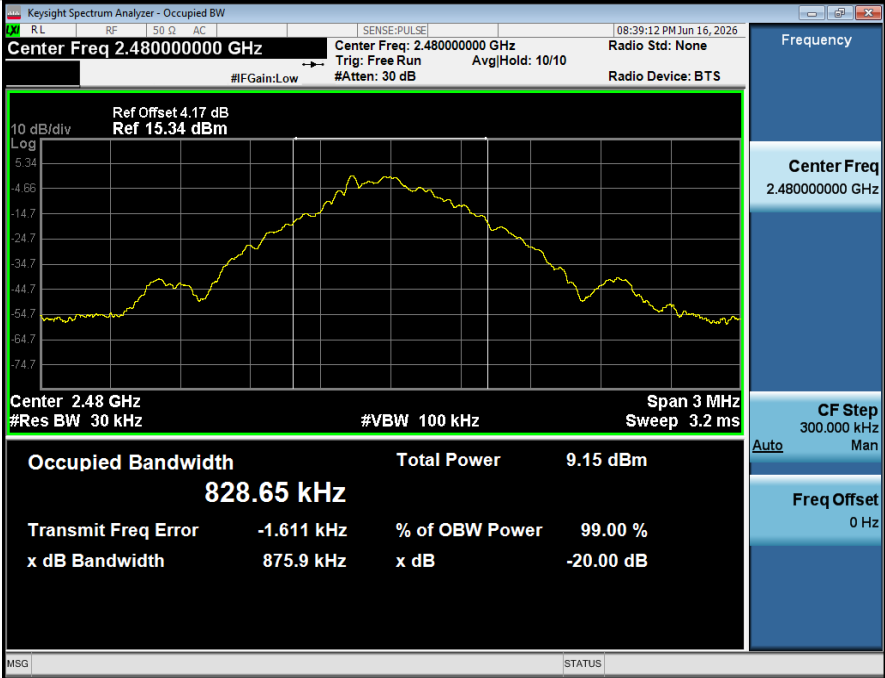
Test Result

Condition	Antenna	Modulation	Frequency (MHz)	-20dB BW(MHz)	if larger than CFS
NVNT	ANT1	1-DH1	2402.00	0.877	No
NVNT	ANT1	1-DH1	2441.00	0.875	No
NVNT	ANT1	1-DH1	2480.00	0.876	No
NVNT	ANT1	2-DH1	2402.00	1.208	Yes
NVNT	ANT1	2-DH1	2441.00	1.209	Yes
NVNT	ANT1	2-DH1	2480.00	1.209	Yes
NVNT	ANT1	3-DH1	2402.00	1.214	Yes
NVNT	ANT1	3-DH1	2441.00	1.215	Yes
NVNT	ANT1	3-DH1	2480.00	1.215	Yes

Test Graphs



-20dB_Bandwidth_NVNT_ANT1_1-DH1_2480_00



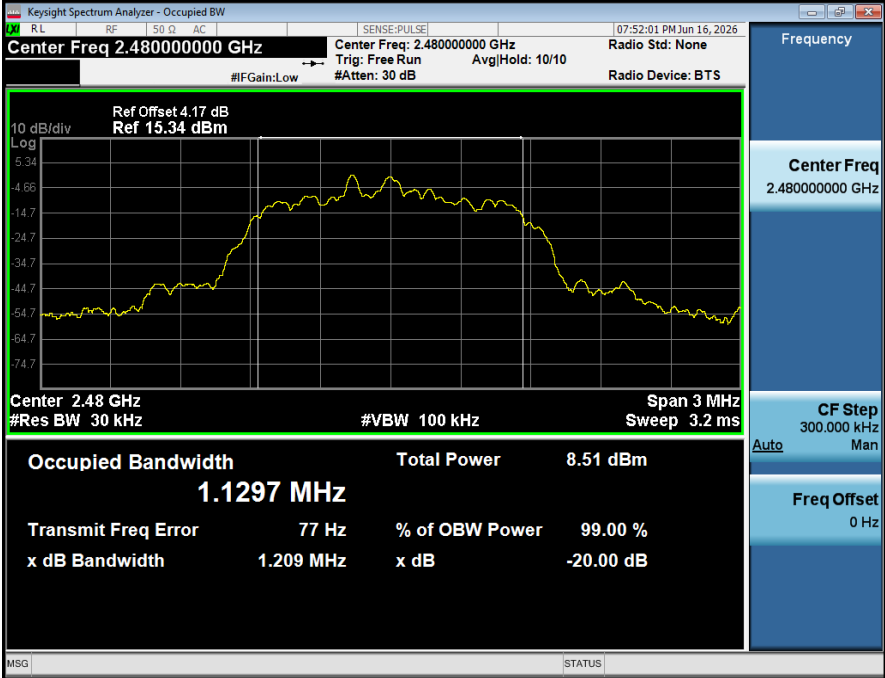
-20dB_Bandwidth_NVNT_ANT1_2-DH1_2402_00



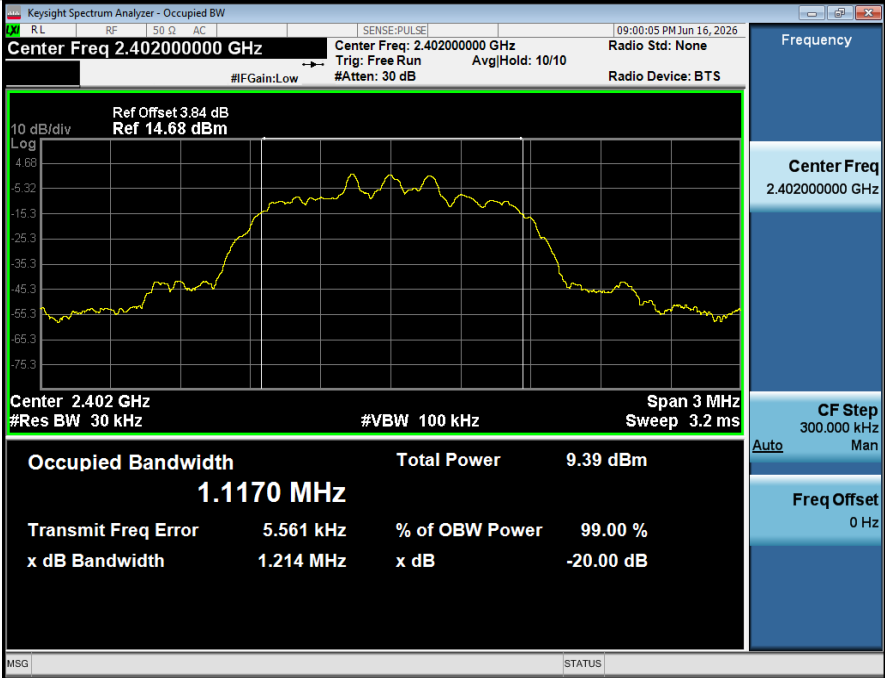
-20dB_Bandwidth_NVNT_ANT1_2-DH1_2441_00



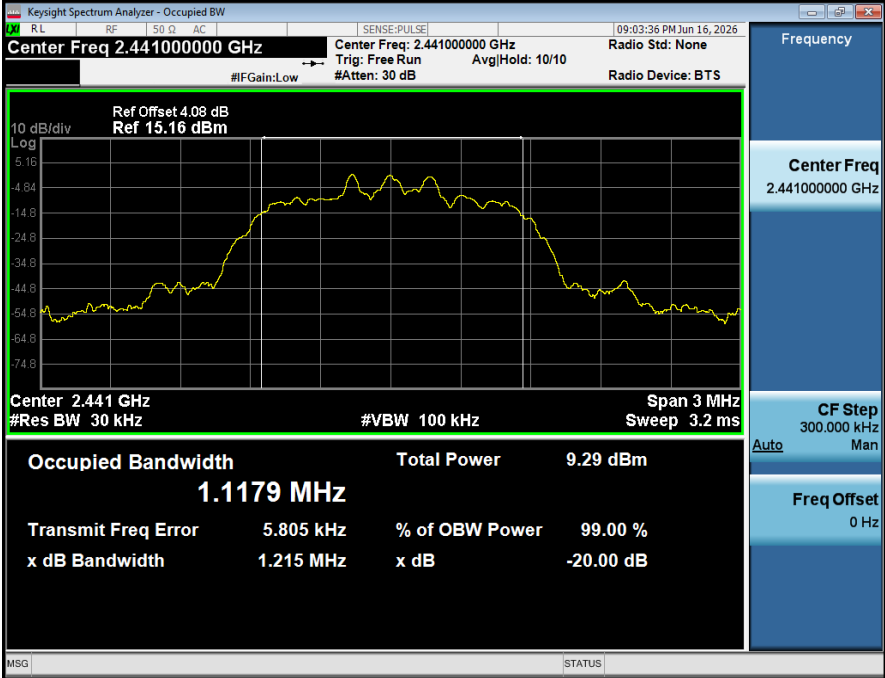
-20dB_Bandwidth_NVNT_ANT1_2-DH1_2480_00



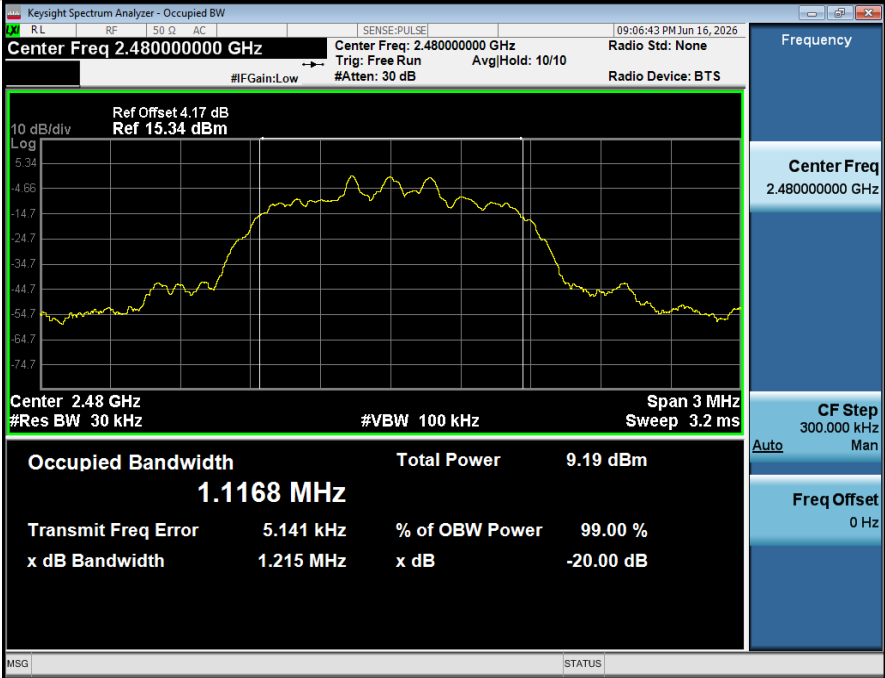
-20dB_Bandwidth_NVNT_ANT1_3-DH1_2402_00



-20dB_Bandwidth_NVNT_ANT1_3-DH1_2441_00



-20dB_Bandwidth_NVNT_ANT1_3-DH1_2480_00

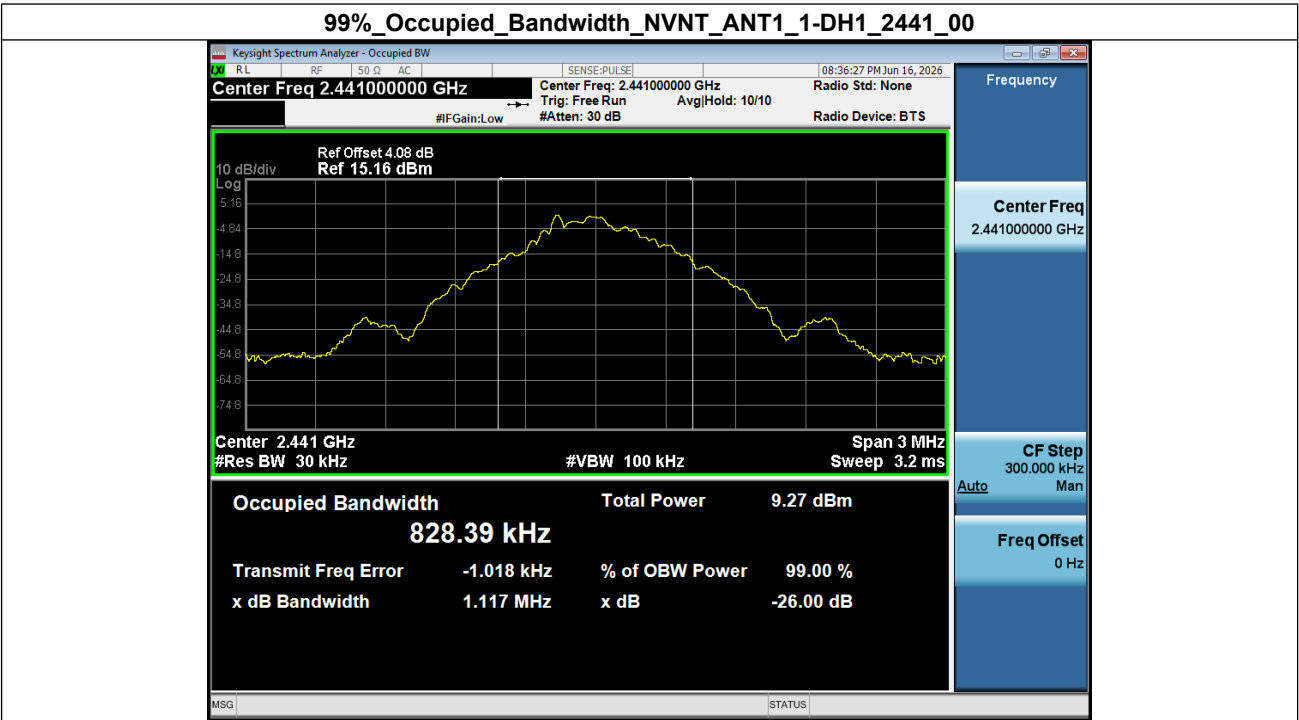
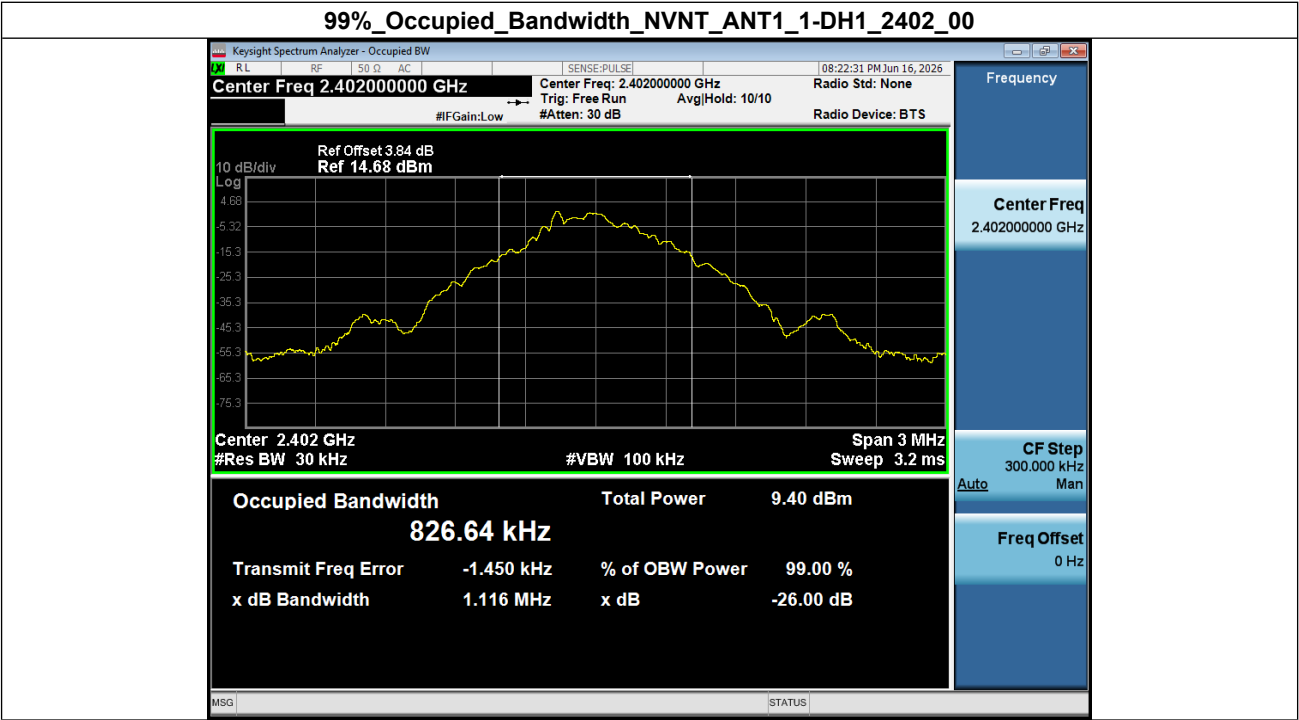


Appendix A.2: Test Results of 99% Bandwidth

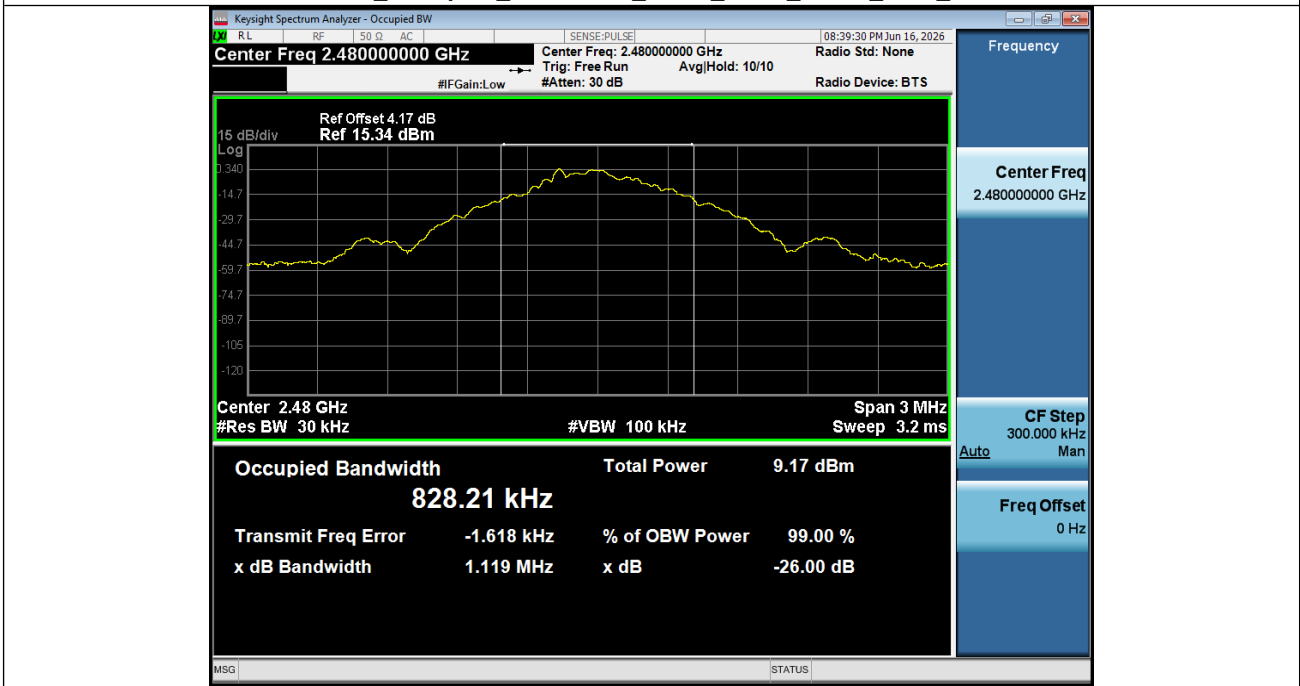
Test Result

Condition	Antenna	Modulation	Frequency (MHz)	99% BW (MHz)
NVNT	ANT1	1-DH1	2402.00	0.827
NVNT	ANT1	1-DH1	2441.00	0.828
NVNT	ANT1	1-DH1	2480.00	0.828
NVNT	ANT1	2-DH1	2402.00	1.129
NVNT	ANT1	2-DH1	2441.00	1.129
NVNT	ANT1	2-DH1	2480.00	1.129
NVNT	ANT1	3-DH1	2402.00	1.117
NVNT	ANT1	3-DH1	2441.00	1.118
NVNT	ANT1	3-DH1	2480.00	1.116

Test Graphs



99%_Occupied_Bandwidth_NVNT_ANT1_1-DH1_2480_00



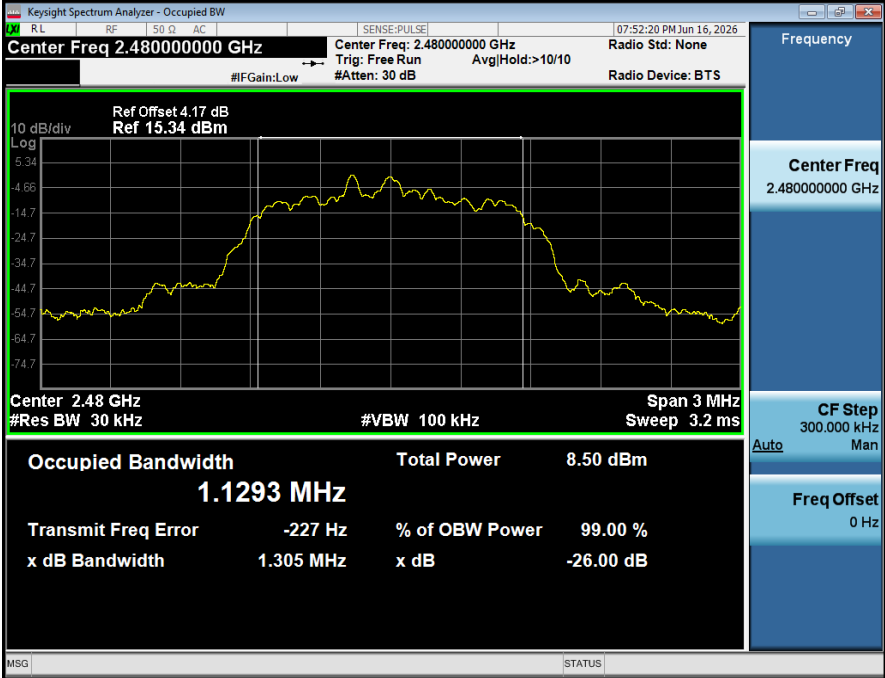
99%_Occupied_Bandwidth_NVNT_ANT1_2-DH1_2402_00



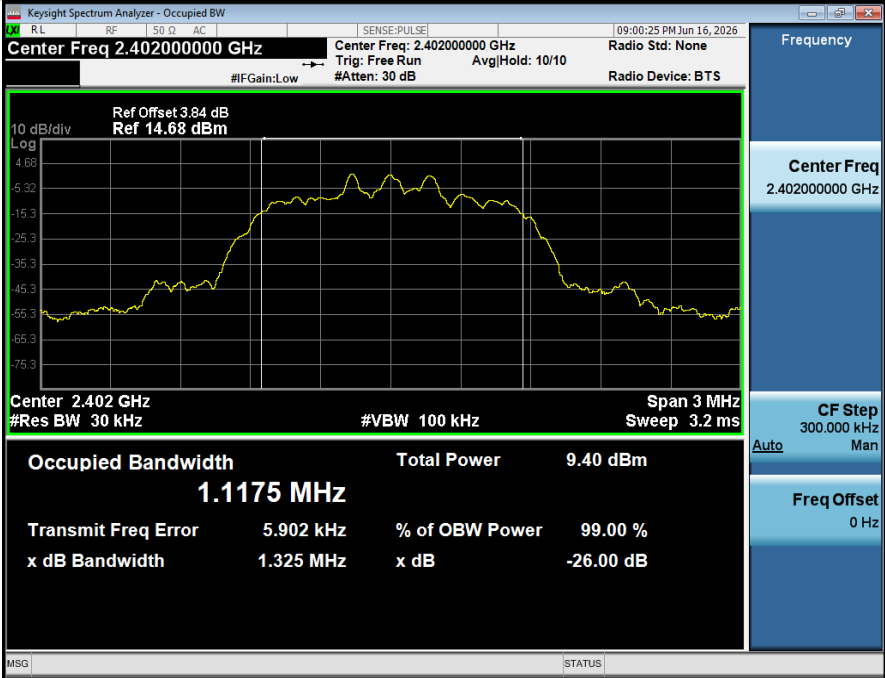
99%_Occupied_Bandwidth_NVNT_ANT1_2-DH1_2441_00



99%_Occupied_Bandwidth_NVNT_ANT1_2-DH1_2480_00



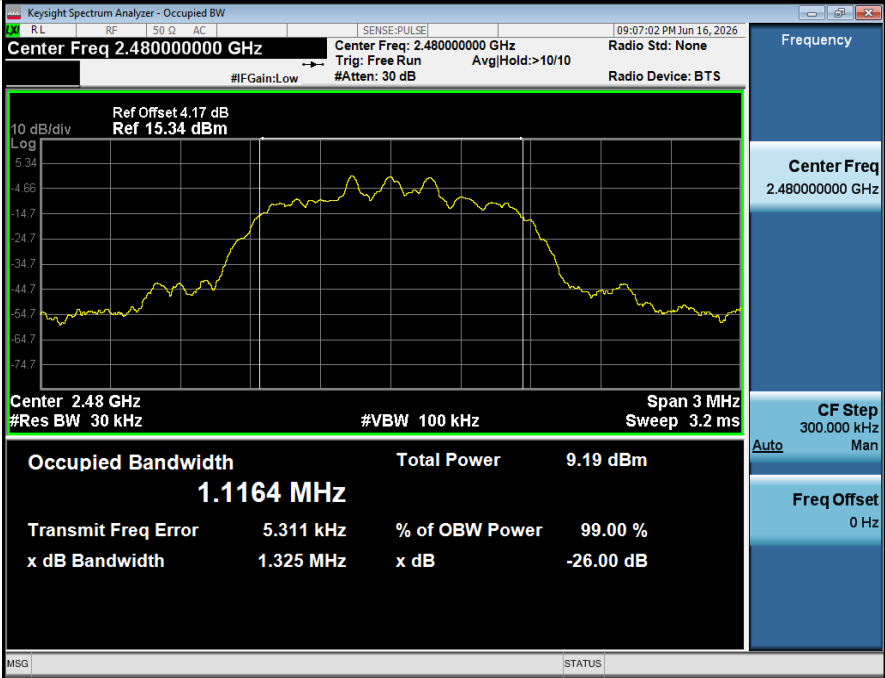
99%_Occupied_Bandwidth_NVNT_ANT1_3-DH1_2402_00



99%_Occupied_Bandwidth_NVNT_ANT1_3-DH1_2441_00



99%_Occupied_Bandwidth_NVNT_ANT1_3-DH1_2480_00



Appendix A.3: Test Results of Carrier Frequency Separation

Test Result

Condition	Antenna	Modulation	Frequency (MHz)	Hopping NO.0 (MHz)	Hopping NO.1 (MHz)	Carrier Frequencies Separation(MHz)	Limit (MHz)	Result
NVNT	ANT1	1-DH1	2441.00	2440.834	2441.836	1.00	0.875	Pass
NVNT	ANT1	2-DH1	2441.00	2440.840	2441.848	1.01	0.806	Pass
NVNT	ANT1	3-DH1	2441.00	2440.834	2441.845	1.01	0.810	Pass

Test Graphs

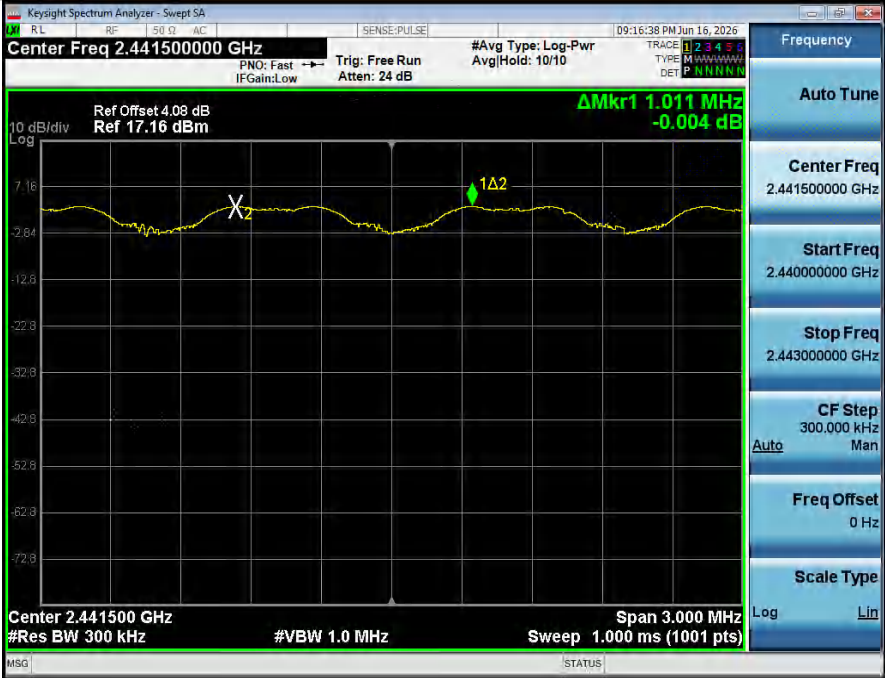
Carrier_Frequencies_Separation_(Hopping)_NVNT_ANT1_1-DH1_Hopping



Carrier_Frequencies_Separation_(Hopping)_NVNT_ANT1_2-DH1_Hopping



Carrier_Frequencies_Separation_(Hopping)_NVNT_ANT1_3-DH1_Hopping



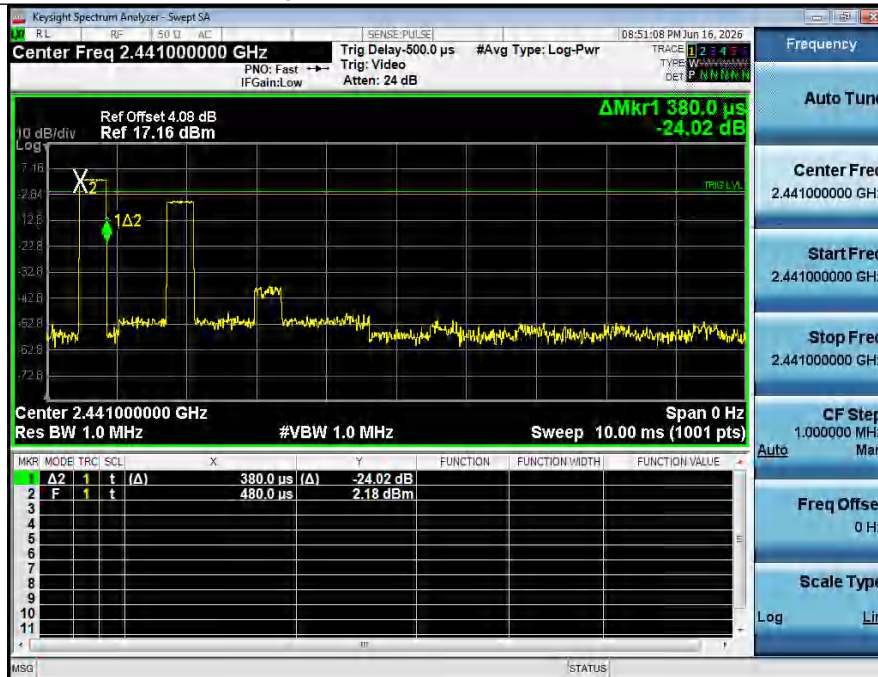
Appendix A.4: Test Results of Time of Occupancy

Test Result

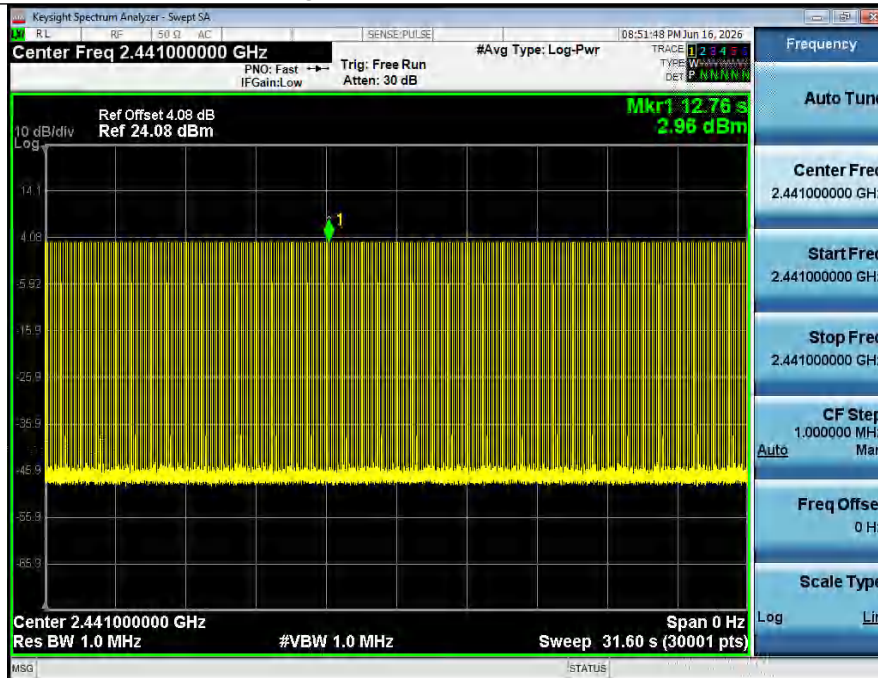
Condition	Antenna	Packet Type	Pulse Time (ms)	Hops	Dwell Time (ms)	Limit (s)	Result
NVNT	ANT1	1-DH1	0.380	320.00	121.600	0.40	Pass
NVNT	ANT1	2-DH1	0.390	320.00	124.800	0.40	Pass
NVNT	ANT1	3-DH1	0.390	320.00	124.800	0.40	Pass
NVNT	ANT1	1-DH3	1.630	160.00	260.800	0.40	Pass
NVNT	ANT1	1-DH5	2.880	107.00	308.160	0.40	Pass
NVNT	ANT1	2-DH3	1.650	160.00	264.000	0.40	Pass
NVNT	ANT1	2-DH5	2.900	106.00	307.400	0.40	Pass
NVNT	ANT1	3-DH3	1.640	160.00	262.400	0.40	Pass
NVNT	ANT1	3-DH5	2.890	106.00	306.340	0.40	Pass

Test Graphs

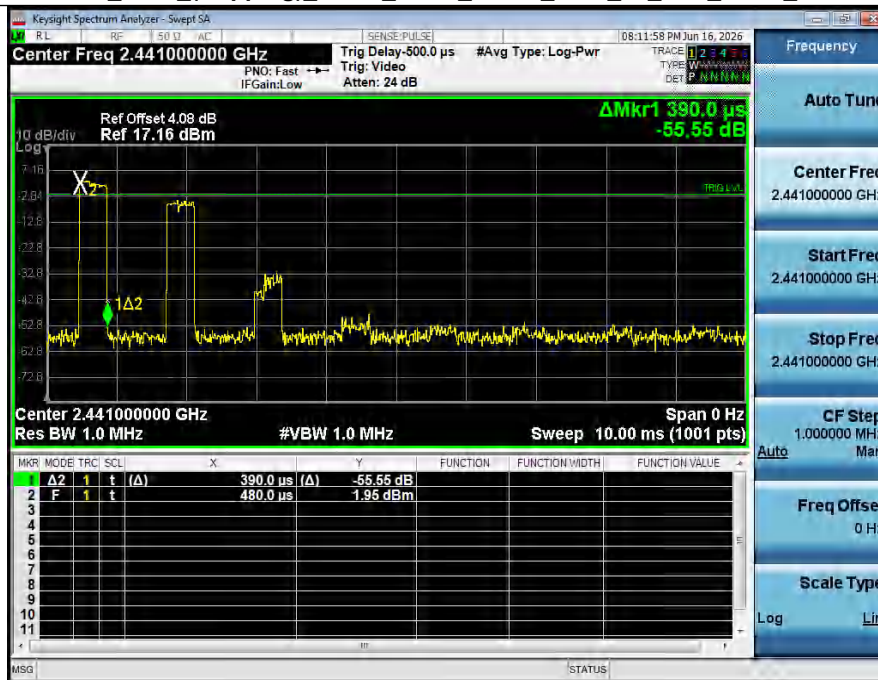
Dwell_Time_(Hopping)_NVNT_ANT1_1-DH1_2441_00_One_Burst_Time



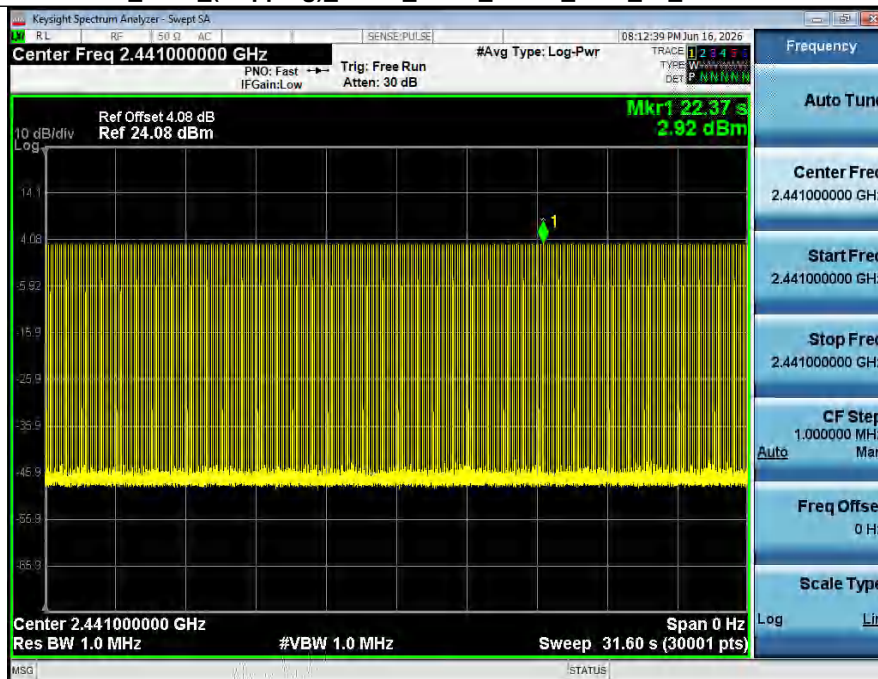
Dwell_Time_(Hopping)_NVNT_ANT1_1-DH1_2441_00_Accumulated



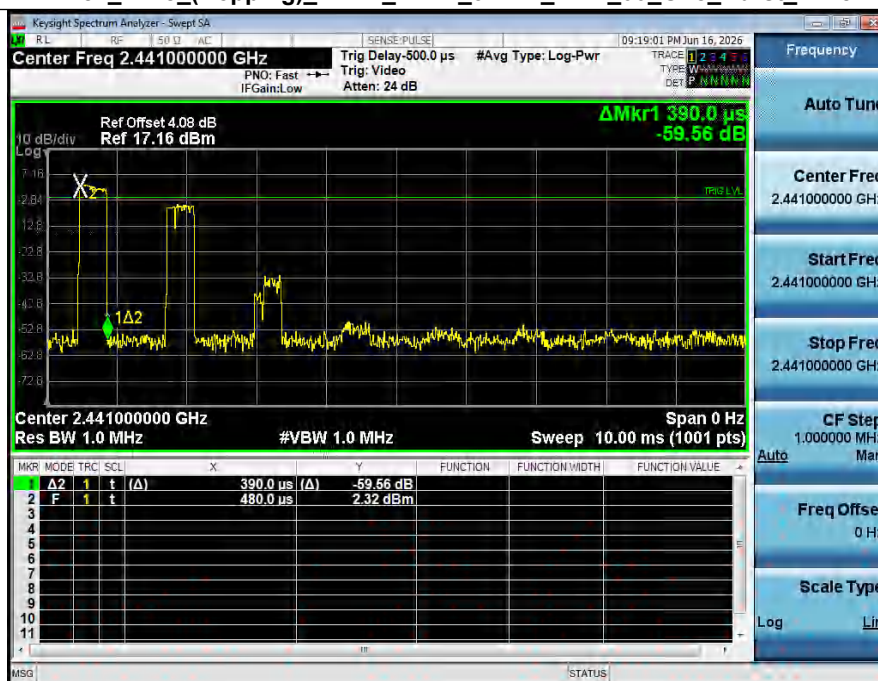
Dwell_Time_(Hopping)_NVNT_ANT1_2-DH1_2441_00_One_Burst_Time



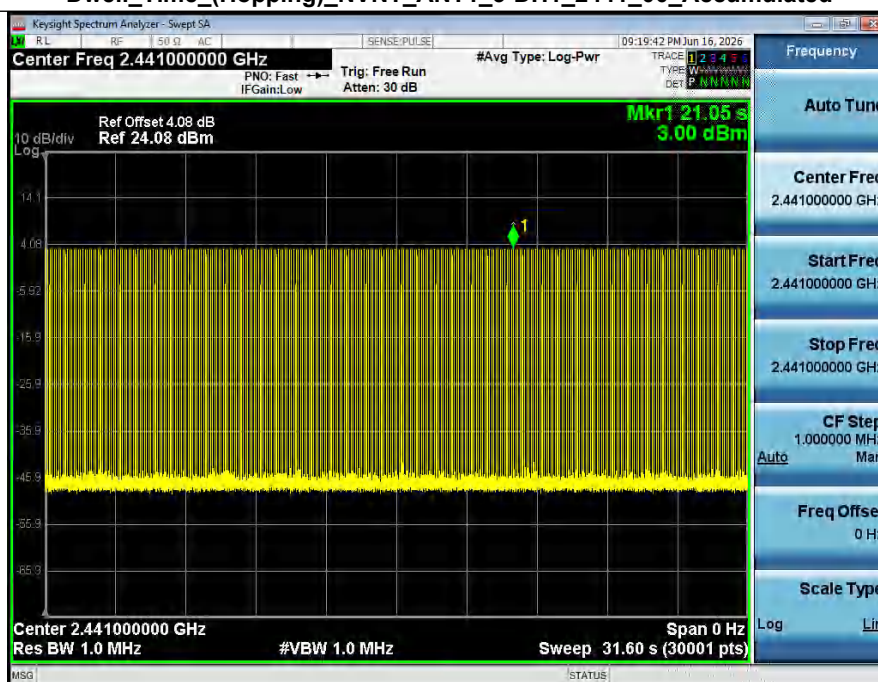
Dwell_Time_(Hopping)_NVNT_ANT1_2-DH1_2441_00_Accumulated



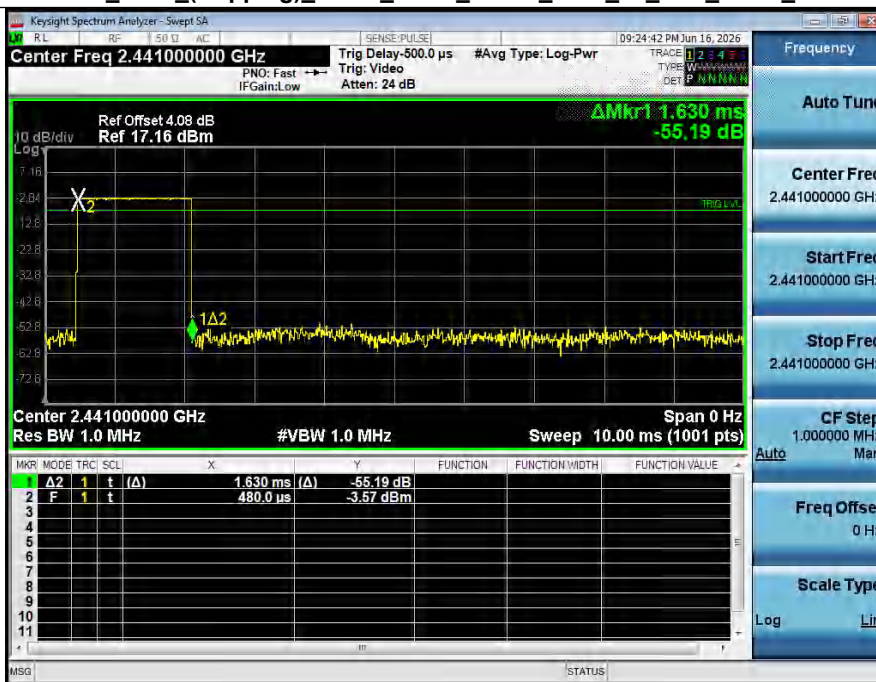
Dwell_Time_(Hopping)_NVNT_ANT1_3-DH1_2441_00_One_Burst_Time



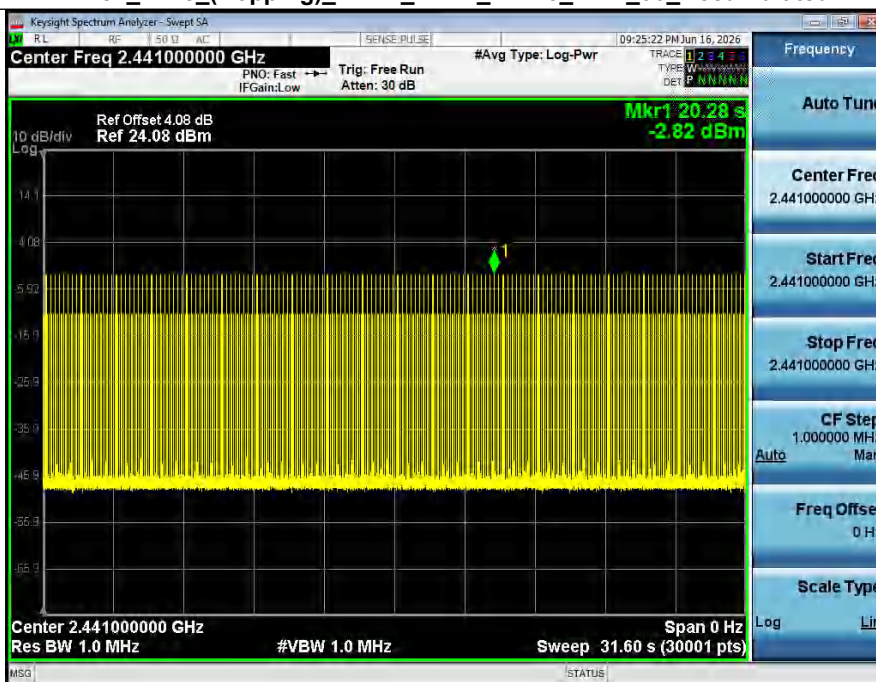
Dwell_Time_(Hopping)_NVNT_ANT1_3-DH1_2441_00_Accumulated



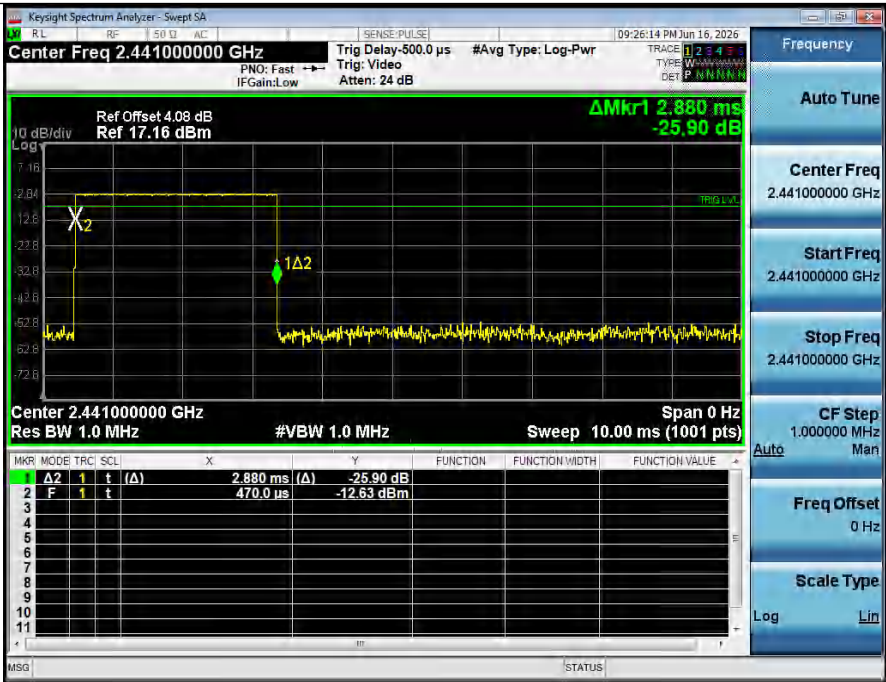
Dwell_Time_(Hopping)_NVNT_ANT1_1-DH3_2441_00_One_Burst_Time



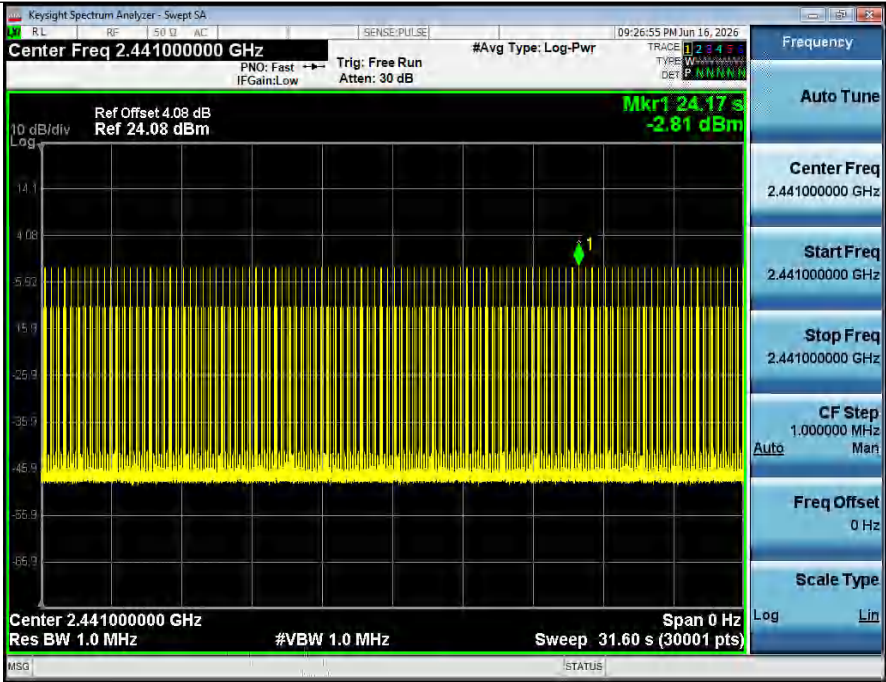
Dwell_Time_(Hopping)_NVNT_ANT1_1-DH3_2441_00_Accumulated



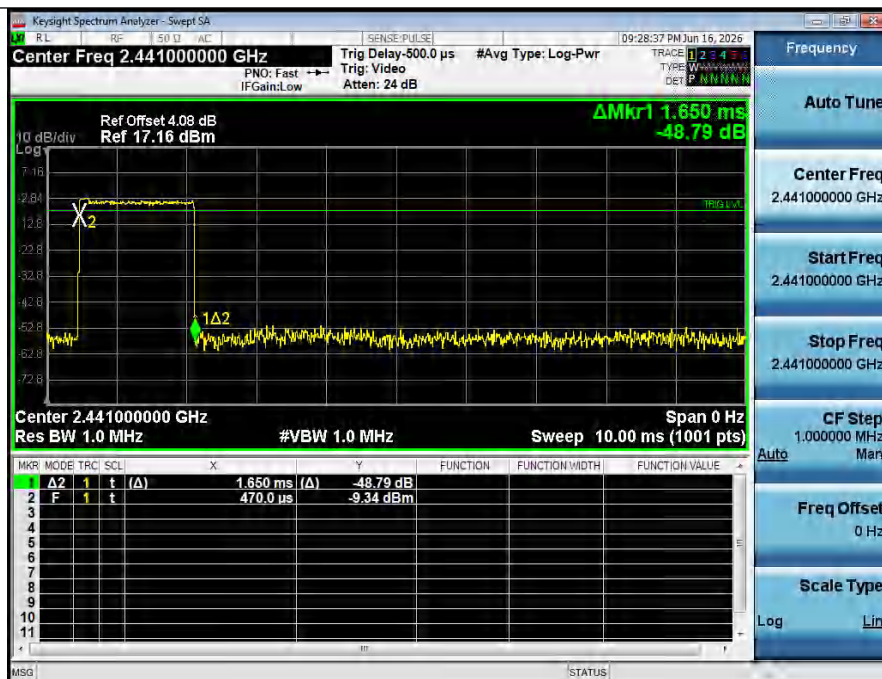
Dwell_Time_(Hopping)_NVNT_ANT1_1-DH5_2441_00_One_Burst_Time



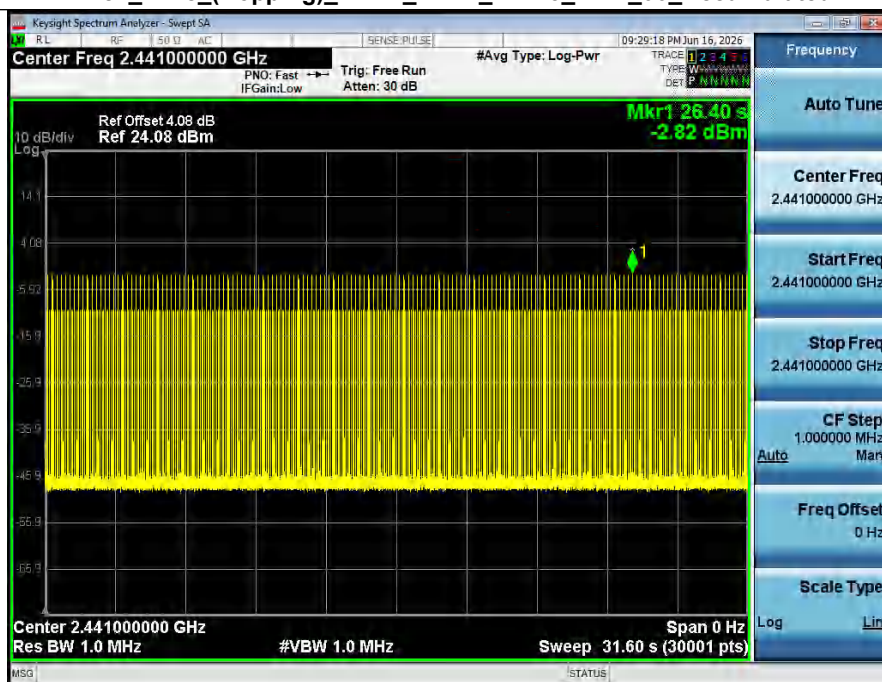
Dwell_Time_(Hopping)_NVNT_ANT1_1-DH5_2441_00_Accumulated



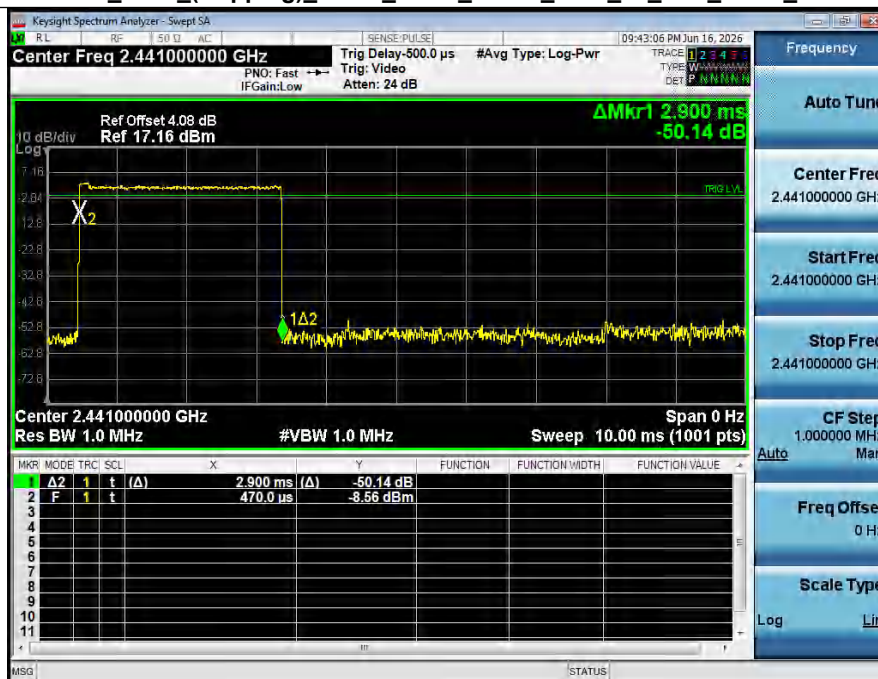
Dwell_Time_(Hopping)_NVNT_ANT1_2-DH3_2441_00_One_Burst_Time



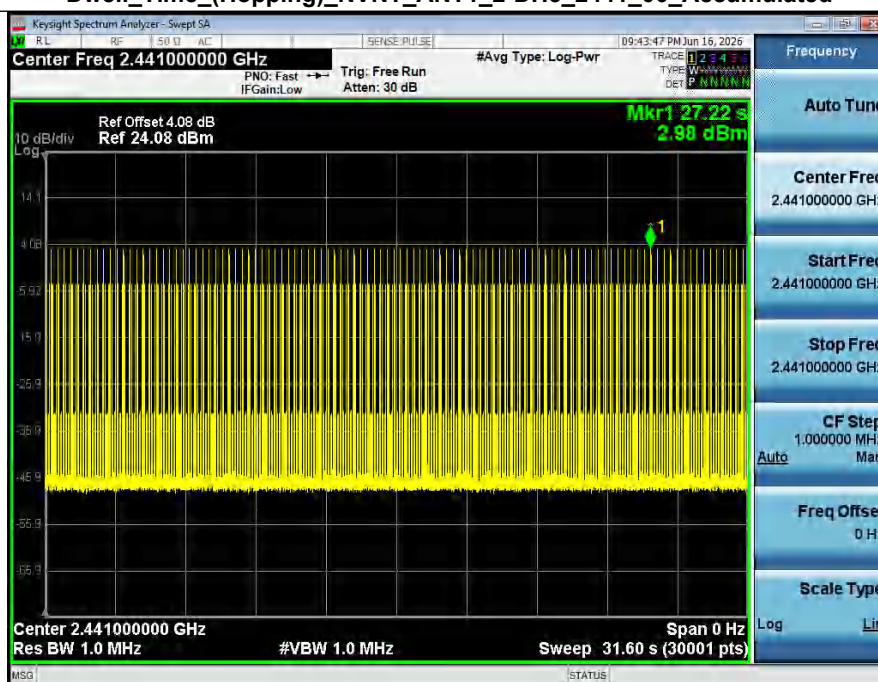
Dwell_Time_(Hopping)_NVNT_ANT1_2-DH3_2441_00_Accumulated

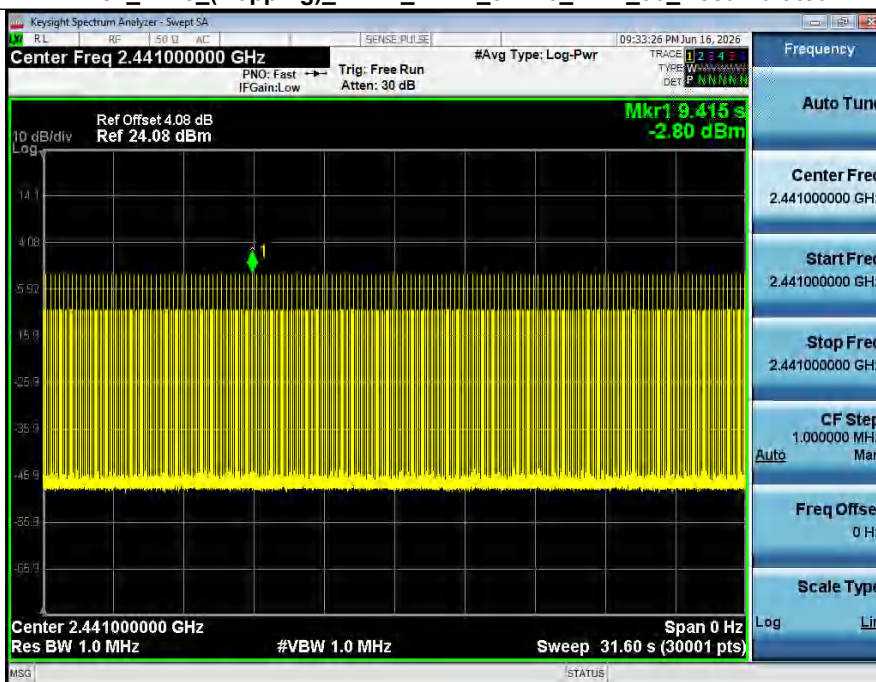
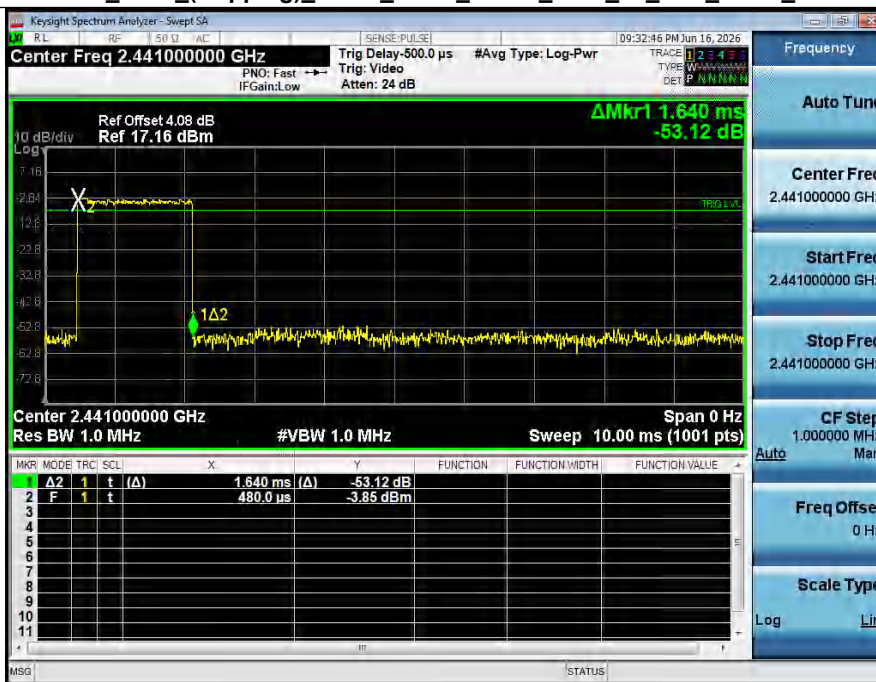


Dwell_Time_(Hopping)_NVNT_ANT1_2-DH5_2441_00_One_Burst_Time

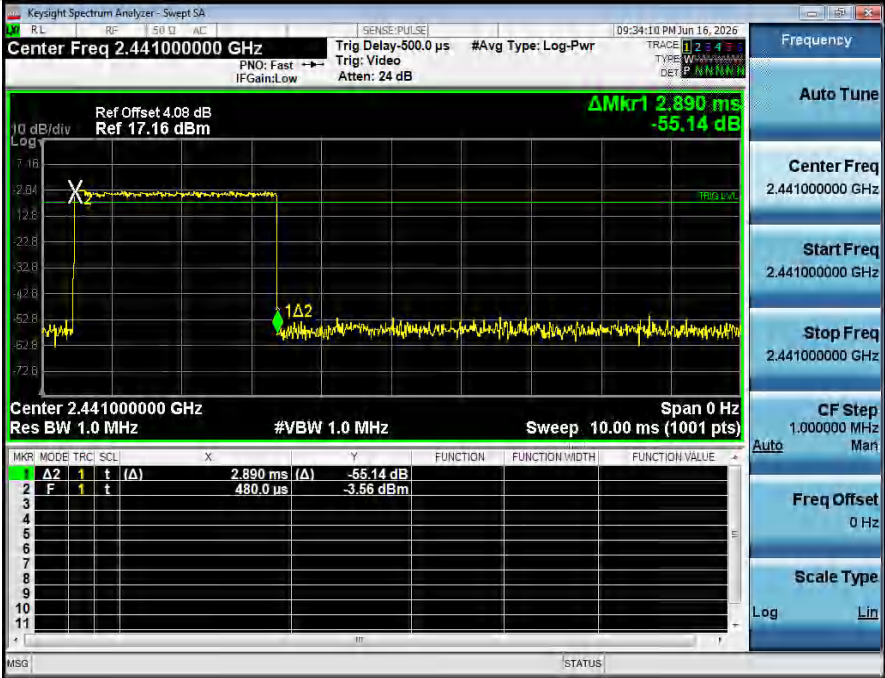


Dwell_Time_(Hopping)_NVNT_ANT1_2-DH5_2441_00_Accumulated

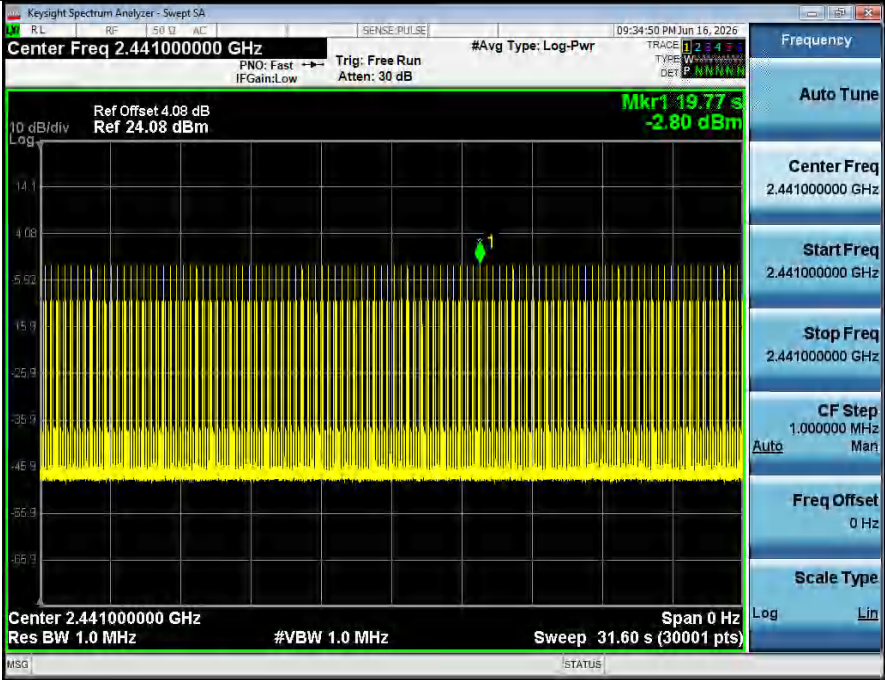




Dwell_Time_(Hopping)_NVNT_ANT1_3-DH5_2441_00_One_Burst_Time



Dwell_Time_(Hopping)_NVNT_ANT1_3-DH5_2441_00_Accumulated



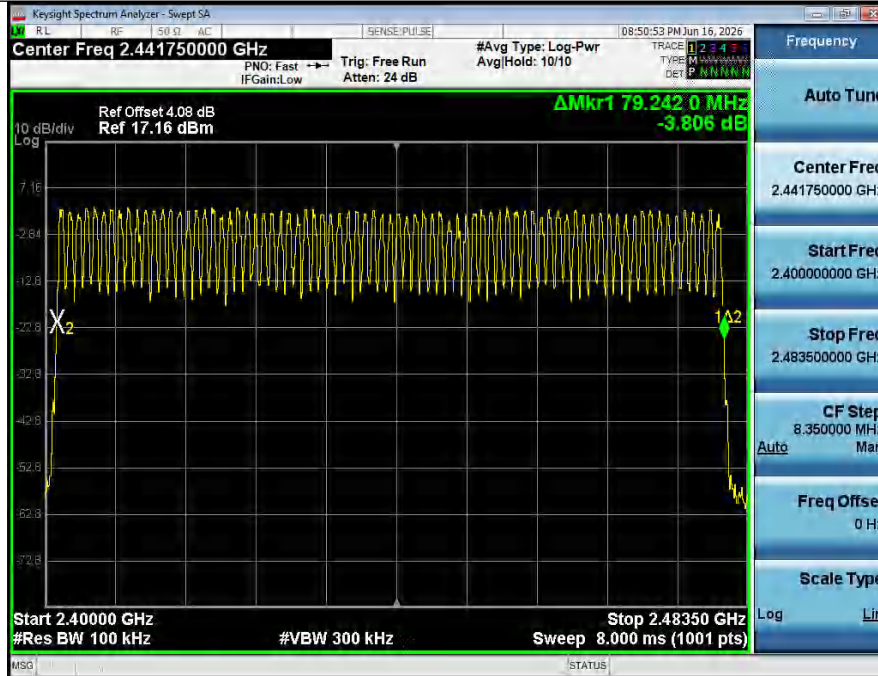
Appendix A.5: Test Results of Number of Hopping Frequency

Test Result

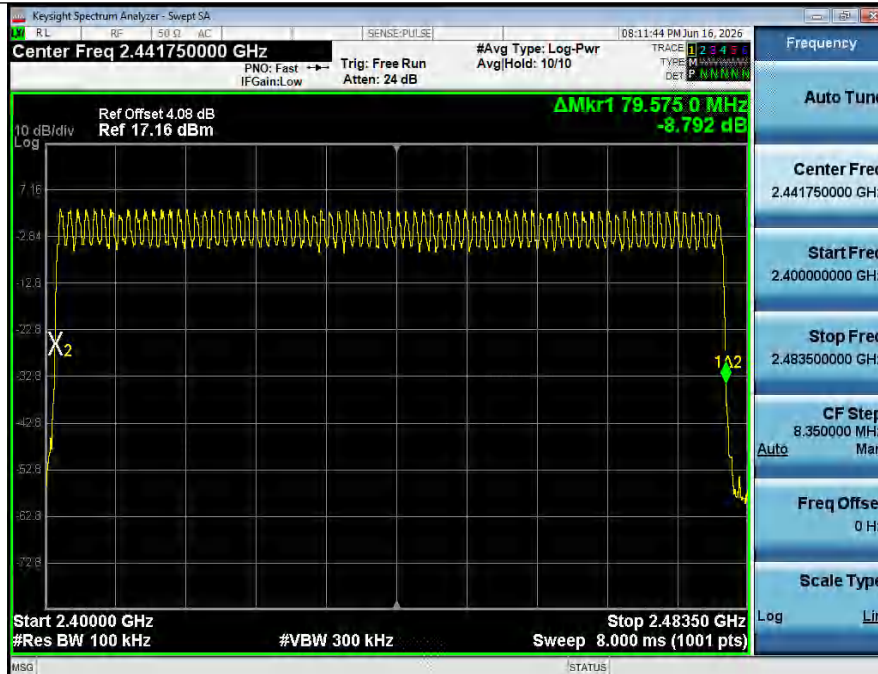
Condition	Antenna	Modulation	Hopping Num	Limit	Result
NVNT	ANT1	1-DH1	79	15	Pass
NVNT	ANT1	2-DH1	79	15	Pass
NVNT	ANT1	3-DH1	79	15	Pass

Test Graphs

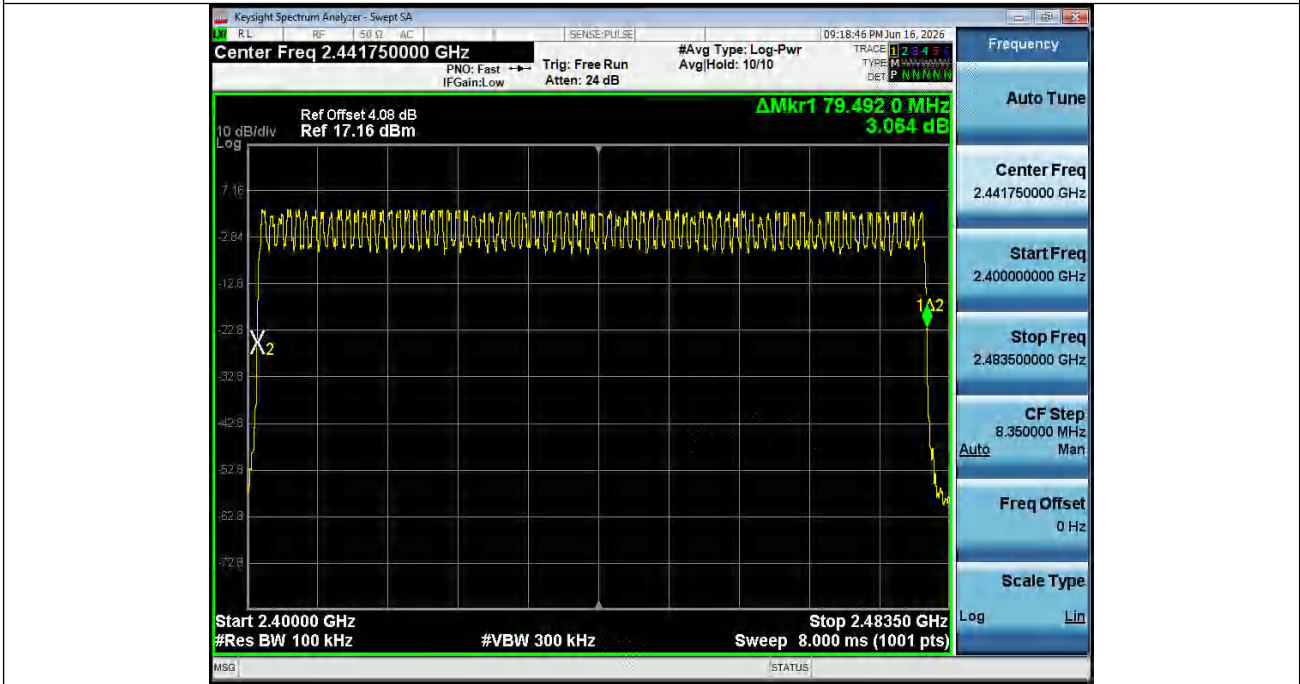
Number_of_Hopping_Channel_(Hopping)_NVNT_ANT1_1-DH1_Hopping



Number_of_Hopping_Channel_(Hopping)_NVNT_ANT1_2-DH1_Hopping



Number_of_Hopping_Channel_(Hopping)_NVNT_ANT1_3-DH1_Hopping



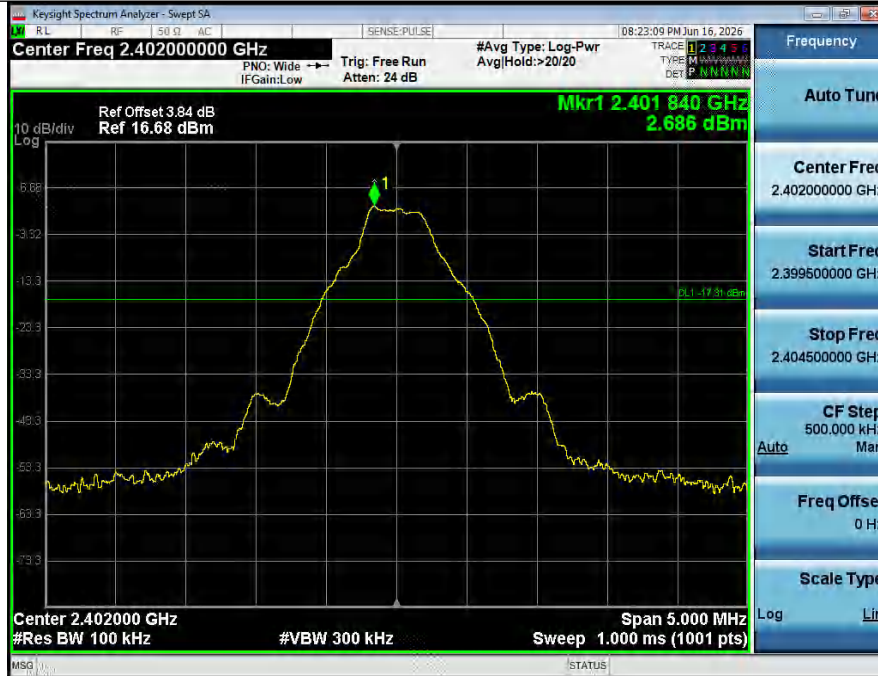
Appendix A.6: Test Results of Band Edge Measurements

Test Result

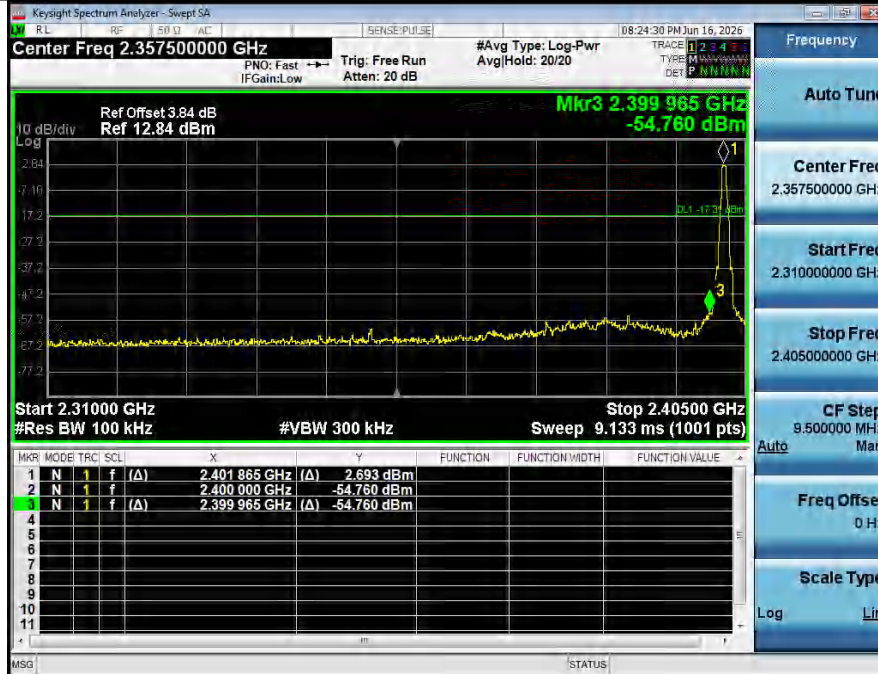
Condition	Antenna	Modulation	TX Mode	Ref_level (dBm)	Bandedge MAX.Value	Limit	Result
NVNT	ANT1	1-DH1	2402.00	2.686	-54.760	-17.314	Pass
NVNT	ANT1	1-DH1	Hopping_LCH	2.715	-55.591	-17.285	Pass
NVNT	ANT1	1-DH1	2480.00	2.408	-55.703	-17.592	Pass
NVNT	ANT1	1-DH1	Hopping_HCH	3.021	-57.695	-16.979	Pass
NVNT	ANT1	2-DH1	2402.00	2.648	-56.439	-17.352	Pass
NVNT	ANT1	2-DH1	Hopping_LCH	2.686	-57.497	-17.314	Pass
NVNT	ANT1	2-DH1	2480.00	2.397	-57.753	-17.603	Pass
NVNT	ANT1	2-DH1	Hopping_HCH	3.043	-57.969	-16.957	Pass
NVNT	ANT1	3-DH1	2402.00	2.717	-54.566	-17.283	Pass
NVNT	ANT1	3-DH1	Hopping_LCH	2.793	-55.553	-17.207	Pass
NVNT	ANT1	3-DH1	2480.00	2.510	-57.785	-17.490	Pass
NVNT	ANT1	3-DH1	Hopping_HCH	3.124	-57.579	-16.876	Pass

Test Graphs

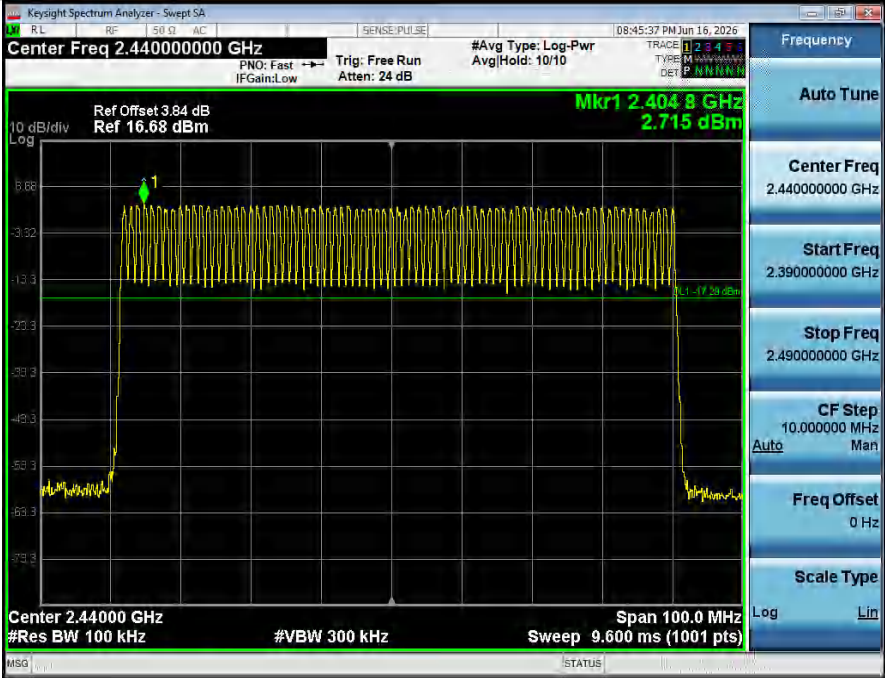
1_Reference_Level_NVNT_ANT1_1-DH1_2402_00



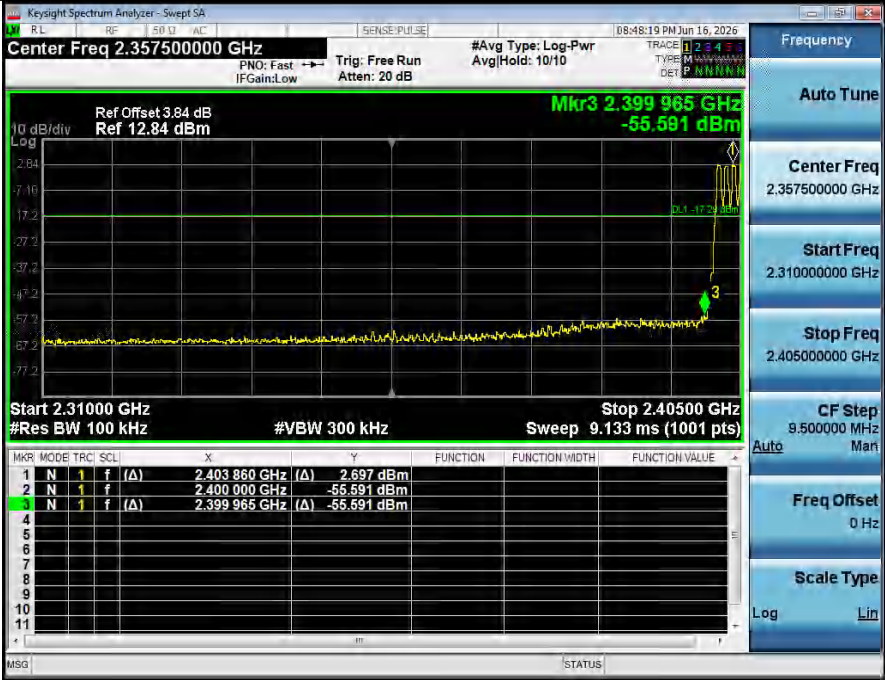
2_Bandedge_NVNT_ANT1_1-DH1_2402_00



1_Reference_Level_Hopping_NVNT_ANT1_1-DH1_Hopping



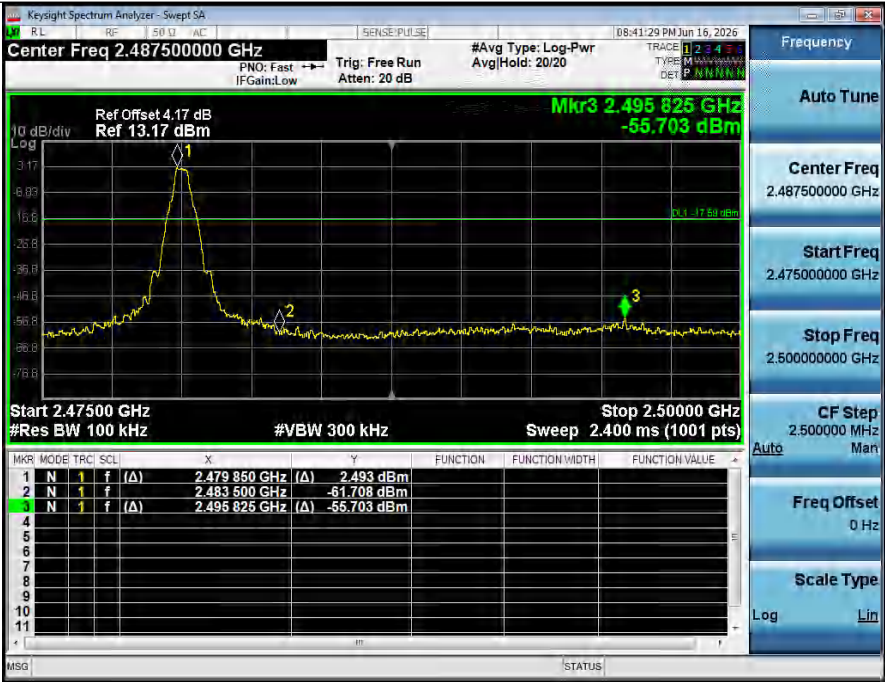
2_Band_Edge_(Hopping)_NVNT_ANT1_1-DH1_Hopping



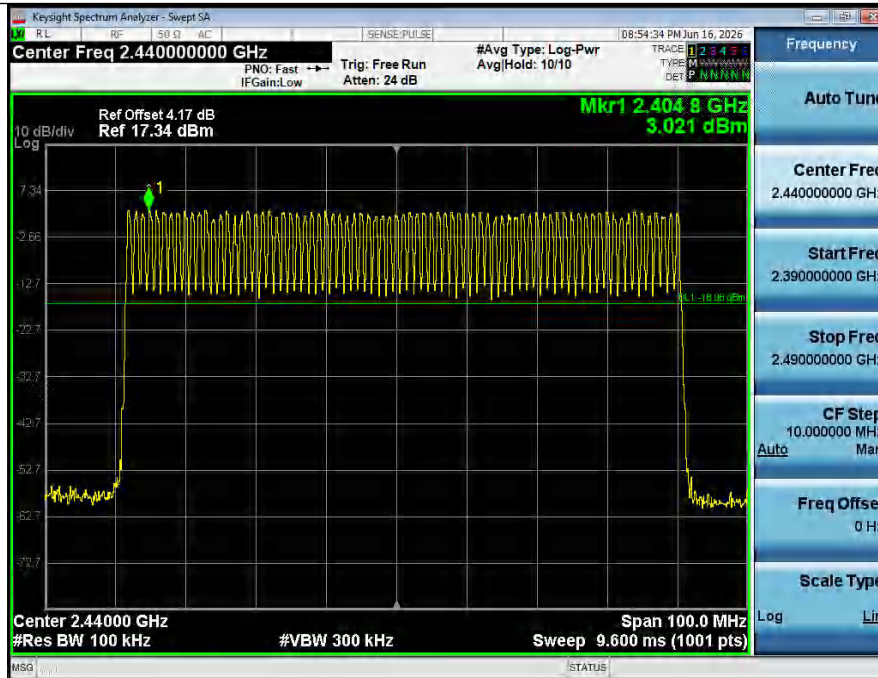
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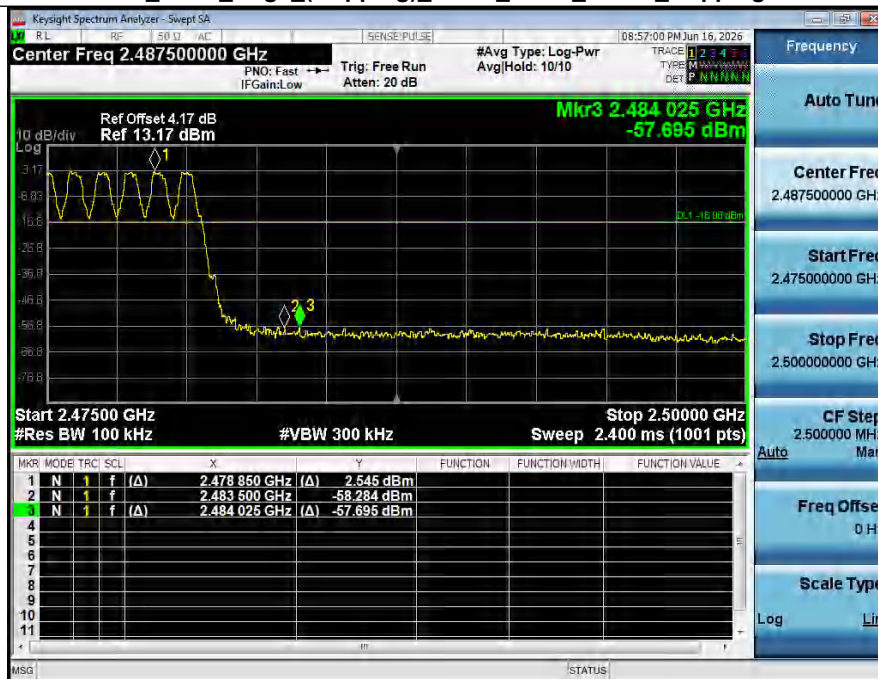
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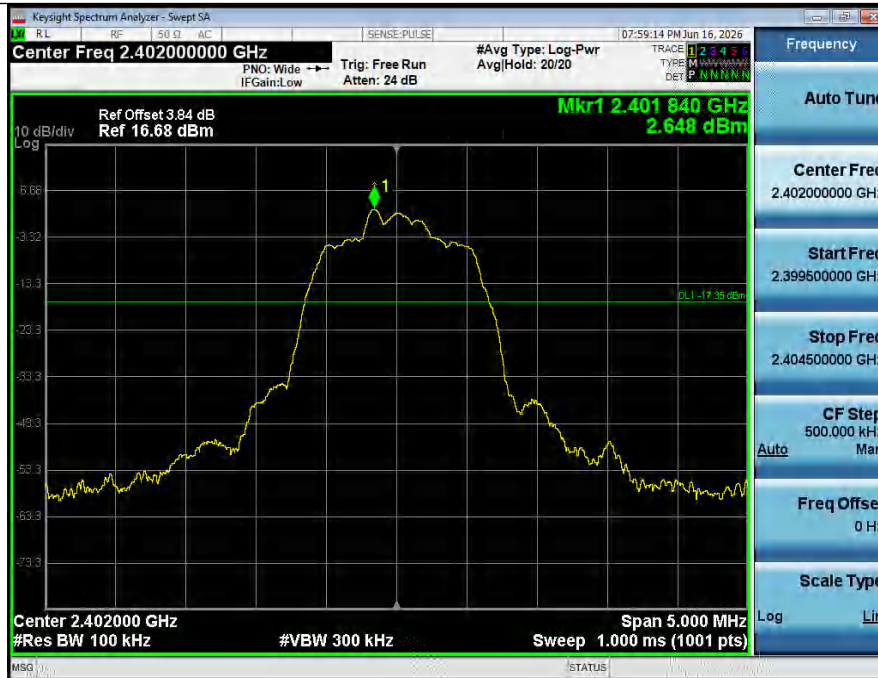
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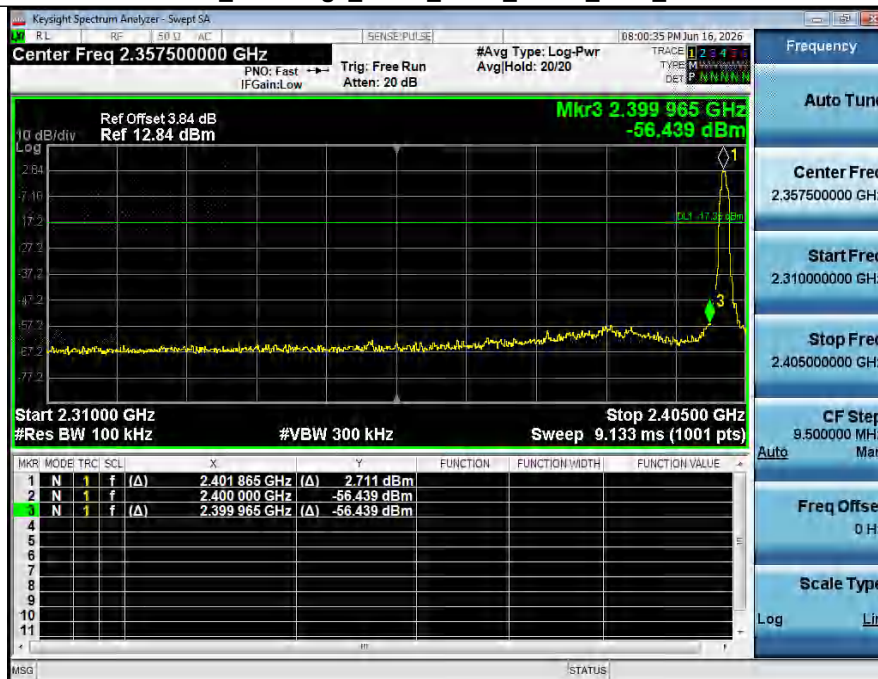
2_Band_Edge_(Hopping)_NVNT_ANT1_1-DH1_Hopping



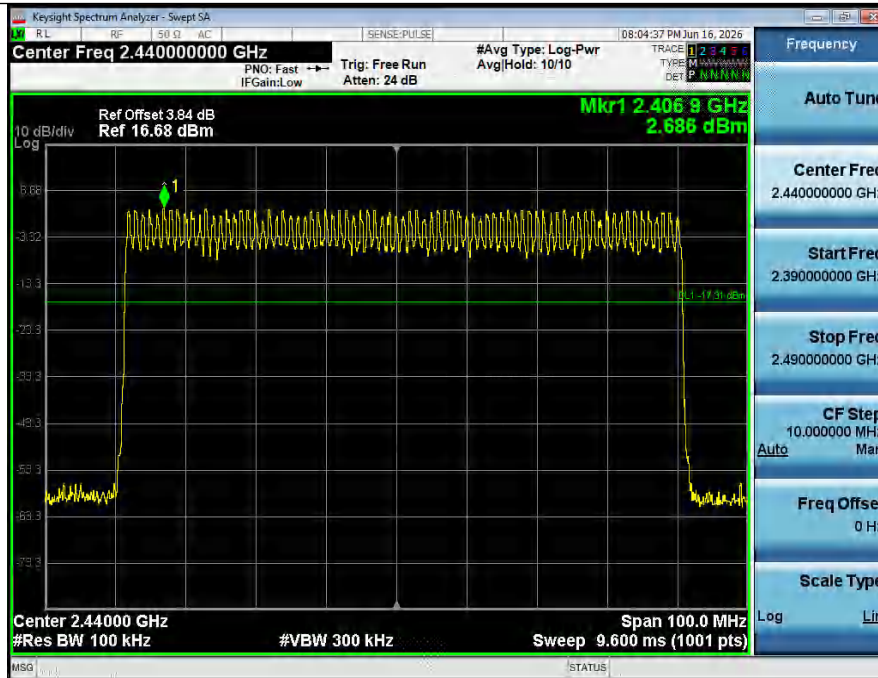
1_Reference_Level_NVNT_ANT1_2-DH1_2402_00



2_Bandedge_NVNT_ANT1_2-DH1_2402_00



1_Reference_Level_Hopping_NVNT_ANT1_2-DH1_Hopping



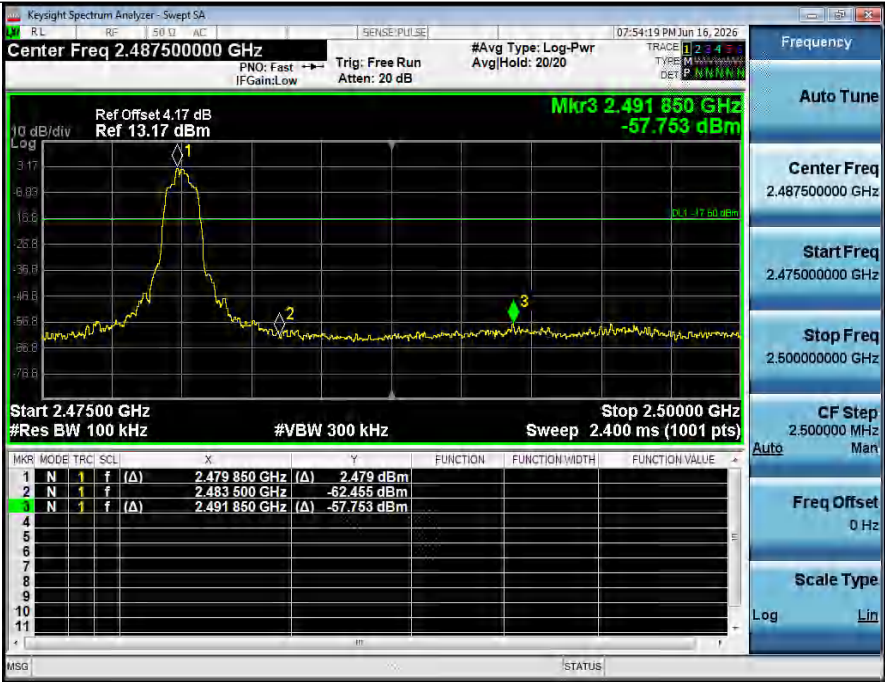
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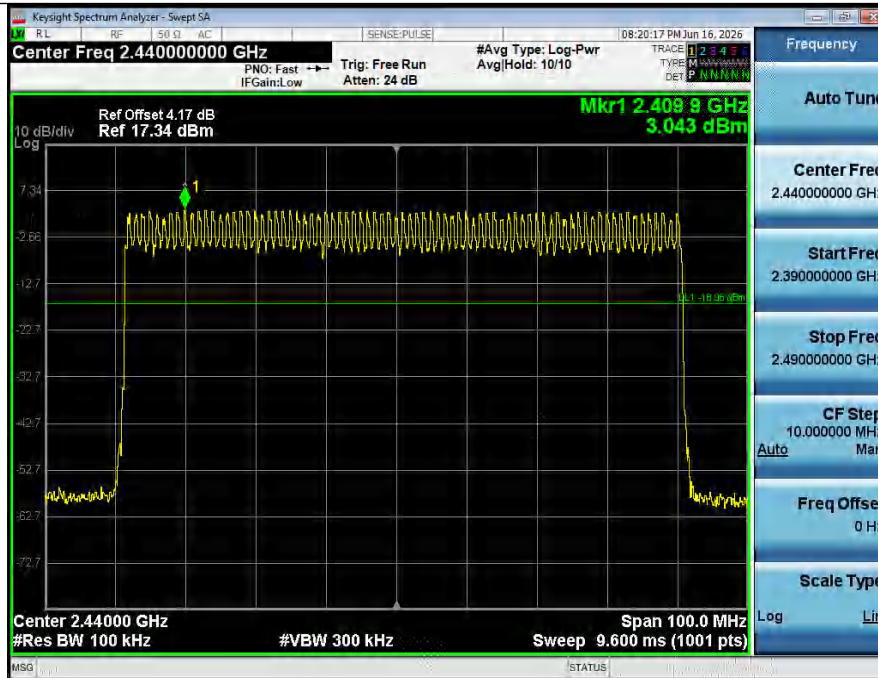
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2_Bandedge_NVNT_ANT1_2-DH1_2480_00



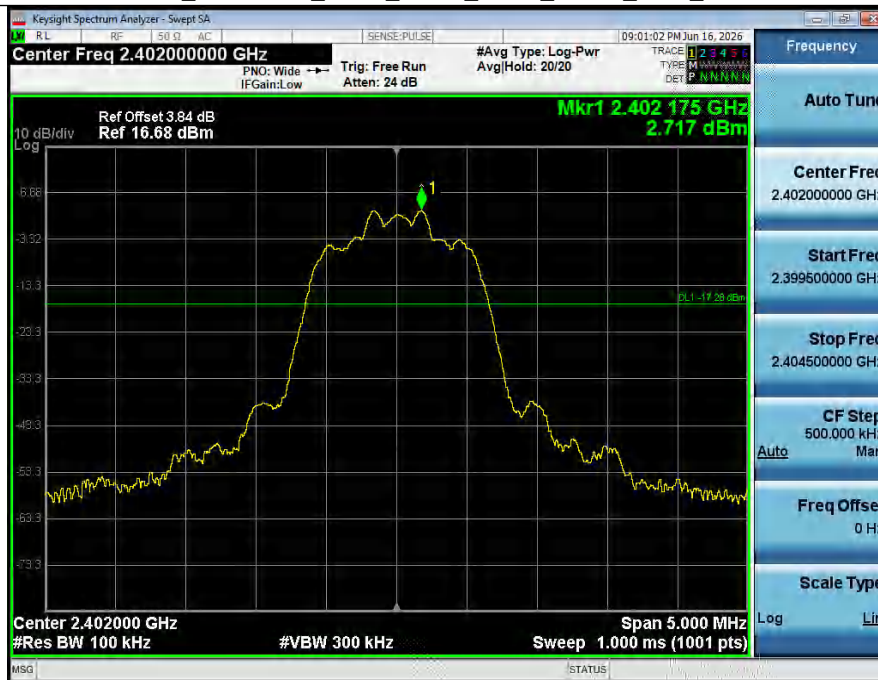
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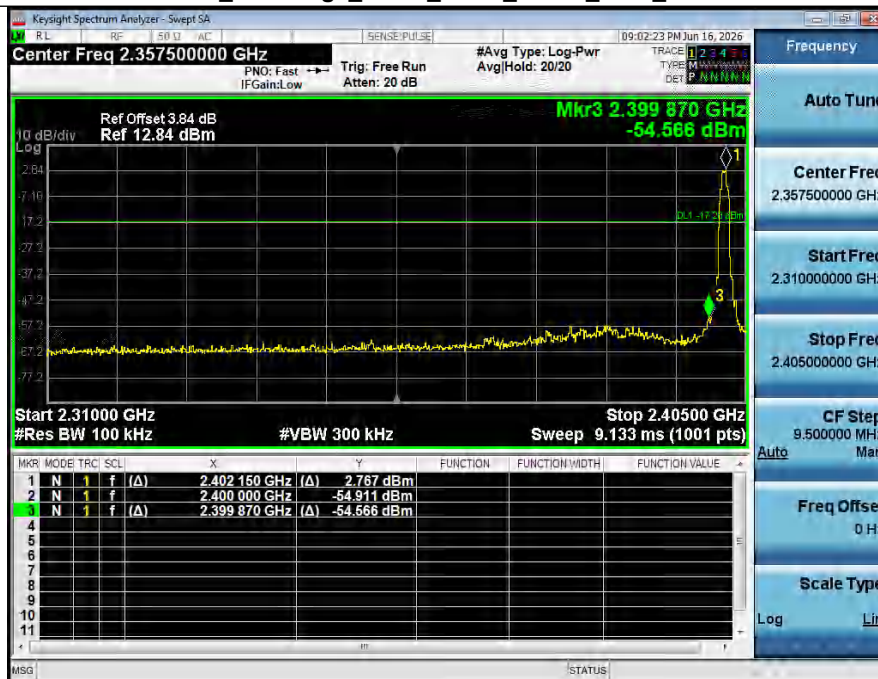
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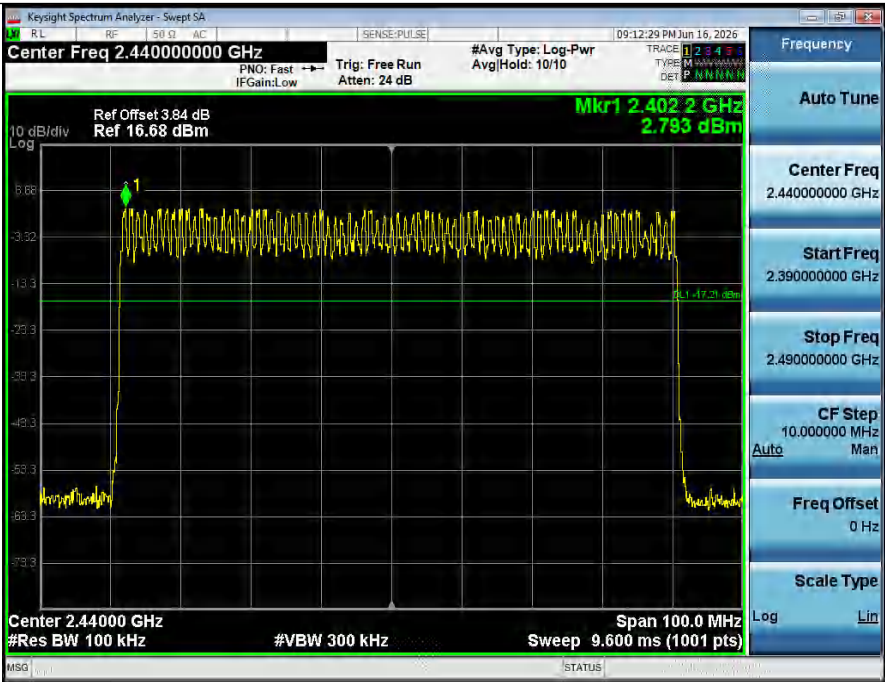
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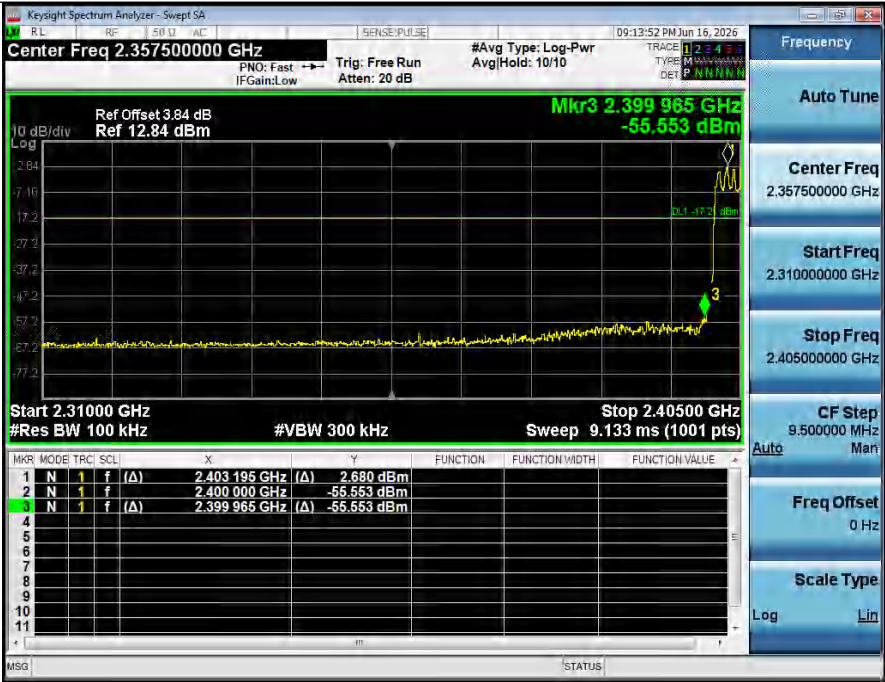
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1_Reference_Level_Hopping_NVNT_ANT1_3-DH1_Hopping



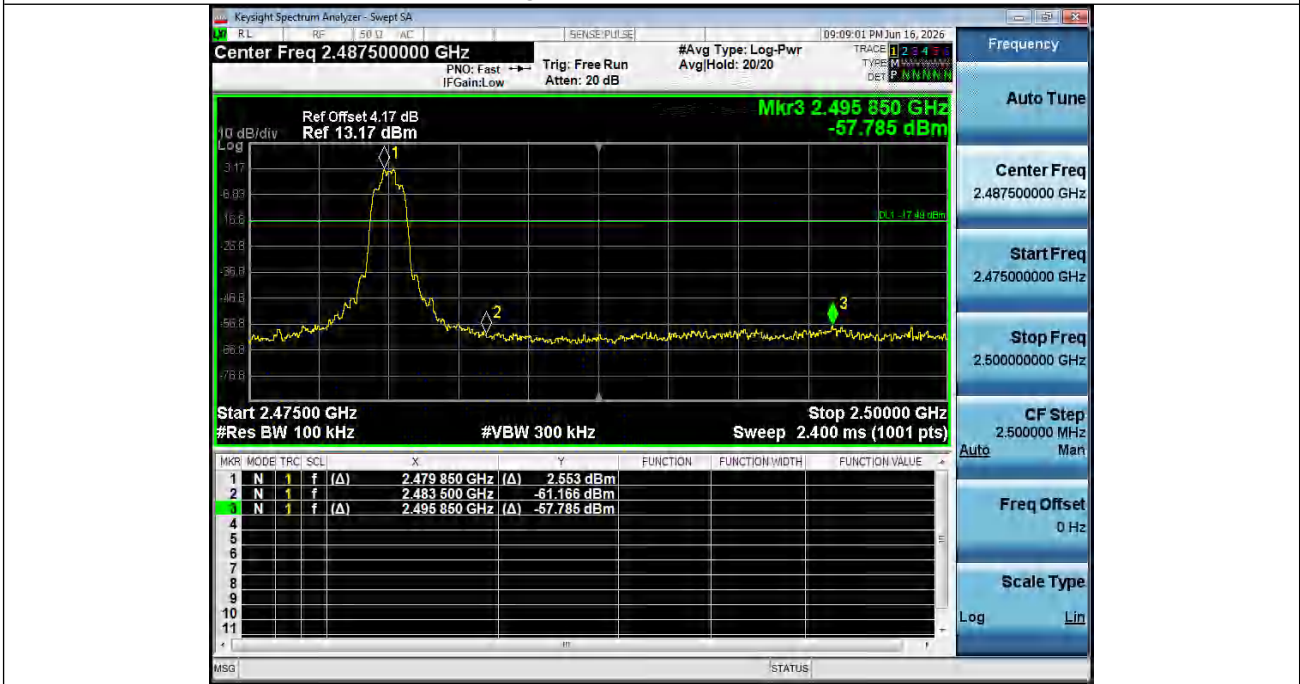
2_Band_Edge_(Hopping)_NVNT_ANT1_3-DH1_Hopping



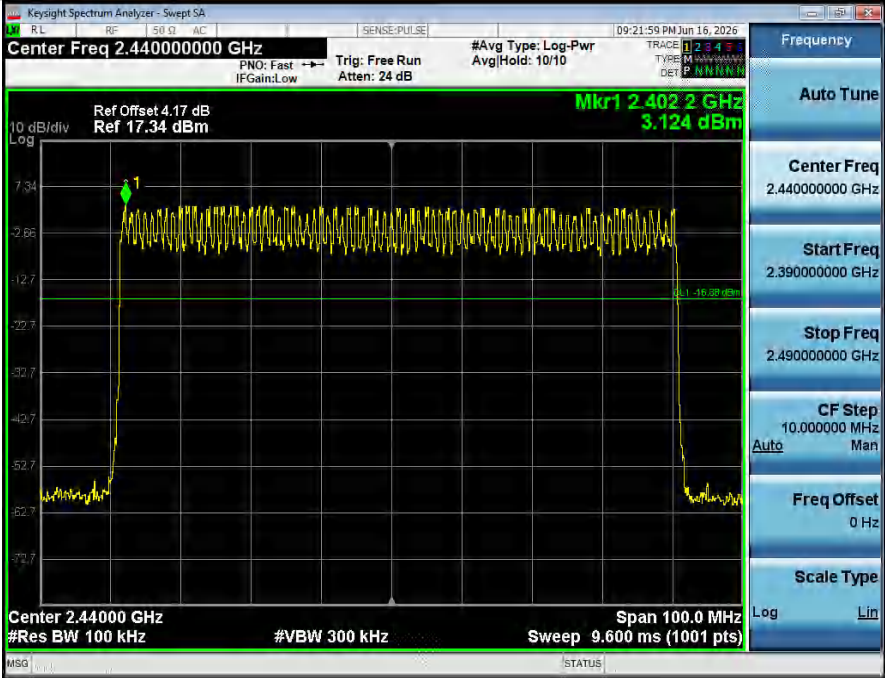
1_Reference_Level_NVNT_ANT1_3-DH1_2480_00



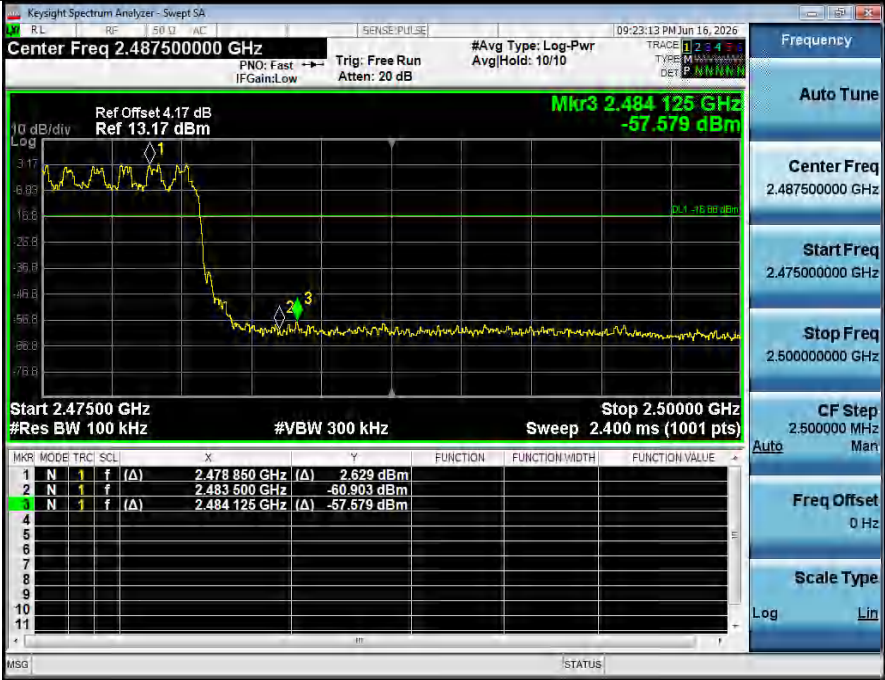
2_Bandedge_NVNT_ANT1_3-DH1_2480_00



1_Reference_Level_Hopping_NVNT_ANT1_3-DH1_Hopping



2_Band_Edge_(Hopping)_NVNT_ANT1_3-DH1_Hopping

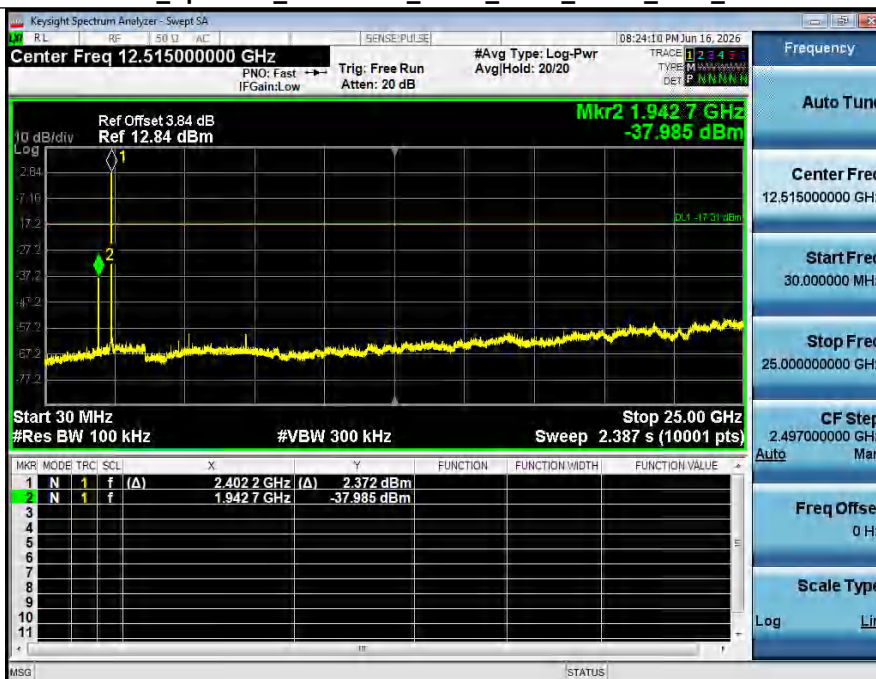


Appendix A.7: Test Results of Conducted Spurious Emission

Test Result

Condition	Antenna	Modulation	TX Mode	Ref_level (dBm)	Spurious MAX.Value (dBm)	Limit	Result
NVNT	ANT1	1-DH1	2402.00	2.686	-37.985	-17.314	Pass
NVNT	ANT1	1-DH1	2441.00	2.539	-39.545	-17.461	Pass
NVNT	ANT1	1-DH1	2480.00	2.408	-53.389	-17.592	Pass
NVNT	ANT1	2-DH1	2402.00	2.648	-53.159	-17.352	Pass
NVNT	ANT1	2-DH1	2441.00	2.459	-52.770	-17.541	Pass
NVNT	ANT1	2-DH1	2480.00	2.397	-52.717	-17.603	Pass
NVNT	ANT1	3-DH1	2402.00	2.717	-53.545	-17.283	Pass
NVNT	ANT1	3-DH1	2441.00	2.566	-53.287	-17.434	Pass
NVNT	ANT1	3-DH1	2480.00	2.510	-53.317	-17.490	Pass

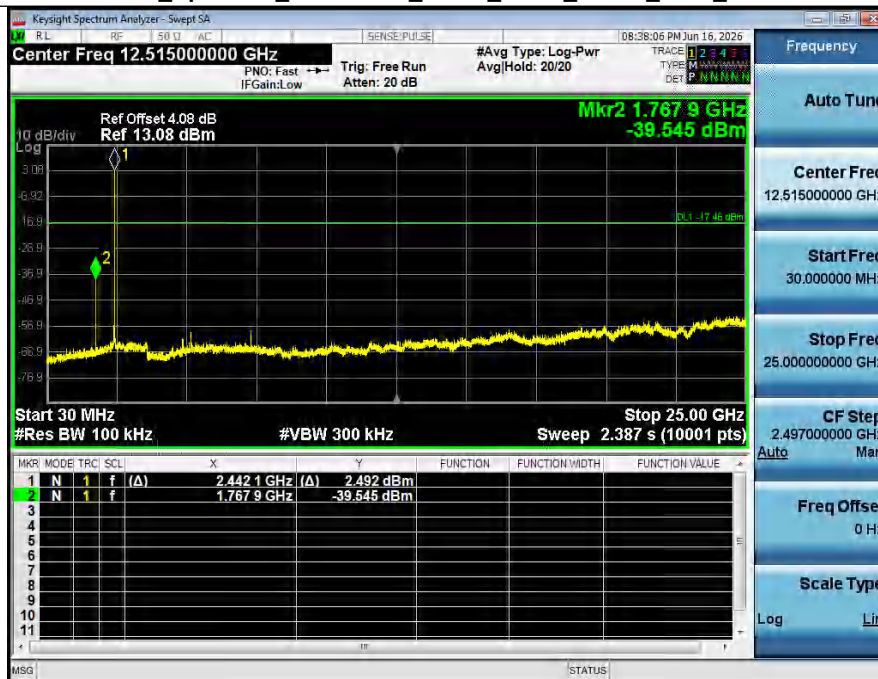
2_Spurious_Emissions_NVNT_ANT1_1-DH1_2402_00



1_Reference_Level_NVNT_ANT1_1-DH1_2441_00



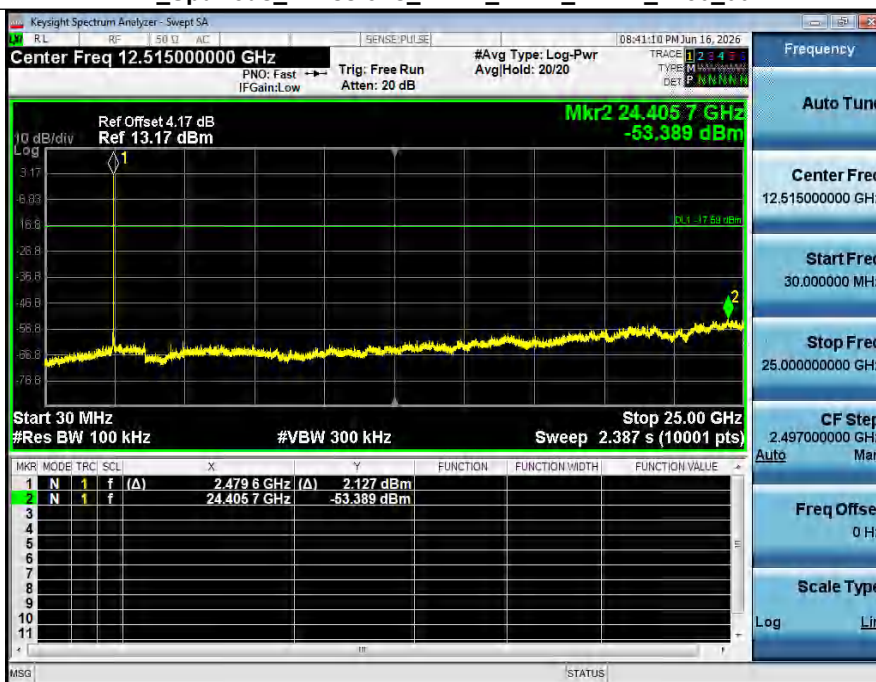
2_Spurious_Emissions_NVNT_ANT1_1-DH1_2441_00



1	Reference	Level	NVNT	ANT1	1-DH1	2480	00
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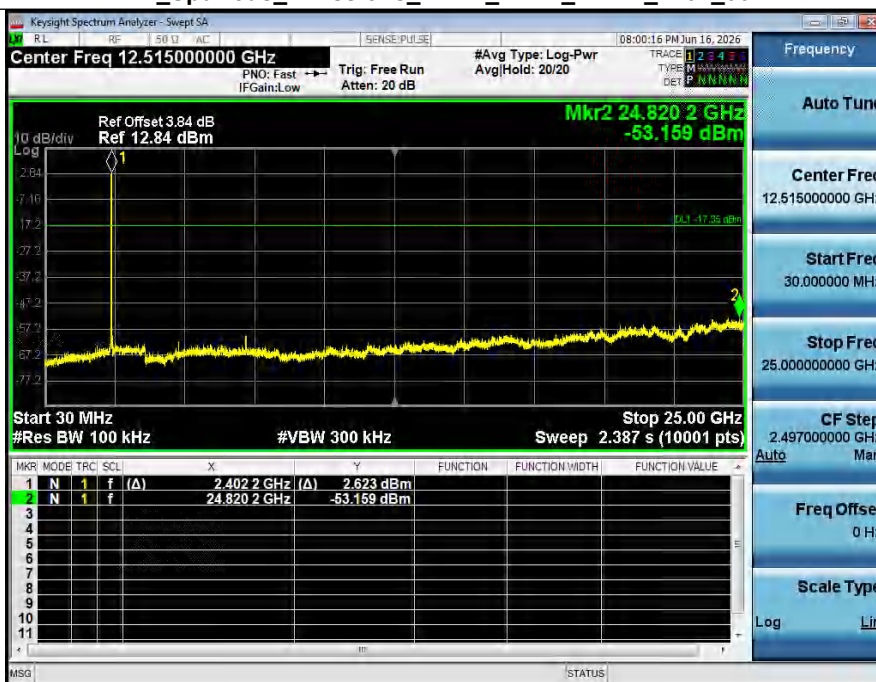
2_Spurious_Emissions_NVNT_ANT1_1-DH1_2480_00



1	Reference	Level	NVNT	ANT1	2-DH1	2402	00
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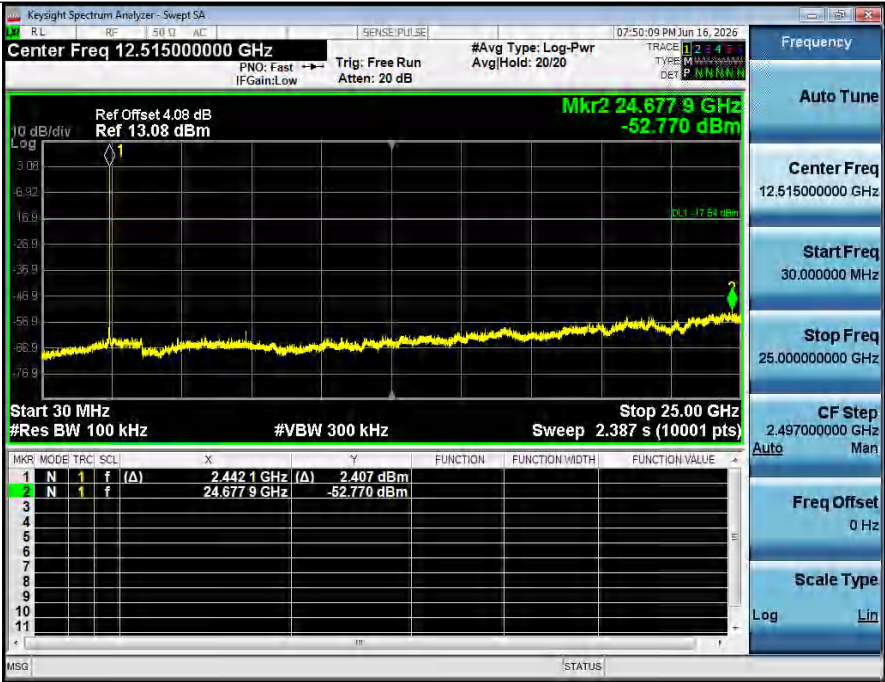
2_Spurious_Emissions_NVNT_ANT1_2-DH1_2402_00



1_Reference_Level_NVNT_ANT1_2-DH1_2441_00



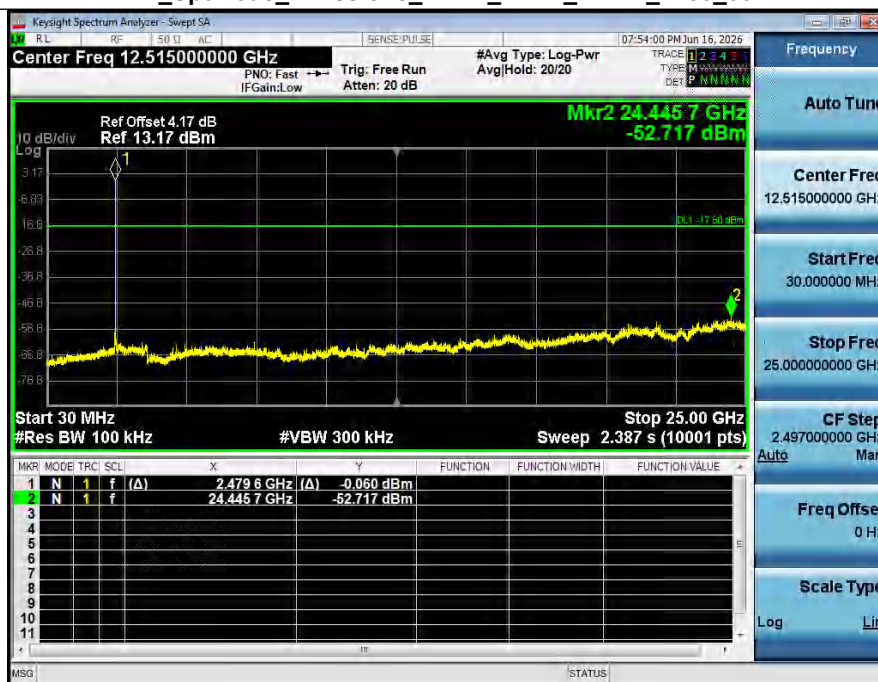
2_Spurious_Emissions_NVNT_ANT1_2-DH1_2441_00



1	Reference	Level	NVNT	ANT1	2-DH1	2480	00
---	-----------	-------	------	------	-------	------	----



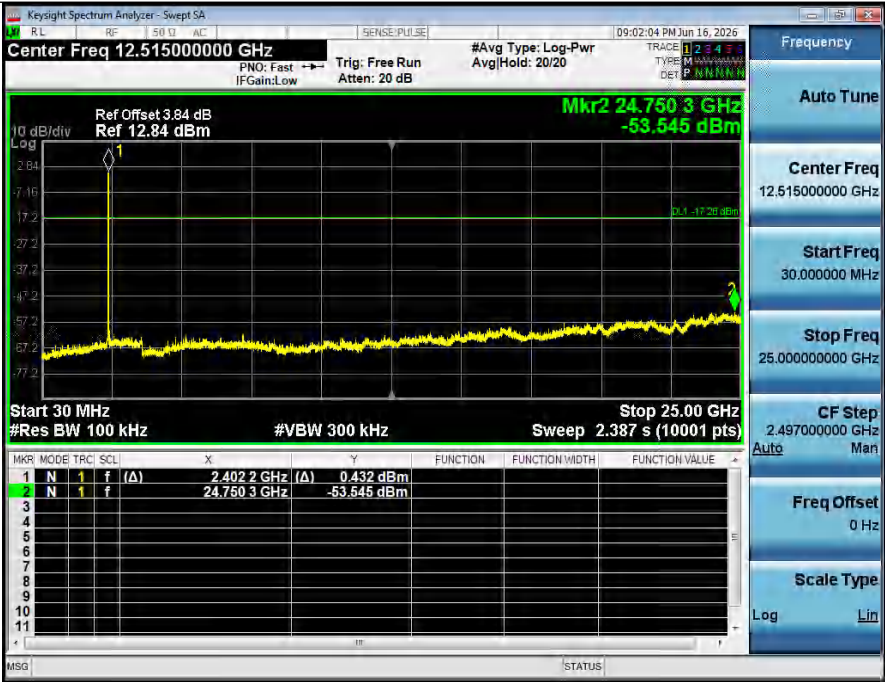
2_Spurious_Emissions_NVNT_ANT1_2-DH1_2480_00



1_Reference_Level_NVNT_ANT1_3-DH1_2402_00



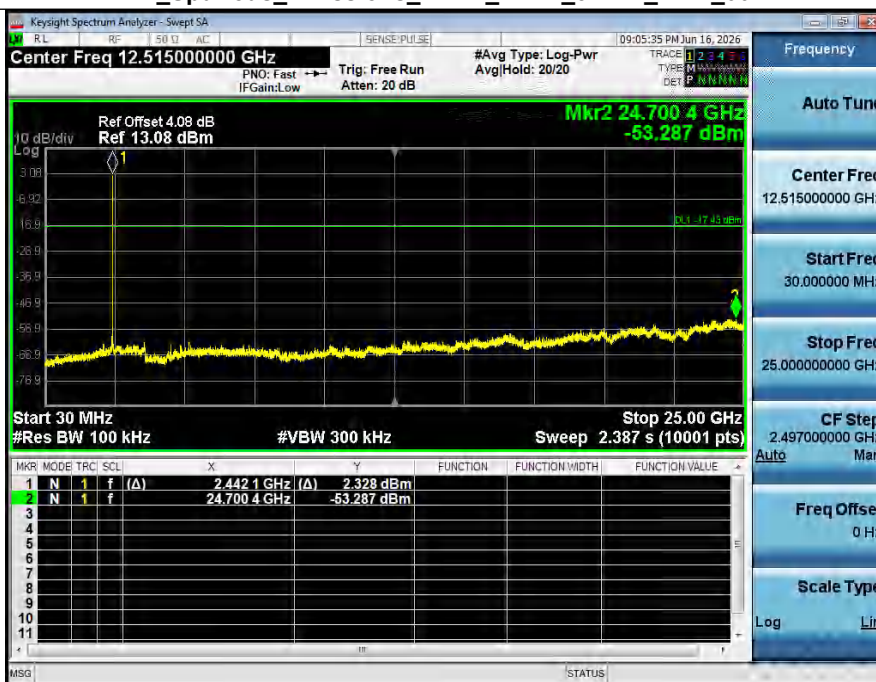
2_Spurious_Emissions_NVNT_ANT1_3-DH1_2402_00



1	Reference	Level	NVNT	ANT1	3-DH1	2441	00
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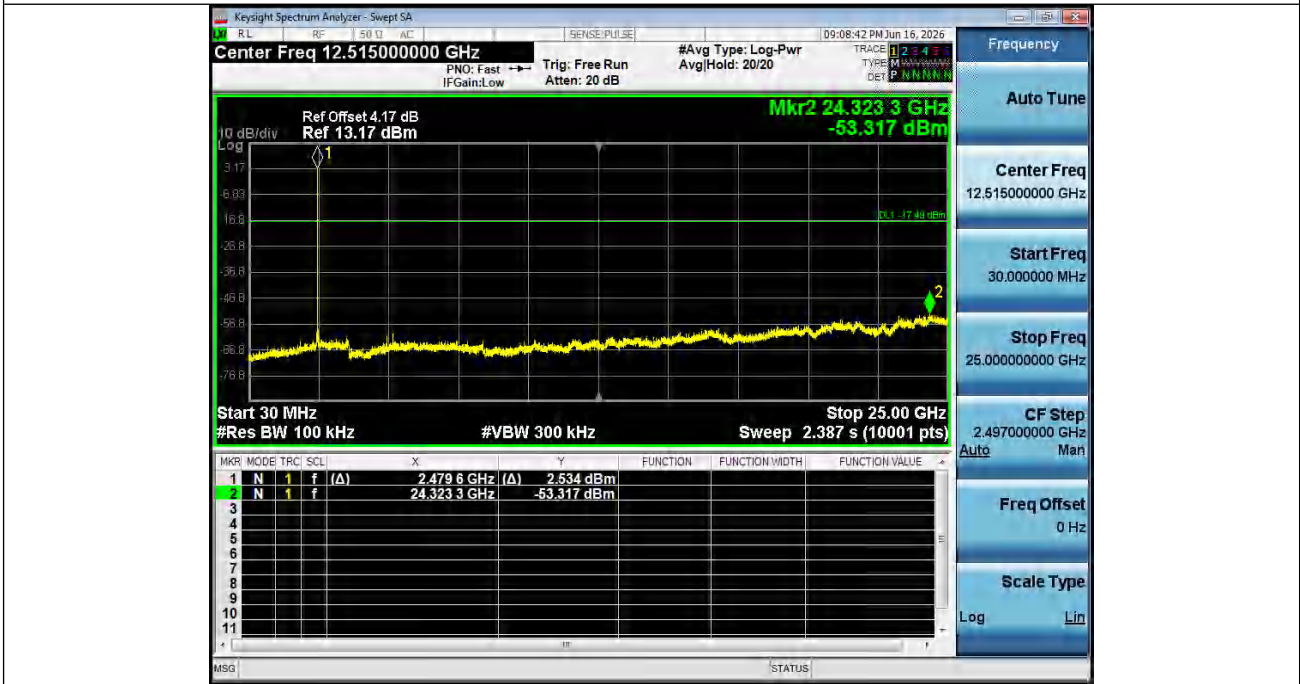
2_Spurious_Emissions_NVNT_ANT1_3-DH1_2441_00



1_Reference_Level_NVNT_ANT1_3-DH1_2480_00



2_Spurious_Emissions_NVNT_ANT1_3-DH1_2480_00



Appendix A.8: Test Results of Radiated Spurious Emissions

Note:

- 1) Testing was carried out within frequency range 9kHz to the tenth harmonics. The measurement results below 30MHz and 18GHz - 26.5GHz were greater than 20dB below the limit, so only the radiated spurious emissions from 30MHz to 18GHz were reported.

30MHz - 1GHz



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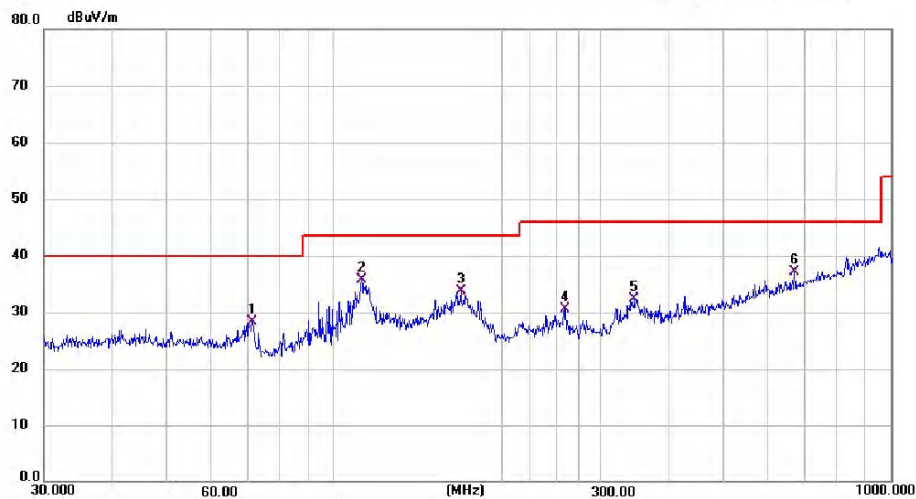
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: GFSK 2402
Test Voltage: Battery
Note:

Polarization: **Vertical**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 26 °C
Humidity: 54 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 11:22:36



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	71.1735	17.04	11.20	28.24	40.00	-11.76	QP	100	132	P	
2 *	111.7870	23.55	12.22	35.77	43.50	-7.73	QP	100	213	P	
3	169.0053	19.34	14.41	33.75	43.50	-9.75	QP	100	89	P	
4	260.0303	16.75	13.74	30.49	46.00	-15.51	QP	100	174	P	
5	345.8982	15.85	16.46	32.31	46.00	-13.69	QP	100	315	P	
6	672.5496	13.77	23.36	37.13	46.00	-8.87	QP	100	190	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#1

Page: 1

Engineer Signature:



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Shajing Street, Bao'an District, Shenzhen, Guangdong, China 518104

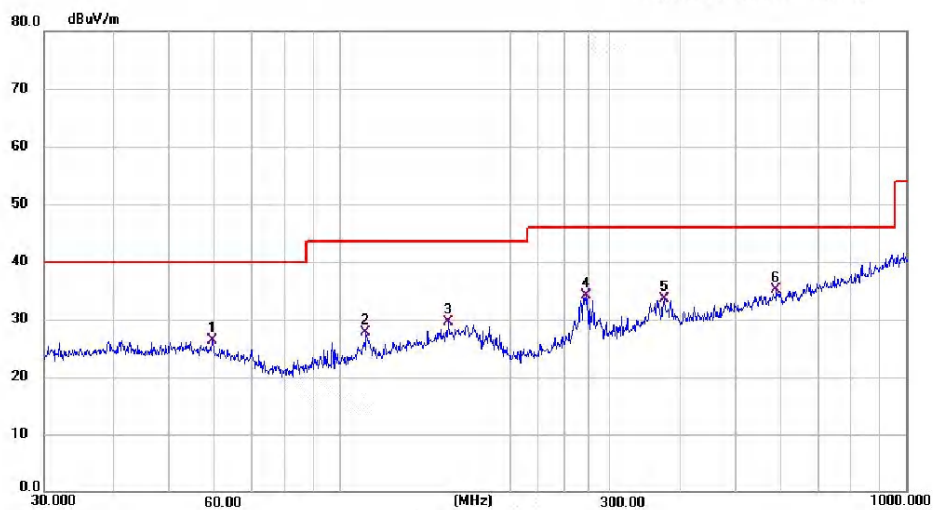
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: GFSK 2402
Test Voltage: Battery
Note:

Polarization: **Horizontal**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 26 °C
Humidity: 54 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 11:24:30



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	59.4926	13.04	13.28	26.32	40.00	-13.68	QP	200	311	P	
2	111.1517	15.48	12.15	27.63	43.50	-15.87	QP	200	109	P	
3	155.2960	14.39	15.20	29.59	43.50	-13.91	QP	200	262	P	
4	272.7553	19.79	14.23	34.02	46.00	-11.98	QP	200	182	P	
5	374.4583	16.38	17.05	33.43	46.00	-12.57	QP	200	43	P	
6 *	588.9050	13.29	21.84	35.13	46.00	-10.87	QP	200	177	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#2

Page: 1

Engineer Signature:



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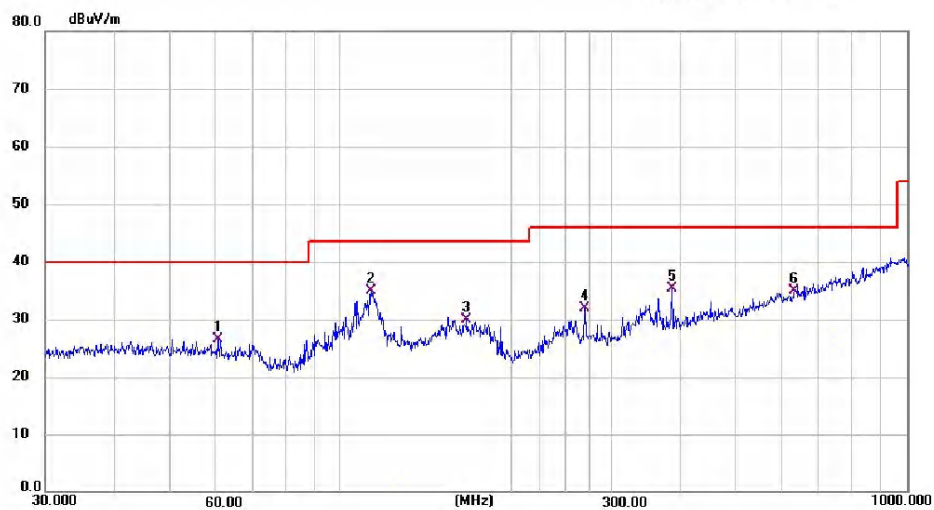
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: GFSK 2480
Test Voltage: Battery
Note:

Polarization: **Vertical**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 26 °C
Humidity: 54 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 10:37:42



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	60.6510	13.40	13.13	26.53	40.00	-13.47	QP	100	154	P	
2 *	113.0682	22.47	12.37	34.84	43.50	-8.66	QP	100	278	P	
3	166.7975	15.26	14.60	29.86	43.50	-13.64	QP	100	105	P	
4	269.6646	17.70	14.11	31.81	46.00	-14.19	QP	100	96	P	
5	384.1000	18.12	17.25	35.37	46.00	-10.63	QP	100	158	P	
6	634.1851	12.17	22.70	34.87	46.00	-11.13	QP	100	317	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#3

Page: 1

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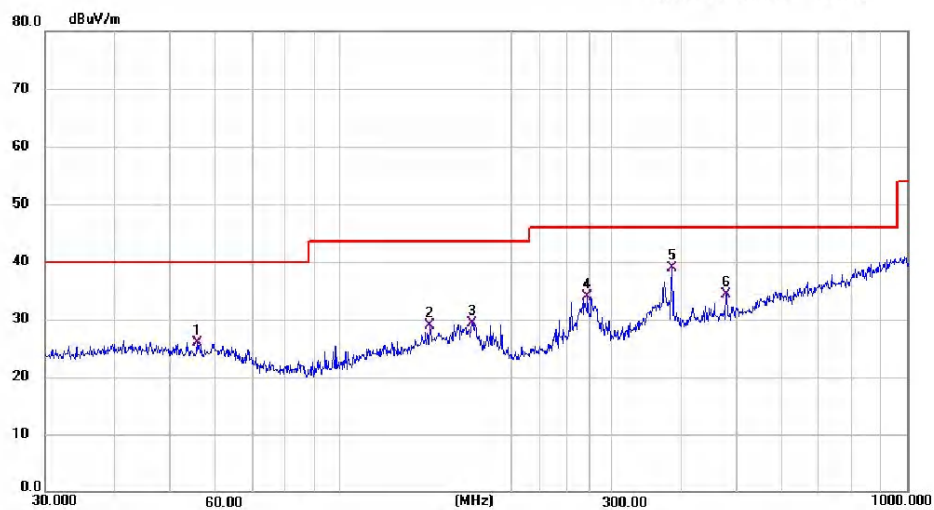
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: GFSK 2480
Test Voltage: Battery
Note:

Polarization: **Horizontal**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 26 °C
Humidity: 54 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 10:45:30



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	55.7312	12.48	13.47	25.95	40.00	-14.05	QP	200	184	P	
2	143.5774	14.13	14.74	28.87	43.50	-14.63	QP	200	132	P	
3	170.7177	15.14	14.22	29.36	43.50	-14.14	QP	200	251	P	
4	272.2776	19.69	14.21	33.90	46.00	-12.10	QP	200	174	P	
5 *	384.1000	21.67	17.25	38.92	46.00	-7.08	QP	200	153	P	
6	480.1064	14.84	19.51	34.35	46.00	-11.65	QP	200	109	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#4

Page: 1

Engineer Signature:



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Shajing Street, Bao'an District, Shenzhen, Guangdong, China 518104

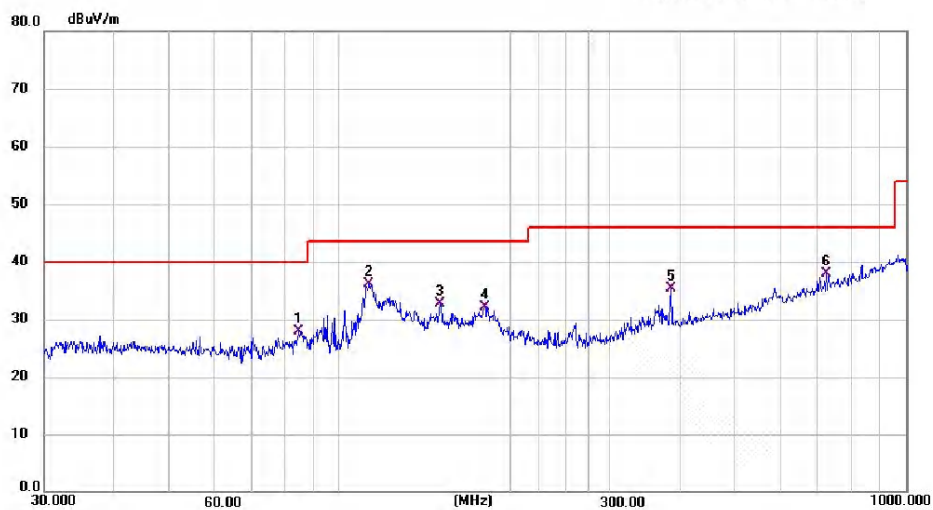
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: $\Pi/4$ DQPSK 2402
Test Voltage: Battery
Note:

Polarization: **Vertical**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 24 °C
Humidity: 56 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 11:09:53



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	84.6277	17.82	10.10	27.92	40.00	-12.08	QP	100	177	P	
2 *	112.8700	23.68	12.35	36.03	43.50	-7.47	QP	100	210	P	
3	150.3400	17.57	15.22	32.79	43.50	-10.71	QP	100	89	P	
4	180.0164	19.20	12.88	32.08	43.50	-11.42	QP	100	40	P	
5	384.1000	17.97	17.25	35.22	46.00	-10.78	QP	100	163	P	
6	722.6755	13.74	24.13	37.87	46.00	-8.13	QP	100	125	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#5

Page: 1

Engineer Signature:



Shenzhen PSI Testing Co., Ltd.
1-2F, Building 5, Yudafu Industrial Park, No. 10, Xingye West Road,
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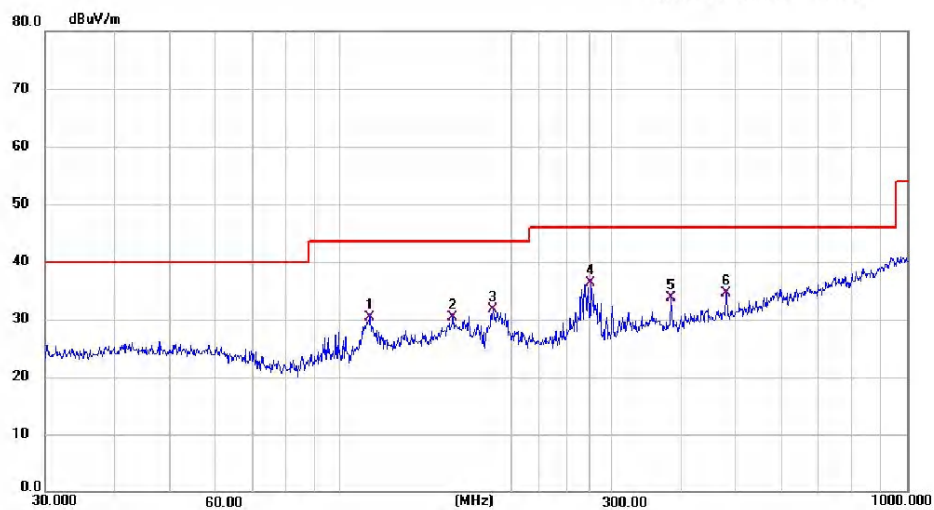
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: $\Pi/4$ DQPSK 2402
Test Voltage: Battery
Note:

Polarization: **Horizontal**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 24 °C
Humidity: 56 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 11:17:57



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	112.4750	18.06	12.29	30.35	43.50	-13.15	QP	200	199	P	
2	158.1123	15.07	15.18	30.25	43.50	-13.25	QP	200	321	P	
3	185.2190	19.37	12.33	31.70	43.50	-11.80	QP	200	18	P	
4 *	276.4869	21.93	14.38	36.31	46.00	-9.69	QP	200	109	P	
5	383.9318	16.44	17.24	33.68	46.00	-12.32	QP	200	72	P	
6	480.1064	14.95	19.51	34.46	46.00	-11.54	QP	200	178	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#6

Page: 1

Engineer Signature:



Shenzhen PSI Testing Co., Ltd.
1-2F, Building 5, Yudafu Industrial Park, No. 10, Xingye West Road,
Shajing Street, Bao'an District, Shenzhen, Guangdong, China 518104

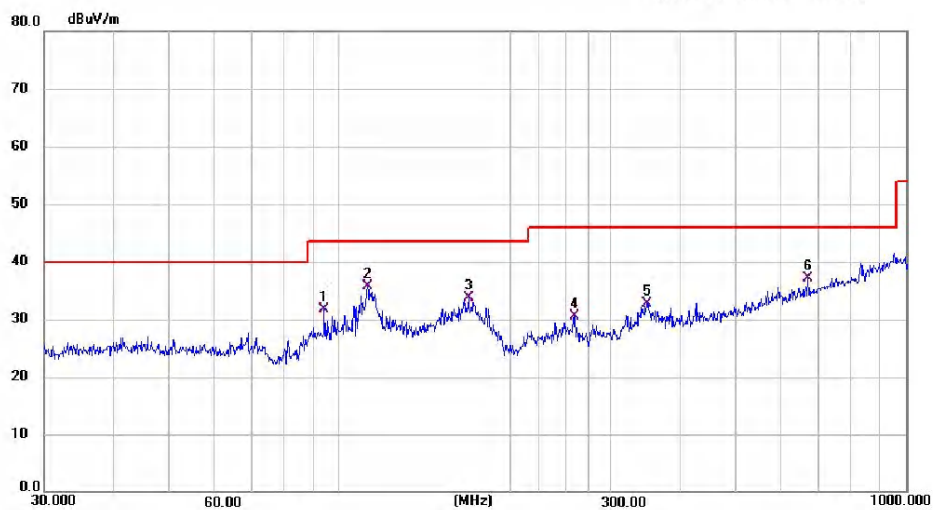
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: $\Pi/4$ DQPSK 2480
Test Voltage: Battery
Note:

Polarization: **Vertical**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 26 °C
Humidity: 54 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 17:02:36



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	94.0151	21.23	10.54	31.77	43.50	-11.73	QP	100	215	P	
2 *	111.7870	23.55	12.22	35.77	43.50	-7.73	QP	100	188	P	
3	169.0053	19.34	14.41	33.75	43.50	-9.75	QP	100	162	P	
4	260.0303	16.75	13.74	30.49	46.00	-15.51	QP	100	299	P	
5	348.4852	16.24	16.53	32.77	46.00	-13.23	QP	100	67	P	
6	672.5496	13.77	23.36	37.13	46.00	-8.87	QP	100	150	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#7

Page: 1

Engineer Signature:



Shenzhen PSI Testing Co., Ltd.
1-2F, Building 5, Yudafu Industrial Park, No. 10, Xingye West Road,
Shajing Street, Bao'an District, Shenzhen, Guangdong, China 518104

Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: $\Pi/4$ DQPSK 2402
Test Voltage: Battery
Note:

Polarization: **Horizontal**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 26 °C
Humidity: 54 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 17:09:30



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	111.1517	14.83	12.15	26.98	43.50	-16.52	QP	200	185	P	
2	143.5774	14.63	14.74	29.37	43.50	-14.13	QP	200	289	P	
3	184.3281	17.56	12.42	29.98	43.50	-13.52	QP	200	105	P	
4	272.2776	19.19	14.21	33.40	46.00	-12.60	QP	200	27	P	
5 *	384.1000	19.17	17.25	36.42	46.00	-9.58	QP	200	136	P	
6	480.1064	14.84	19.51	34.35	46.00	-11.65	QP	200	188	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#8

Page: 1

Engineer Signature:



Shenzhen PSI Testing Co., Ltd.
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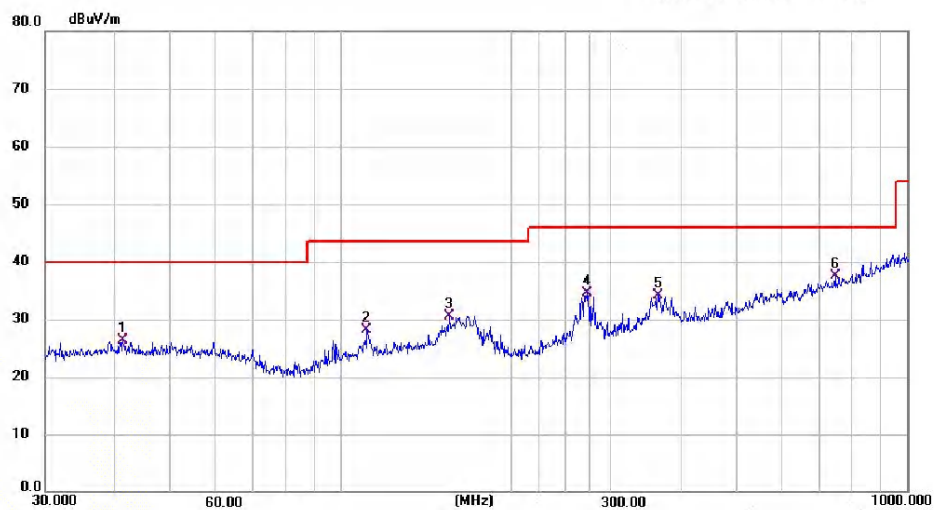
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: 8DPSK 2402
Test Voltage: Battery
Note:

Polarization: **Horizontal**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 26 °C
Humidity: 54 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 17:16:30



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	41.1681	12.02	14.20	26.22	40.00	-13.78	QP	200	89	P	
2	111.1517	15.98	12.15	28.13	43.50	-15.37	QP	200	174	P	
3	155.2960	15.39	15.20	30.59	43.50	-12.91	QP	200	215	P	
4	272.7553	20.29	14.23	34.52	46.00	-11.48	QP	200	56	P	
5	364.1000	17.35	16.85	34.20	46.00	-11.80	QP	200	150	P	
6 *	746.5000	12.93	24.48	37.41	46.00	-8.59	QP	200	211	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#9

Page: 1

Engineer Signature:



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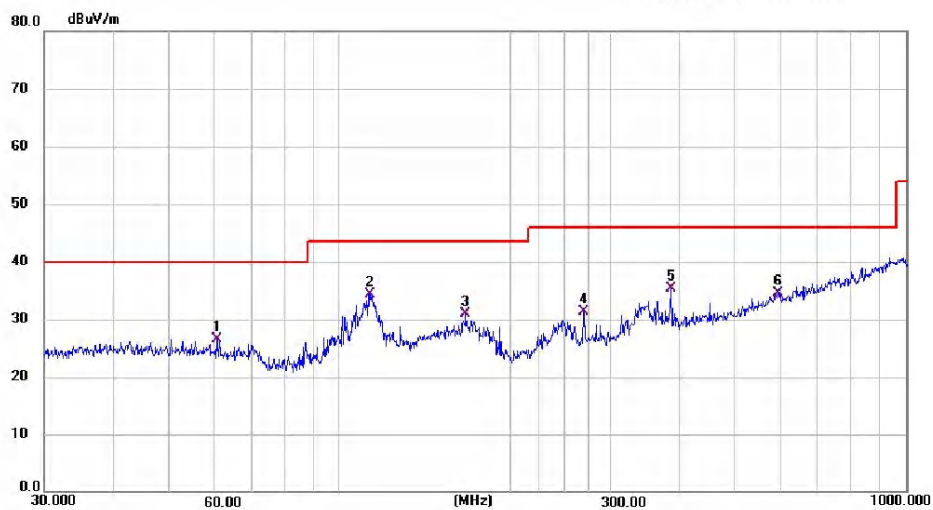
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: 8DPSK 2402
Test Voltage: Battery
Note:

Polarization: **Vertical**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 26 °C
Humidity: 54 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 17:22:42



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	60.6510	13.40	13.13	26.53	40.00	-13.47	QP	100	103	P	
2 *	113.0682	21.97	12.37	34.34	43.50	-9.16	QP	100	131	P	
3	166.7975	16.26	14.60	30.86	43.50	-12.64	QP	100	75	P	
4	269.6646	17.20	14.11	31.31	46.00	-14.69	QP	100	285	P	
5	384.1000	18.12	17.25	35.37	46.00	-10.63	QP	100	16	P	
6	595.1326	12.60	21.96	34.56	46.00	-11.44	QP	100	180	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#10

Page: 1

Engineer Signature:



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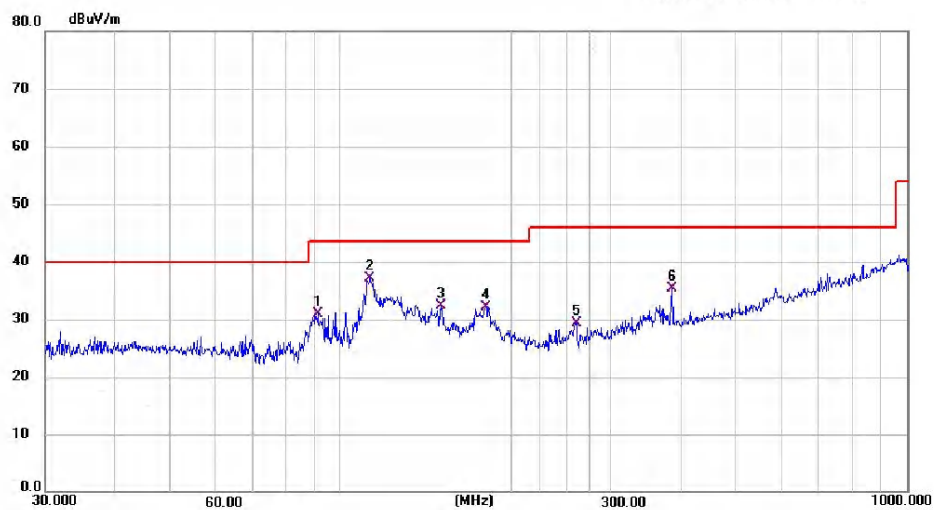
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: 8DPSK 2480
Test Voltage: Battery
Note:

Polarization: **Vertical**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 24 °C
Humidity: 56 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 17:29:53



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	91.0147	20.54	10.33	30.87	43.50	-12.63	QP	100	178	P	
2 *	112.8700	24.68	12.35	37.03	43.50	-6.47	QP	100	215	P	
3	150.3400	17.07	15.22	32.29	43.50	-11.21	QP	100	164	P	
4	180.0164	19.20	12.88	32.08	43.50	-11.42	QP	100	130	P	
5	260.7151	15.48	13.77	29.25	46.00	-16.75	QP	100	329	P	
6	384.1000	17.97	17.25	35.22	46.00	-10.78	QP	100	182	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#11

Page: 1

Engineer Signature:



Shenzhen PSI Testing Co., Ltd.
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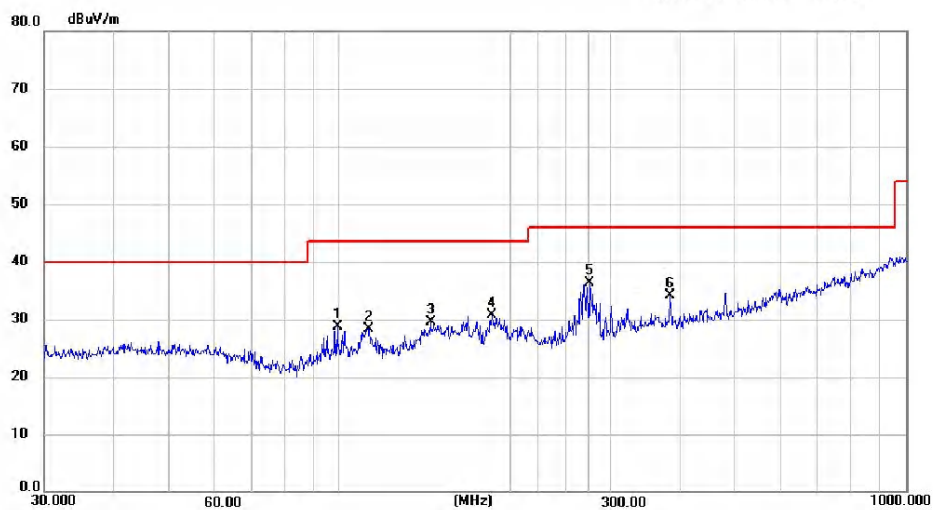
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: 8DPSK 2480
Test Voltage: Battery
Note:

Polarization: **Horizontal**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 24 °C
Humidity: 56 %RH

Radiated Emission Measurement

Test Date: 2026/6/17 17:35:57



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	99.0060	17.73	10.89	28.62	43.50	-14.88	peak			P	
2	112.4750	16.06	12.29	28.35	43.50	-15.15	peak			P	
3	144.3980	14.70	14.80	29.50	43.50	-14.00	peak			P	
4	185.2190	18.37	12.33	30.70	43.50	-12.80	peak			P	
5 *	276.4869	21.93	14.38	36.31	46.00	-9.69	peak			P	
6	383.9318	16.94	17.24	34.18	46.00	-11.82	peak			P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 30M-1G\Data :#12

Page: 1

Engineer Signature:

1GHz - 18GHz

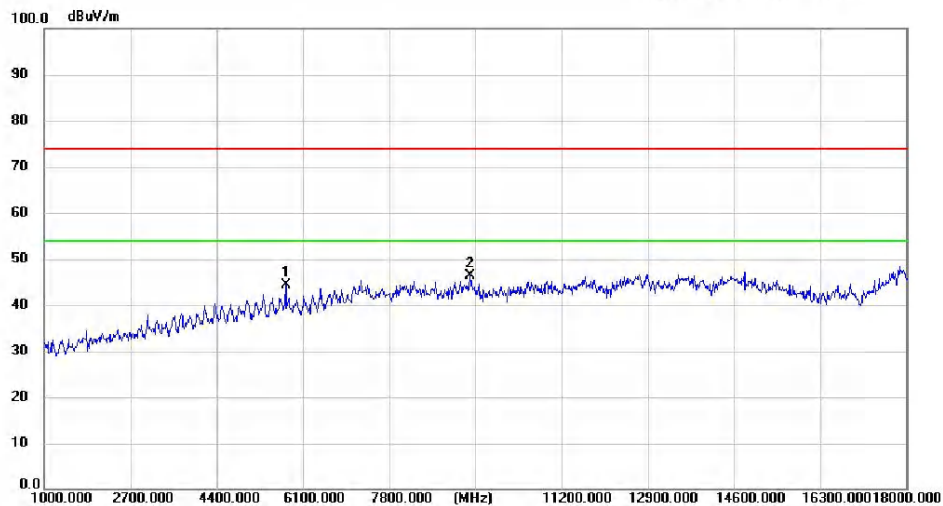


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Shajing Street, Bao'an District, Shenzhen, Guangdong, China 518104

Test Site: PSI EMC Lab-3m Chamber	Polarization: Vertical	Temperature: 26 °C
EUT: L320 Party Speaker	Distance: 3m	Humidity: 54 %RH
M/N: NS-PSL320	Test Engineer: Jeffrey	
Test Mode: GFSK 2402		
Test Voltage: Battery		
Note:		

Radiated Emission Measurement

Test Date: 2026/6/18 19:04:40



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	5768.500	64.60	-20.20	44.40	74.00	-29.60	peak	150	131	P	
2 *	9400.125	62.59	-16.32	46.27	74.00	-27.73	peak	150	278	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 1G-18G\Data :#1

Page: 1

Engineer Signature:

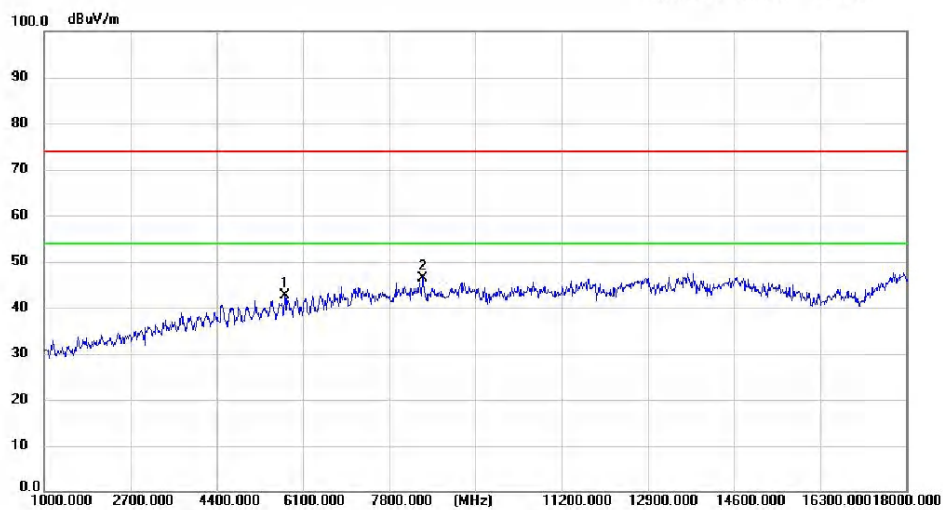


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Shajing Street, Bao'an District, Shenzhen, Guangdong, China 518104

Test Site: PSI EMC Lab-3m Chamber	Polarization: Horizontal	Temperature: 26 °C
EUT: L320 Party Speaker	Distance: 3m	Humidity: 54 %RH
M/N: NS-PSL320	Test Engineer: Jeffrey	
Test Mode: GFSK 2402		
Test Voltage: Battery		
Note:		

Radiated Emission Measurement

Test Date: 2026/6/18 19:10:25



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	5757.875	62.78	-20.23	42.55	74.00	-31.45	peak	150	215	P	
2 *	8465.125	62.95	-16.62	46.33	74.00	-27.67	peak	150	329	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 1G-18G\Data :#2

Page: 1

Engineer Signature:

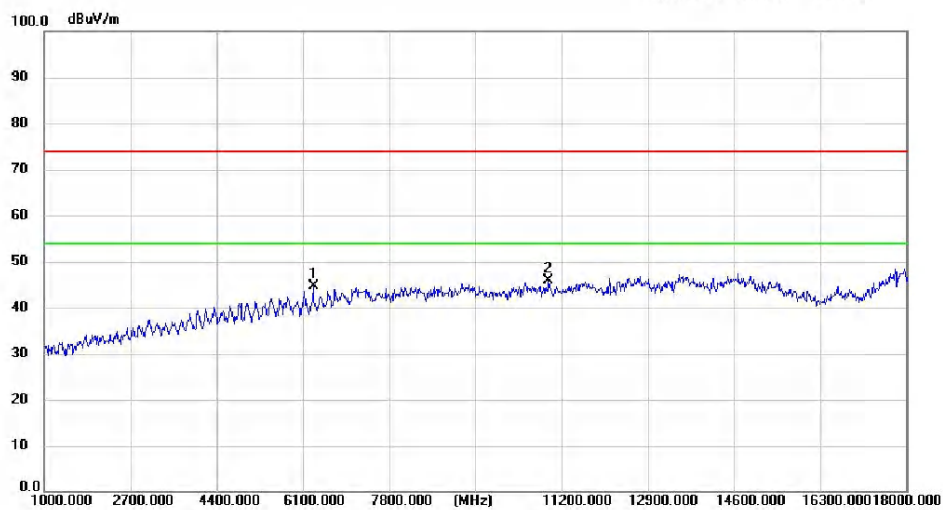


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Test Site: PSI EMC Lab-3m Chamber	Polarization: Vertical	Temperature: 26 °C
EUT: L320 Party Speaker	Distance: 3m	Humidity: 54 %RH
M/N: NS-PSL320	Test Engineer: Jeffrey	
Test Mode: GFSK 2480		
Test Voltage: Battery		
Note:		

Radiated Emission Measurement

Test Date: 2026/6/18 19:17:38



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	6304.000	63.54	-19.01	44.53	74.00	-29.47	peak	150	89	P	
2 *	10945.000	60.94	-15.15	45.79	74.00	-28.21	peak	150	225	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 1G-18G\Data :#3

Page: 1

Engineer Signature:

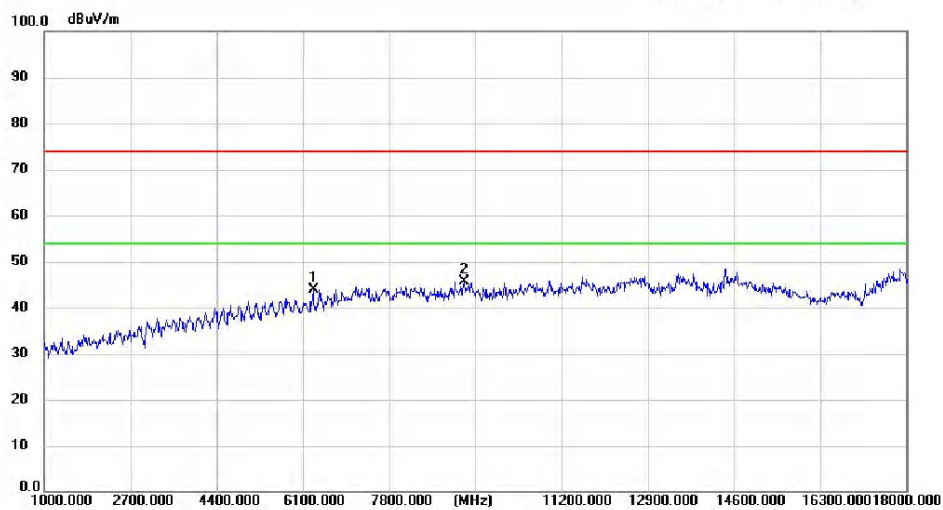


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Shajing Street, Bao'an District, Shenzhen, Guangdong, China 518104

Test Site: PSI EMC Lab-3m Chamber	Polarization: Horizontal	Temperature: 26 °C
EUT: L320 Party Speaker	Distance: 3m	Humidity: 54 %RH
M/N: NS-PSL320	Test Engineer: Jeffrey	
Test Mode: GFSK 2480		
Test Voltage: Battery		
Note:		

Radiated Emission Measurement

Test Date: 2026/6/18 19:23:51



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	6318.875	62.92	-18.97	43.95	74.00	-30.05	peak	150	271	P	
2 *	9285.375	62.05	-16.37	45.68	74.00	-28.32	peak	150	163	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 1G-18G\Data :#4

Page: 1

Engineer Signature:



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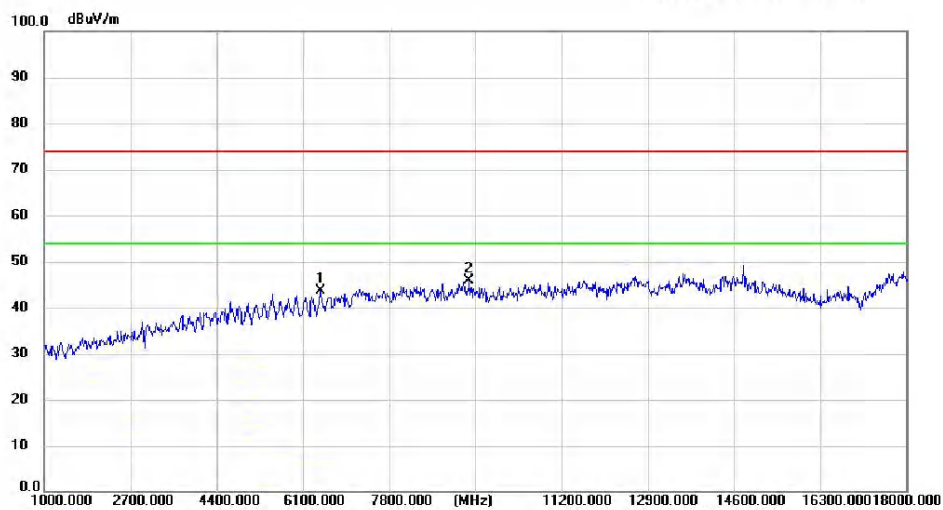
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: $\Pi/4$ DQPSK 2402
Test Voltage: Battery
Note:

Polarization: **Vertical**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 26 °C
Humidity: 54 %RH

Radiated Emission Measurement

Test Date: 2026/6/18 19:29:27



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	6444.250	62.34	-18.68	43.66	74.00	-30.34	peak	150	198	P	
2 *	9381.000	62.22	-16.32	45.90	74.00	-28.10	peak	150	106	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 1G-18G\Data :#5

Page: 1

Engineer Signature:

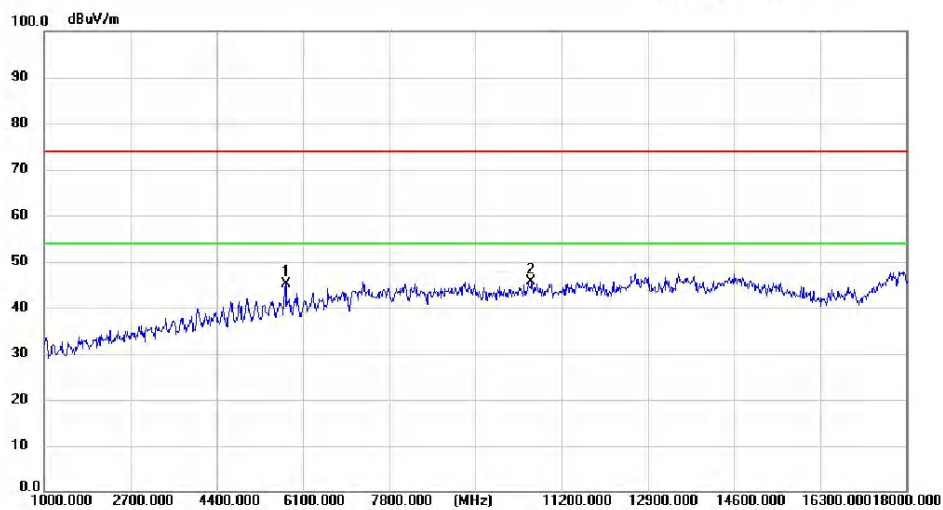


Shenzhen PSI Testing Co., Ltd.
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Shajing Street, Bao'an District, Shenzhen, Guangdong, China 518104

Test Site: PSI EMC Lab-3m Chamber	Polarization: Horizontal	Temperature: 26 °C
EUT: L320 Party Speaker	Distance: 3m	Humidity: 54 %RH
M/N: NS-PSL320	Test Engineer: Jeffrey	
Test Mode: $\Pi/4$ DQPSK 2402		
Test Voltage: Battery		
Note:		

Radiated Emission Measurement

Test Date: 2026/6/18 19:36:18



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	5766.375	65.39	-20.21	45.18	74.00	-28.82	peak	150	192	P	
2 *	10607.125	61.02	-15.48	45.54	74.00	-28.46	peak	150	251	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 1G-18G\Data :#6

Page: 1

Engineer Signature:

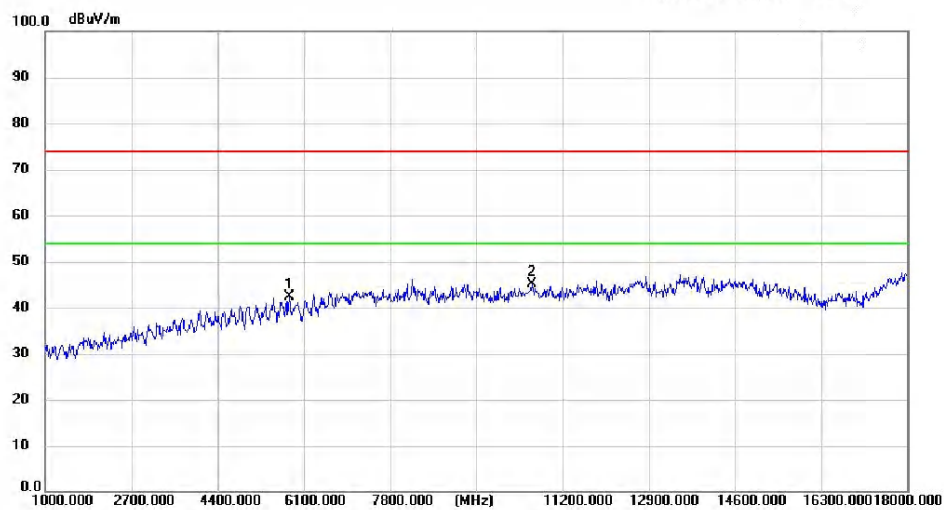


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Test Site: PSI EMC Lab-3m Chamber	Polarization: Vertical	Temperature: 26 °C
EUT: L320 Party Speaker	Distance: 3m	Humidity: 54 %RH
M/N: NS-PSL320	Test Engineer: Jeffrey	
Test Mode: $\Pi/4$ DQPSK 2480		
Test Voltage: Battery		
Note:		

Radiated Emission Measurement

Test Date: 2026/6/18 19:42:29



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	5821.625	62.36	-20.09	42.27	74.00	-31.73	peak	150	209	P	
2 *	10592.250	60.50	-15.49	45.01	74.00	-28.99	peak	150	175	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 1G-18G\Data :#7

Page: 1

Engineer Signature:

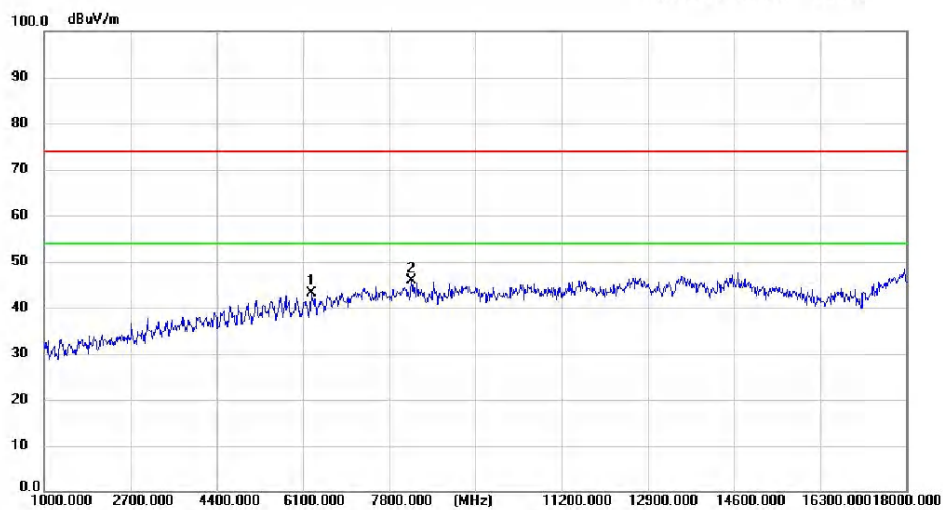


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Test Site: PSI EMC Lab-3m Chamber	Polarization: Horizontal	Temperature: 26 °C
EUT: L320 Party Speaker	Distance: 3m	Humidity: 54 %RH
M/N: NS-PSL320	Test Engineer: Jeffrey	
Test Mode: $\Pi/4$ DQPSK 2480		
Test Voltage: Battery		
Note:		

Radiated Emission Measurement

Test Date: 2026/6/18 19:48:50



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	6284.875	62.08	-19.05	43.03	74.00	-30.97	peak	150	118	P	
2 *	8248.375	62.61	-16.66	45.95	74.00	-28.05	peak	150	215	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 1G-18G\Data :#8

Page: 1

Engineer Signature:

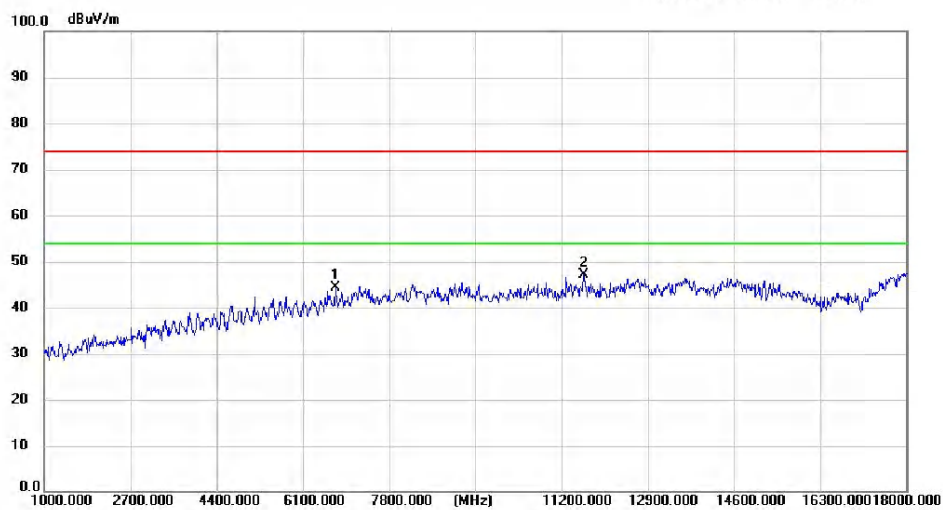


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Test Site: PSI EMC Lab-3m Chamber	Polarization: Vertical	Temperature: 26 °C
EUT: L320 Party Speaker	Distance: 3m	Humidity: 54 %RH
M/N: NS-PSL320	Test Engineer: Jeffrey	
Test Mode: 8DPSK 2402		
Test Voltage: Battery		
Note:		

Radiated Emission Measurement

Test Date: 2026/6/18 19:55:24



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	6750.250	62.24	-17.98	44.26	74.00	-29.74	peak	150	157	P	
2 *	11656.875	61.96	-14.89	47.07	74.00	-26.93	peak	150	249	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 1G-18G\Data :#9

Page: 1

Engineer Signature:

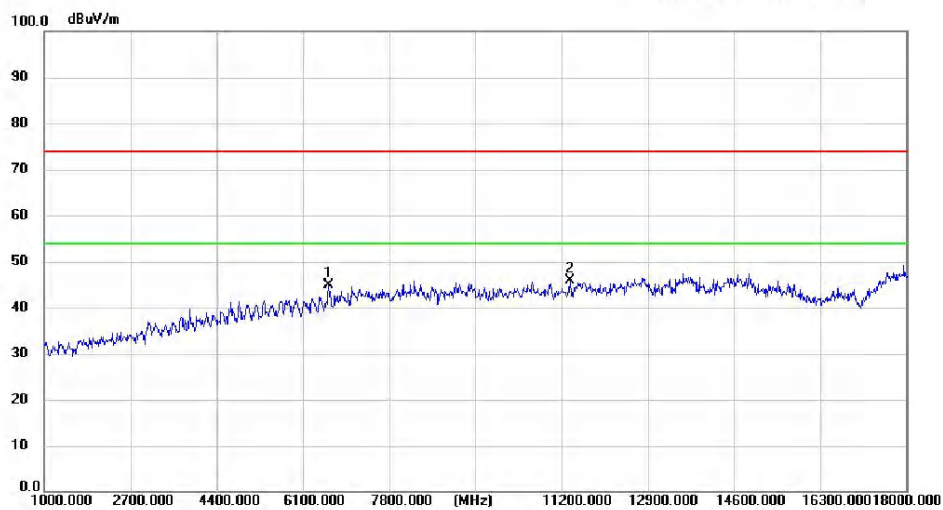


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Test Site: PSI EMC Lab-3m Chamber	Polarization: Horizontal	Temperature: 26 °C
EUT: L320 Party Speaker	Distance: 3m	Humidity: 54 %RH
M/N: NS-PSL320	Test Engineer: Jeffrey	
Test Mode: 8DPSK 2402		
Test Voltage: Battery		
Note:		

Radiated Emission Measurement

Test Date: 2026/6/18 20:02:38



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	6620.625	63.14	-18.28	44.86	74.00	-29.14	peak	150	192	P	
2 *	11374.250	60.76	-14.98	45.78	74.00	-28.22	peak	150	316	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 1G-18G\Data :#10

Page: 1

Engineer Signature:



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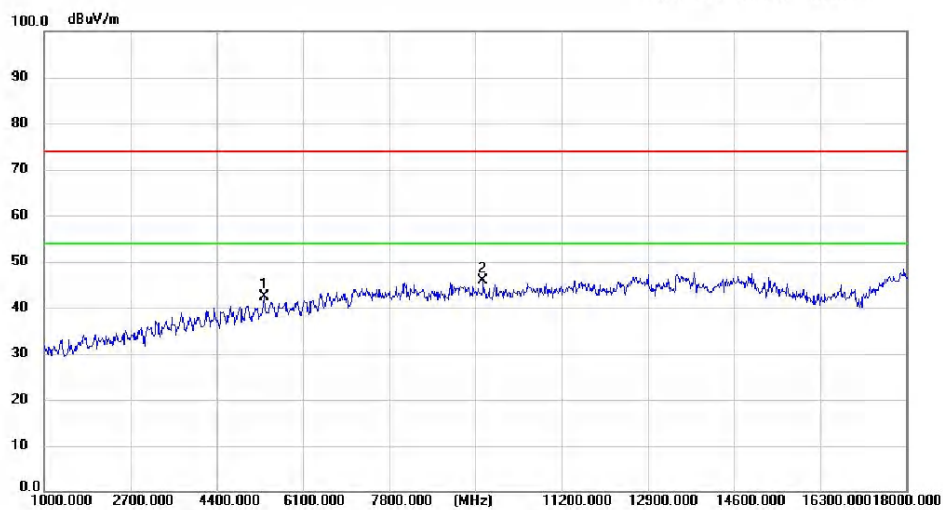
Test Site: PSI EMC Lab-3m Chamber
EUT: L320 Party Speaker
M/N: NS-PSL320
Test Mode: 8DPSK 2480
Test Voltage: Battery
Note:

Polarization: **Vertical**
Distance: 3m
Test Engineer: Jeffrey

Temperature: 26 °C
Humidity: 54 %RH

Radiated Emission Measurement

Test Date: 2026/6/18 20:08:45



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	5335.000	63.44	-21.11	42.33	74.00	-31.67	peak	150	118	P	
2 *	9659.375	62.06	-16.22	45.84	74.00	-28.16	peak	150	315	P	

Note: *:Maximum data x:Over limit !:over margin Level = Reading + Factor Margin = Level - Limit

File: 音箱 1G-18G\Data :#11

Page: 1

Engineer Signature: